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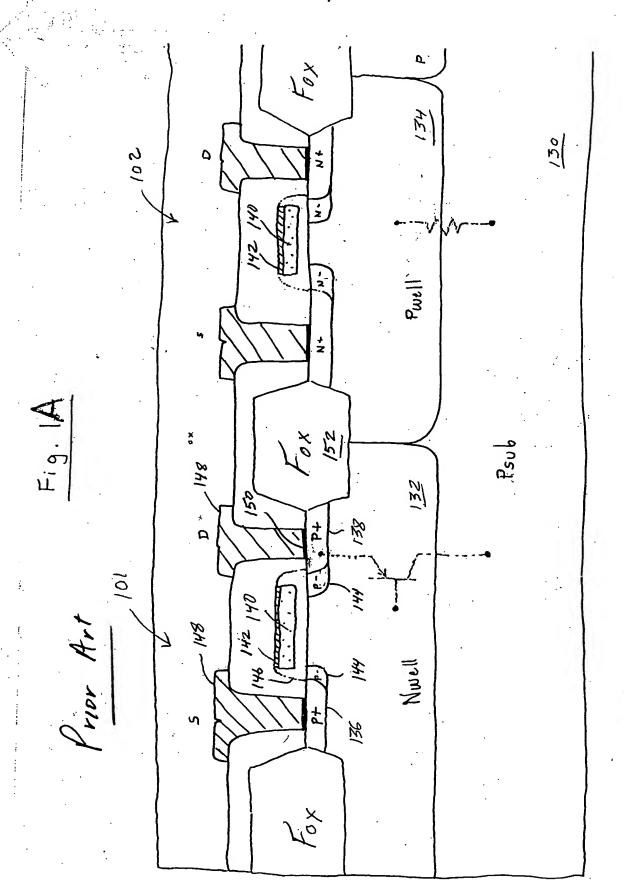
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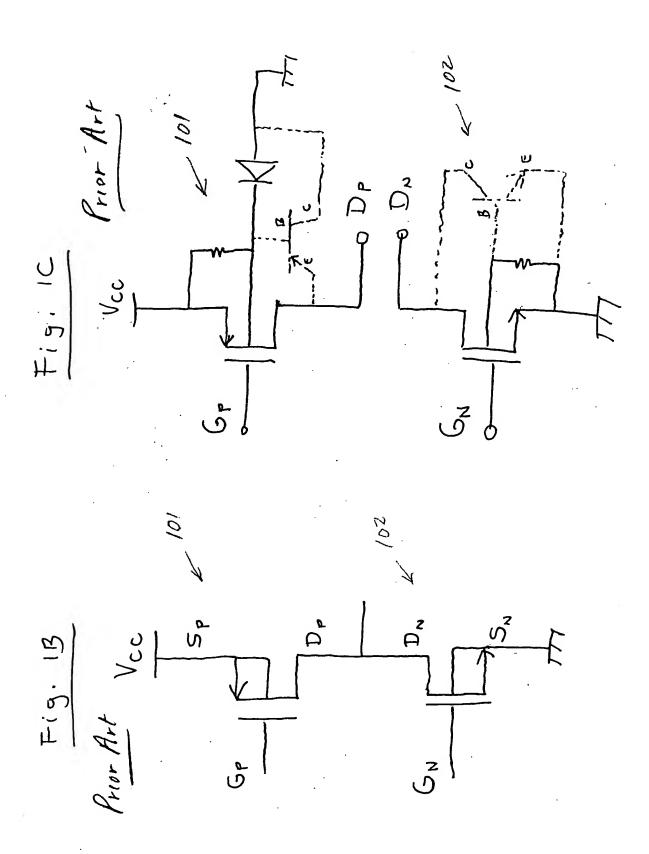
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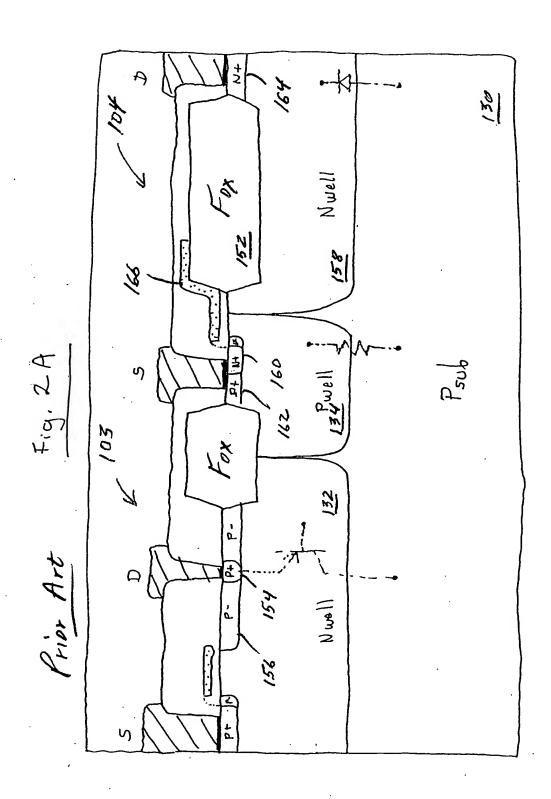
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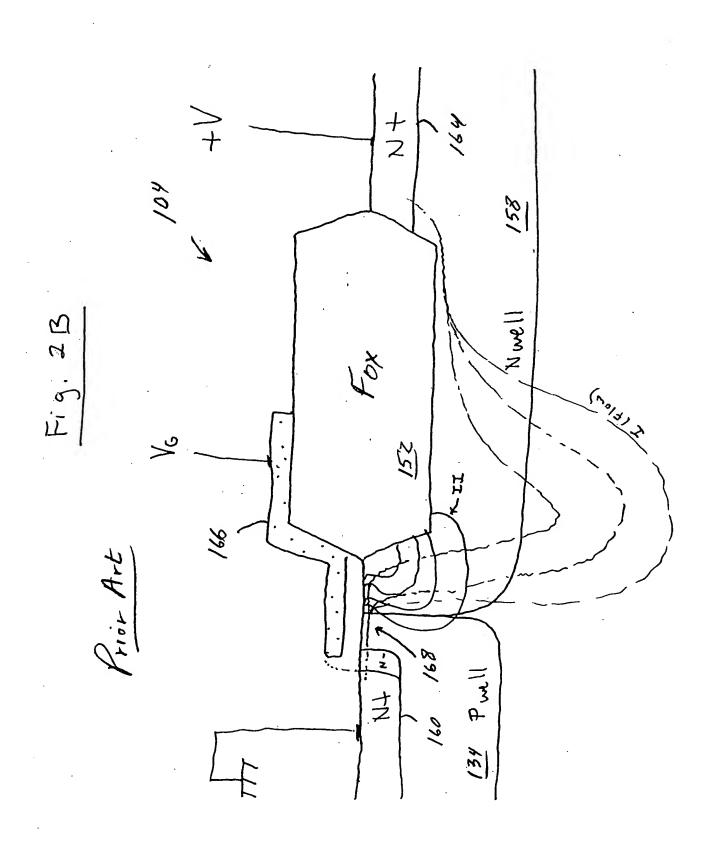
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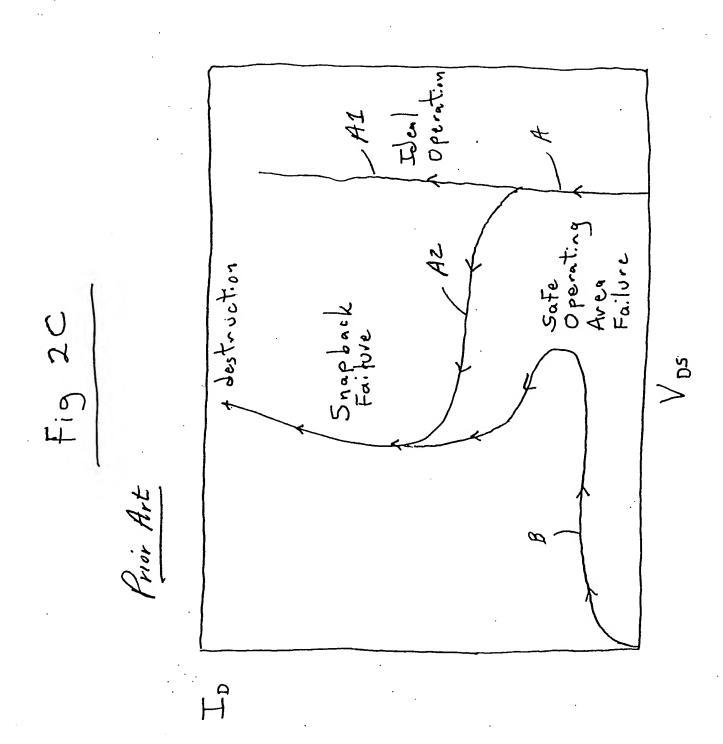
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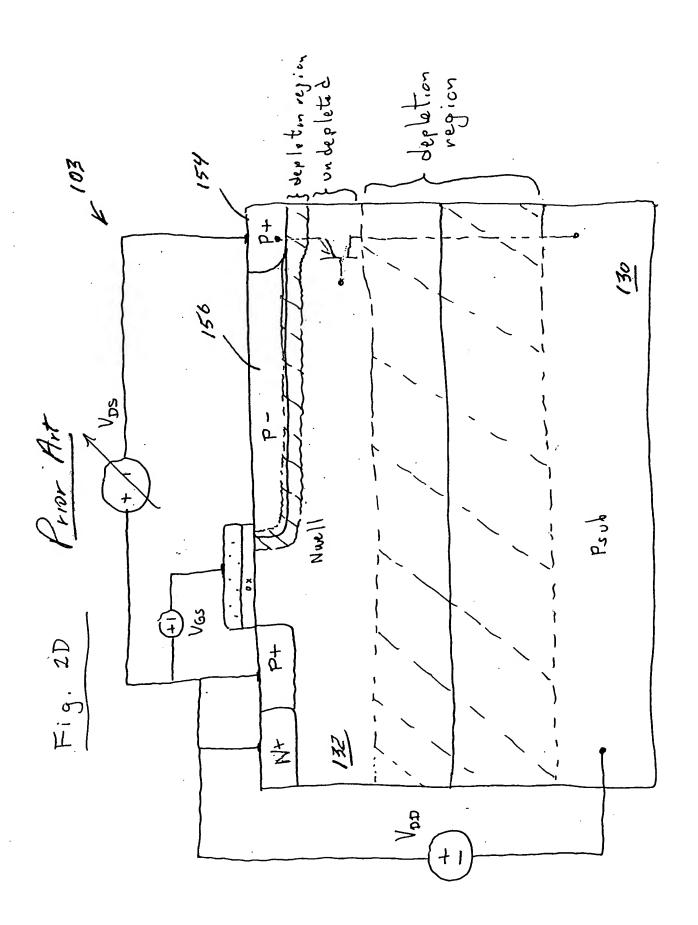


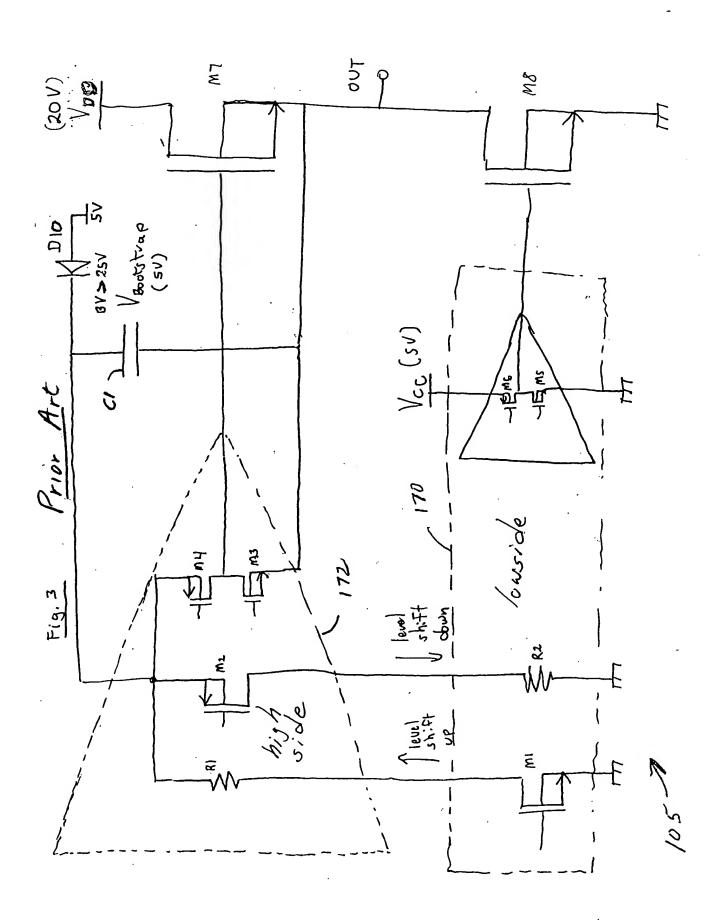


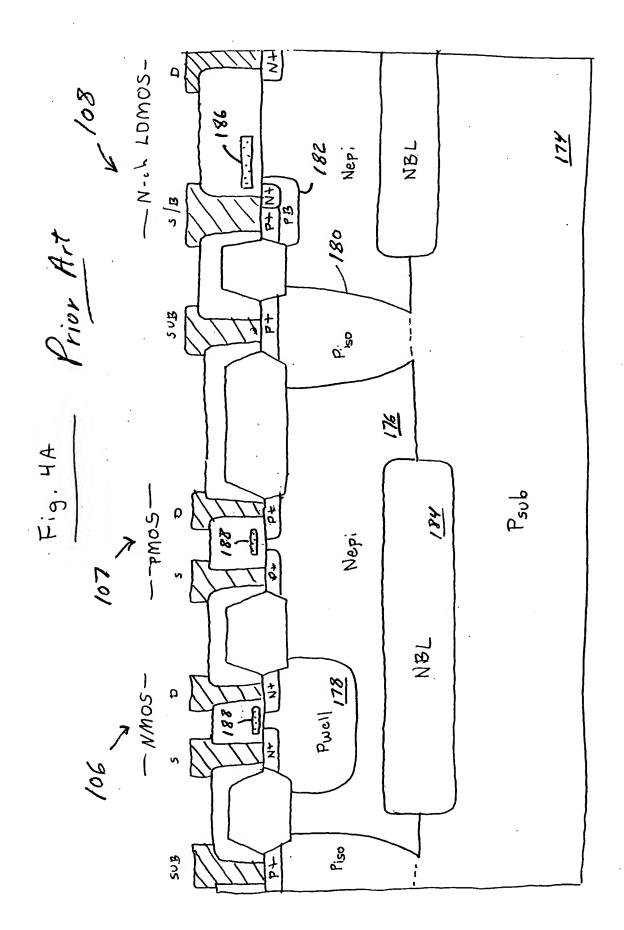


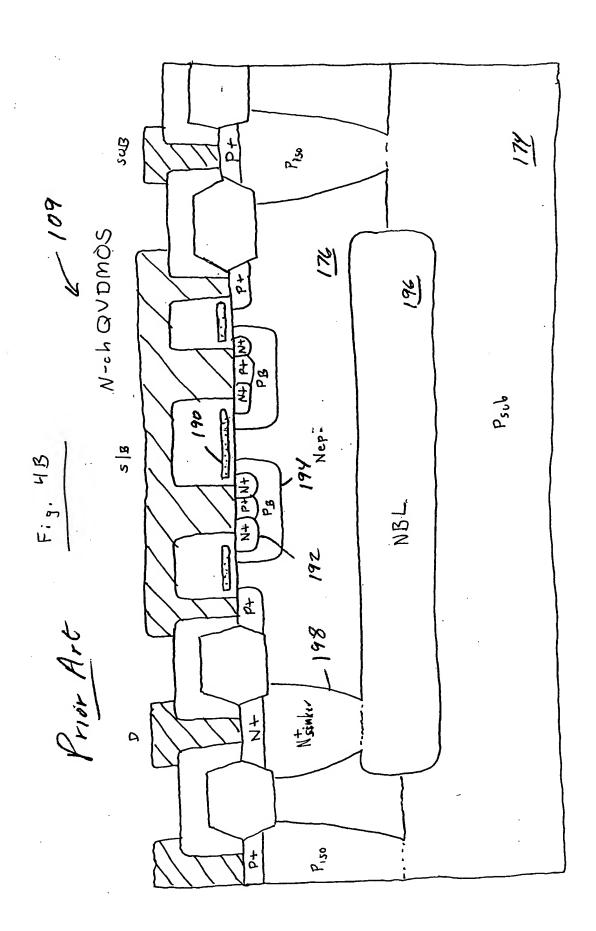


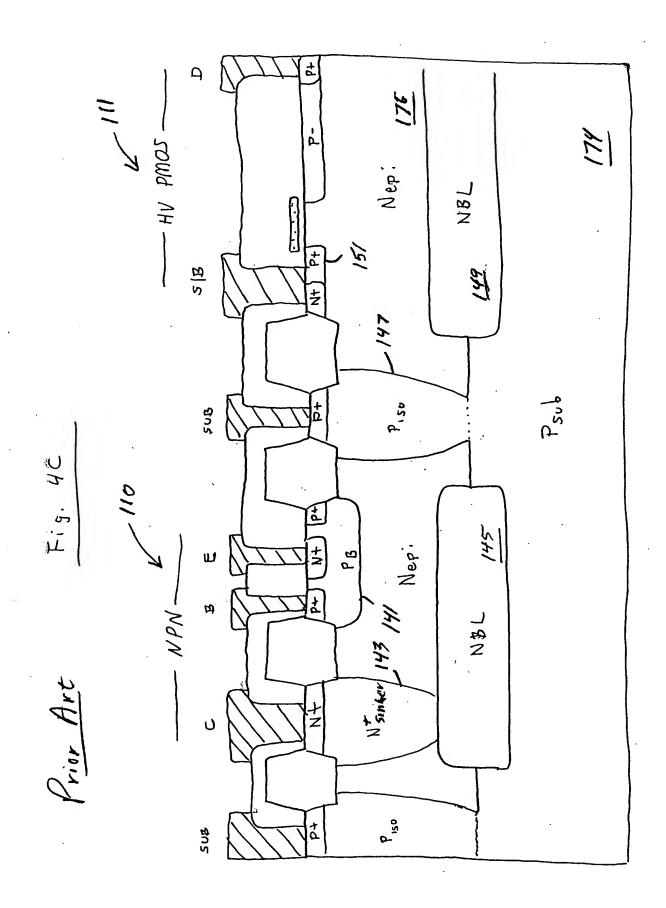


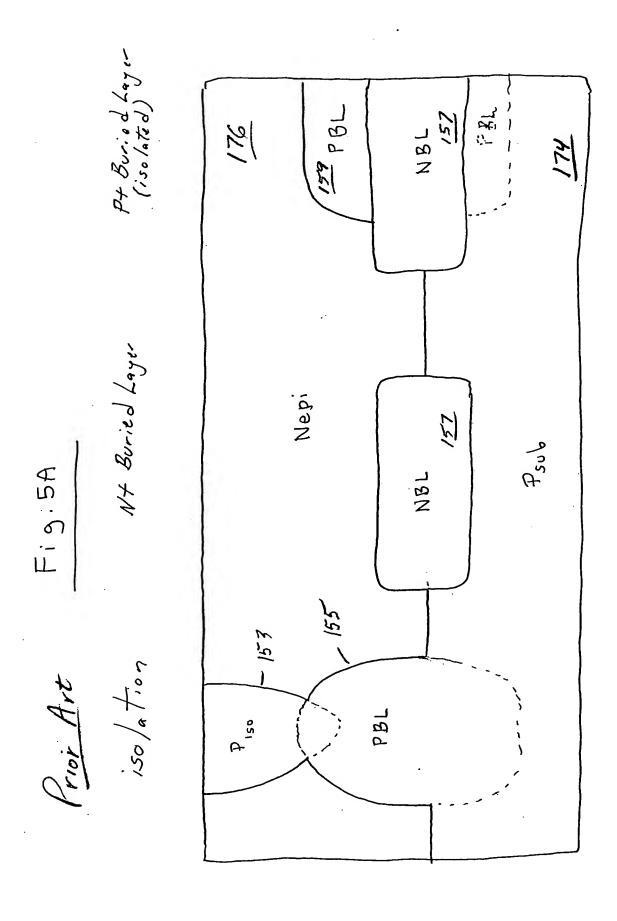


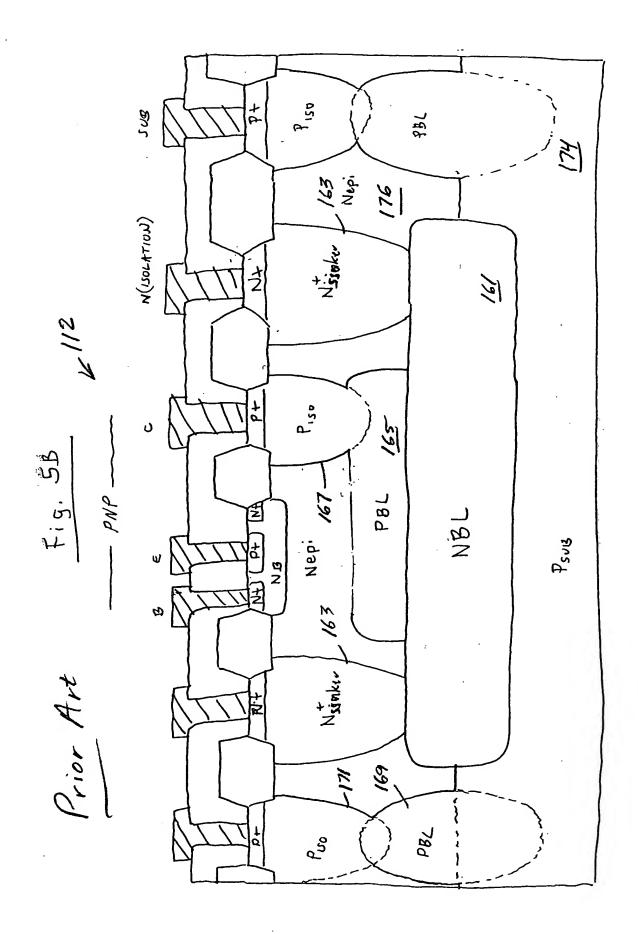


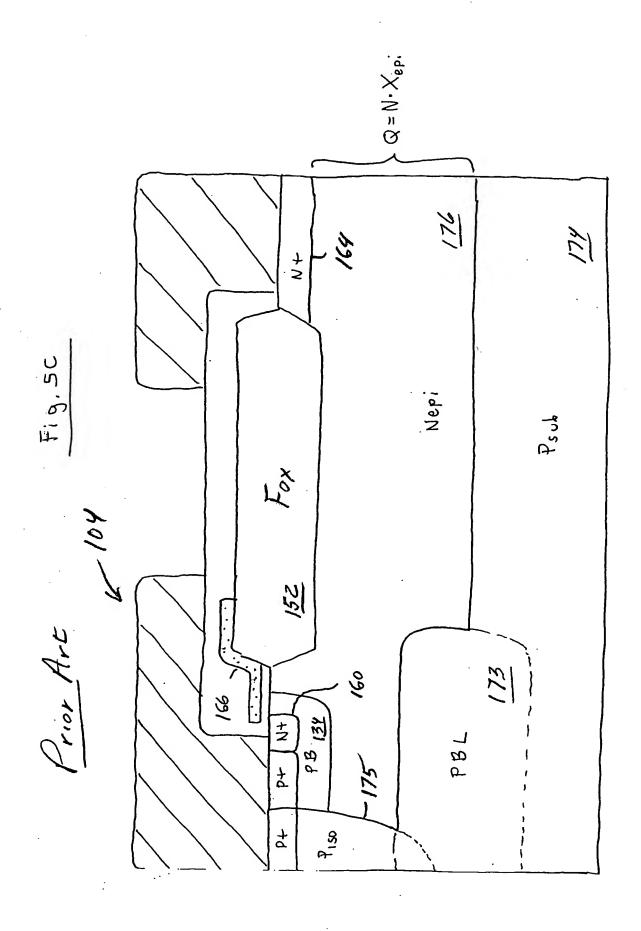


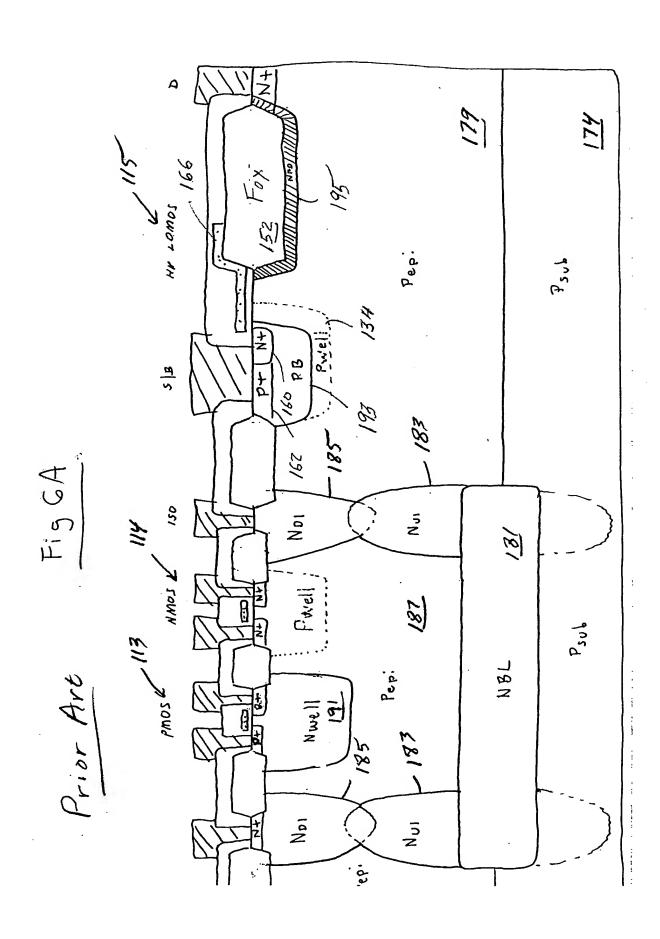


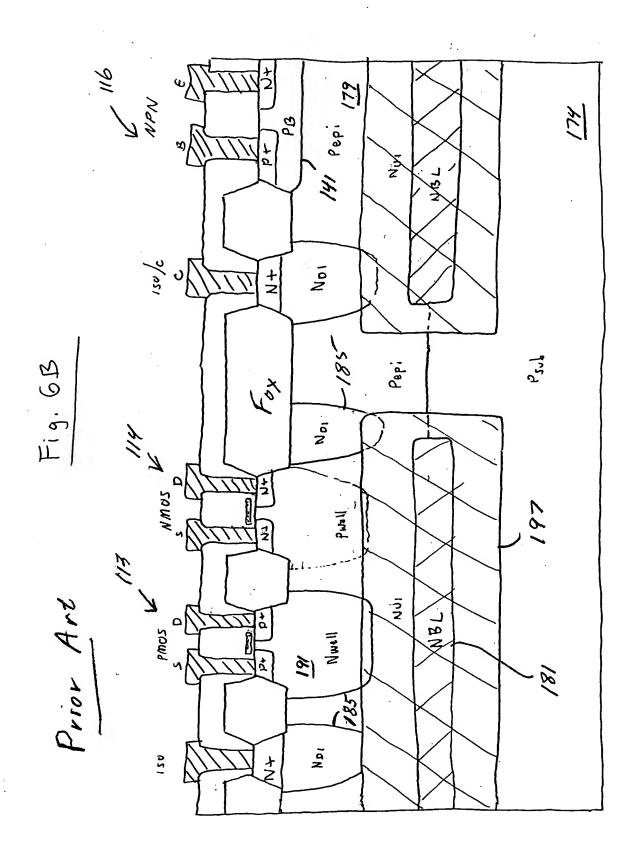












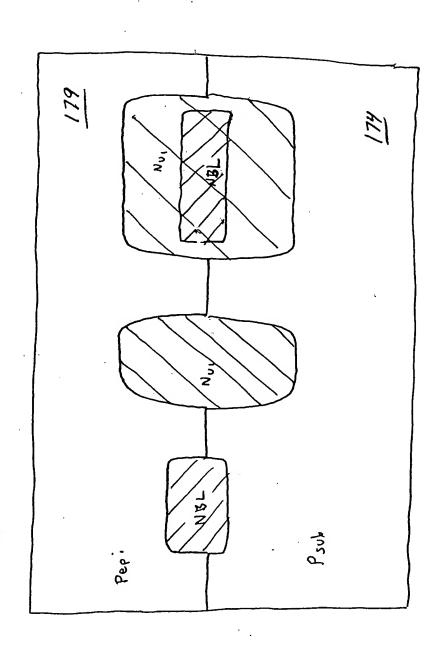
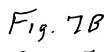
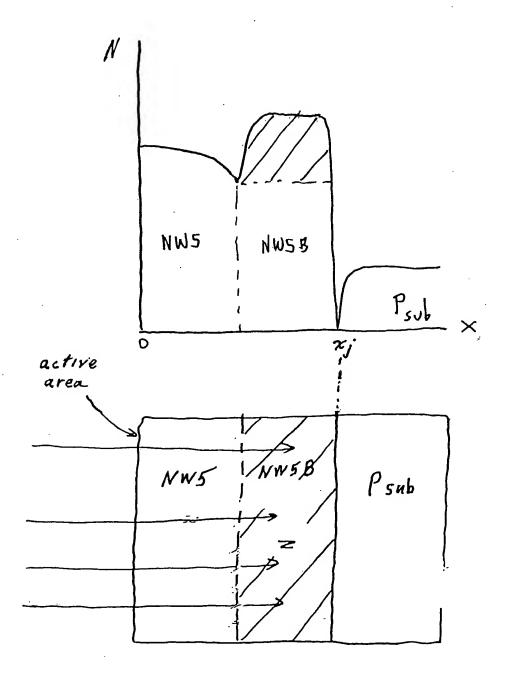
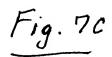


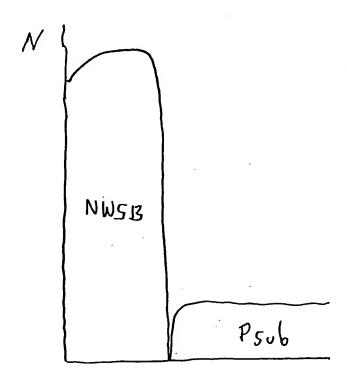
Fig. 6C

Prior Art Fig. 7A Nwell Psub γ_j









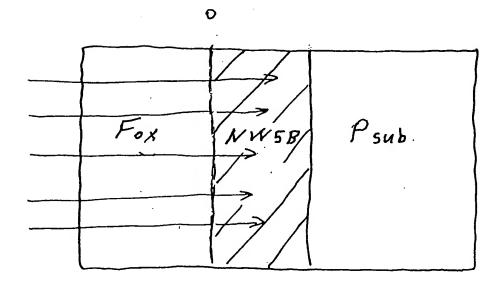


Fig. 8A

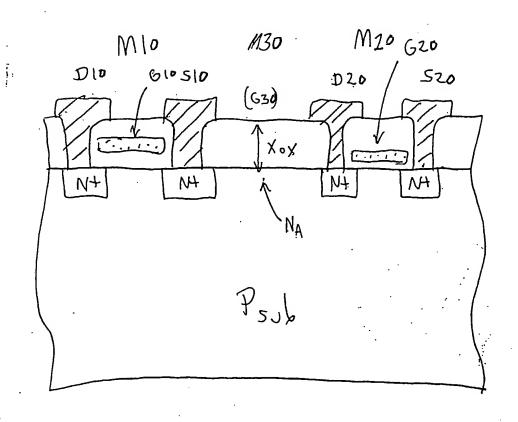
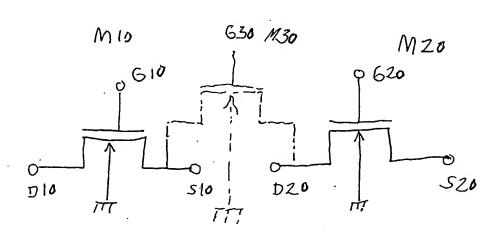
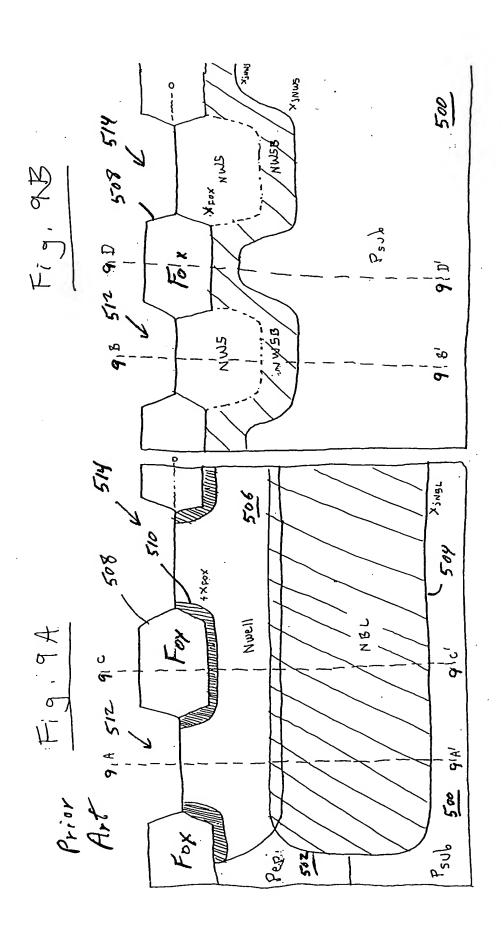
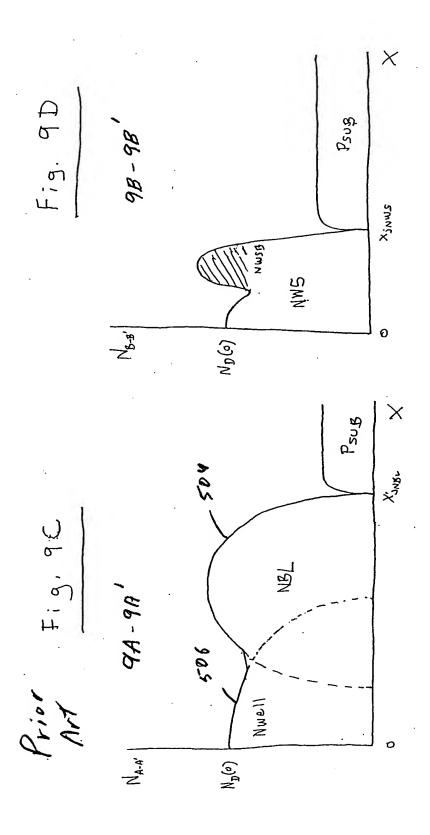
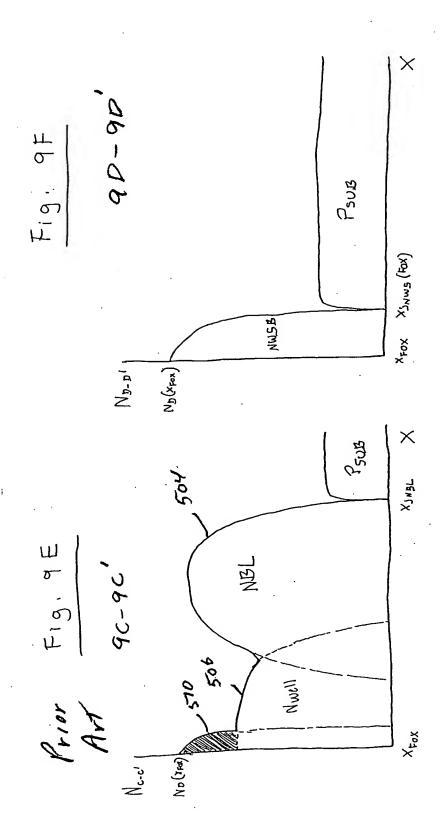


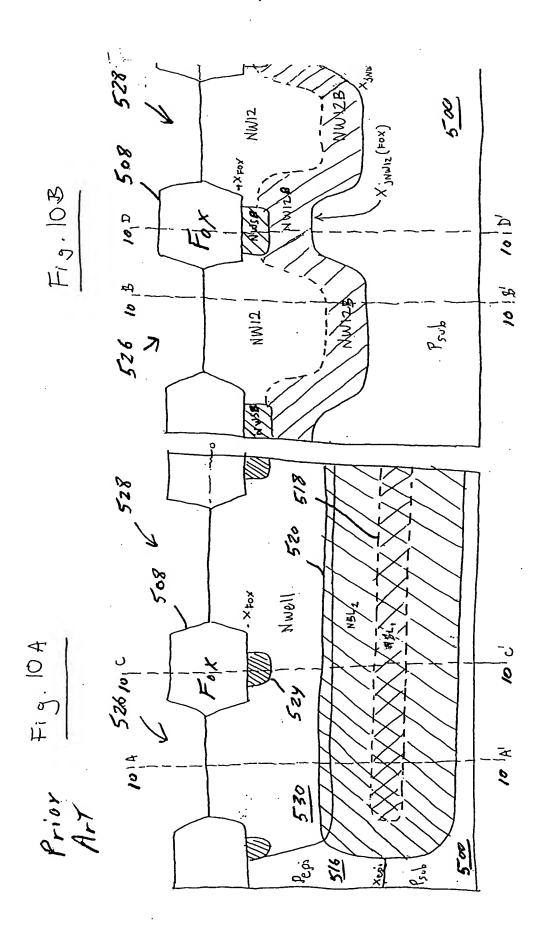
Fig. 8B

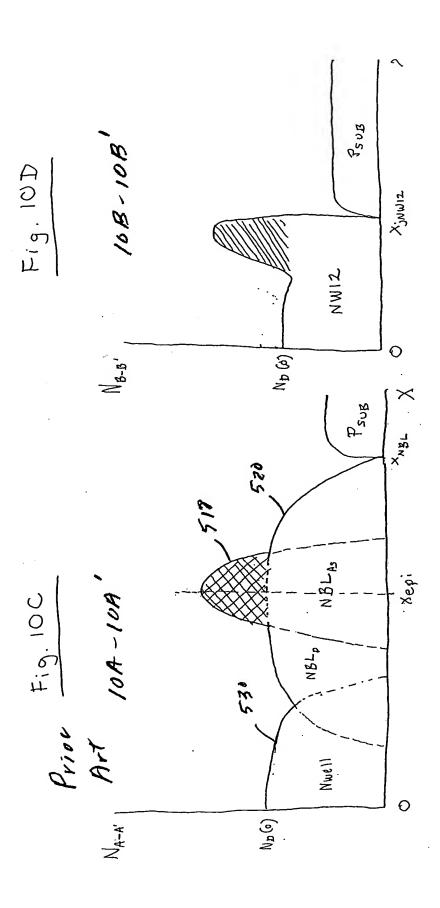


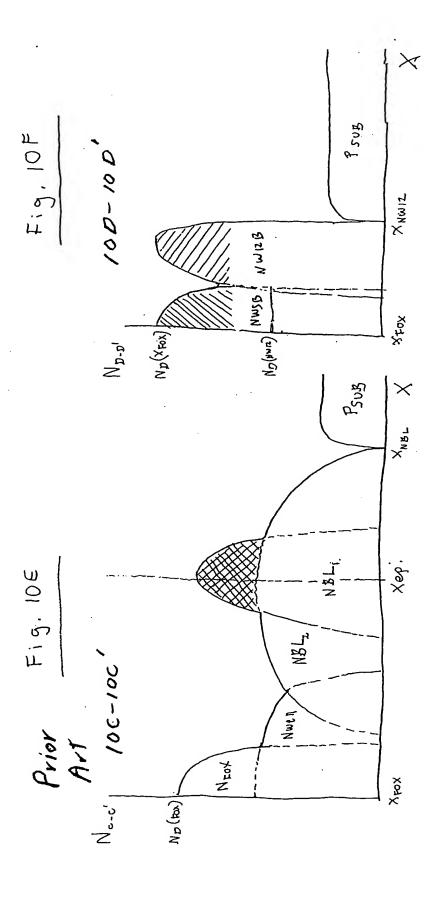


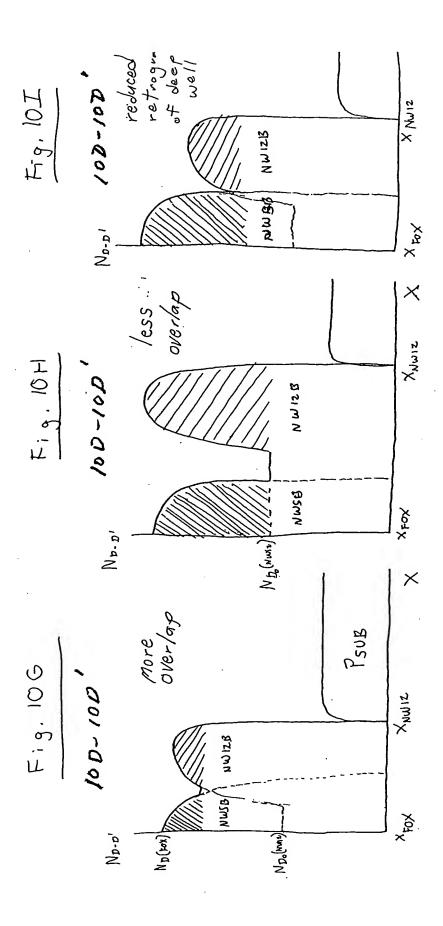


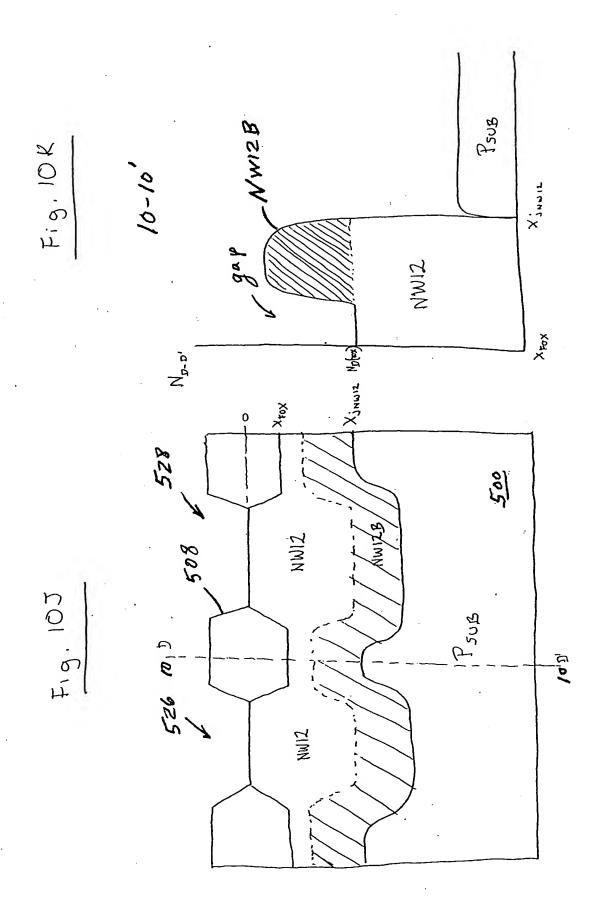


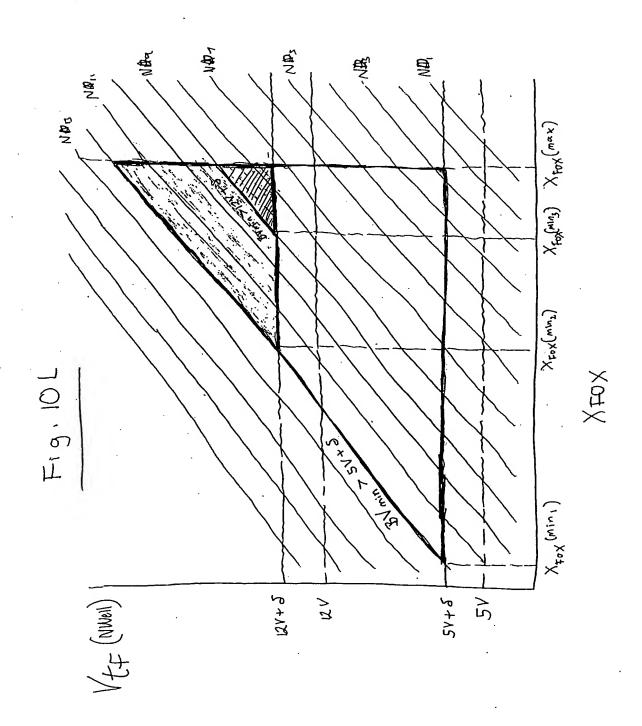


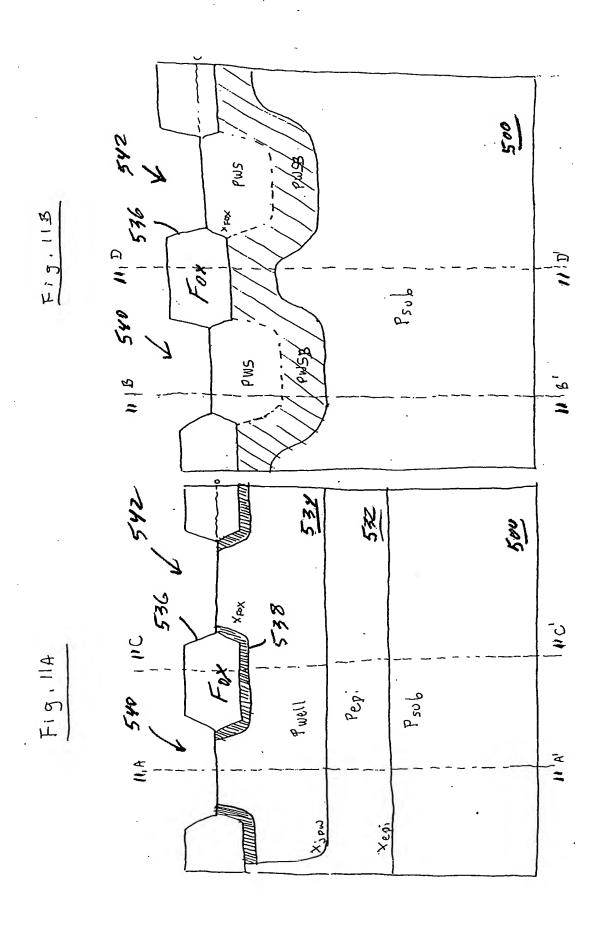


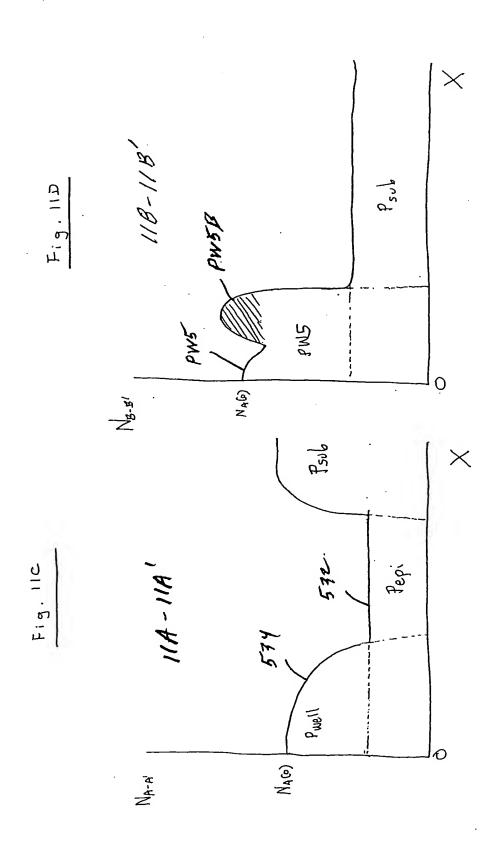


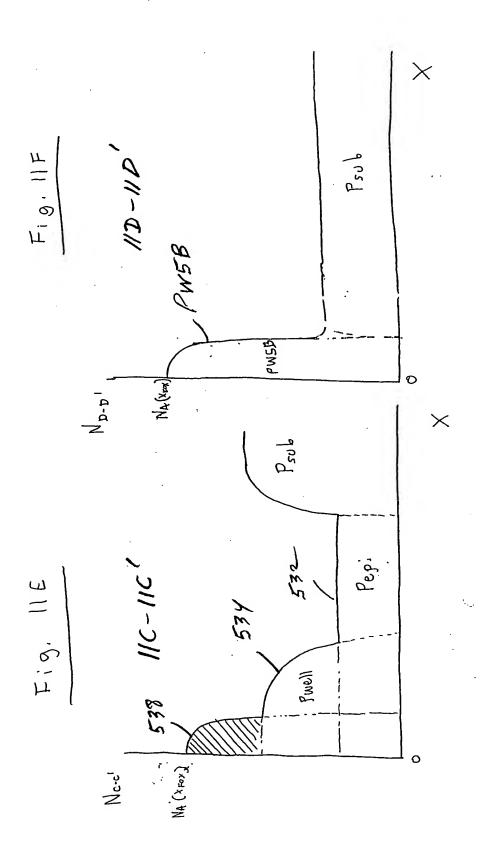


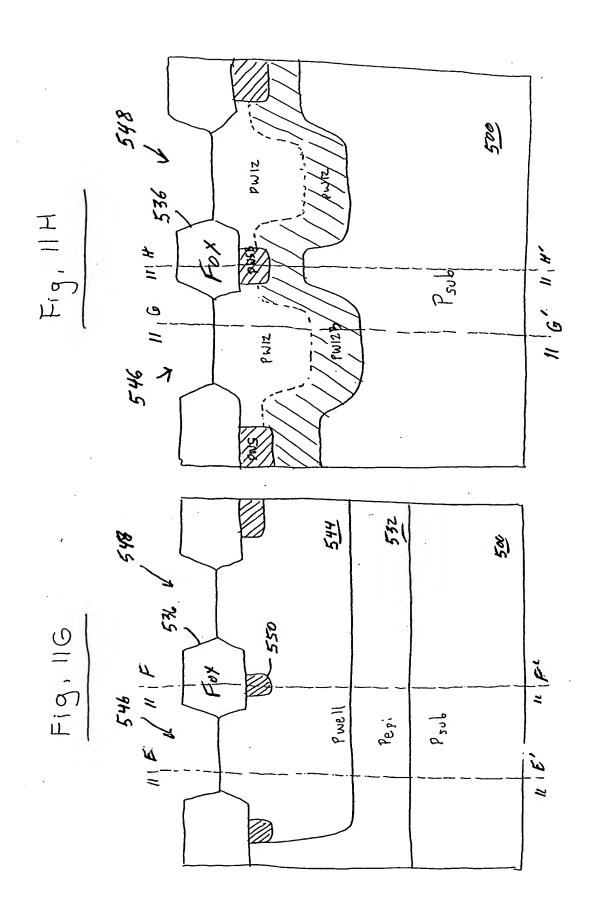


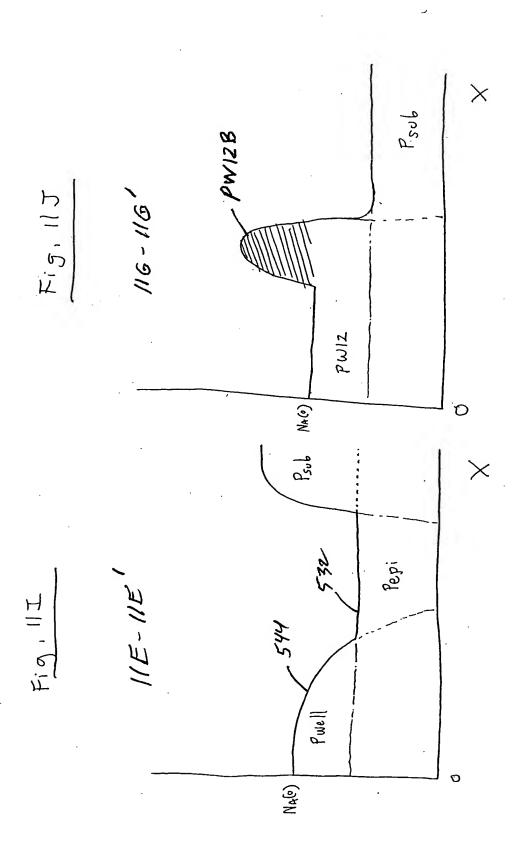


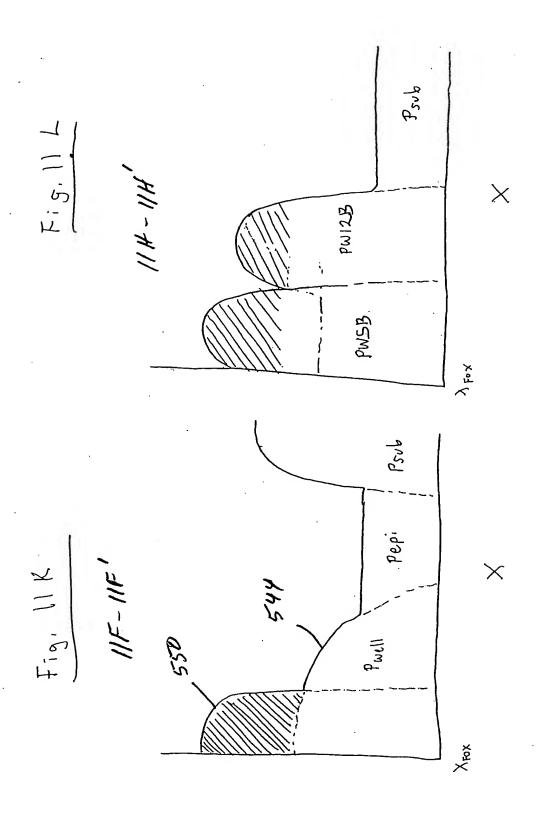


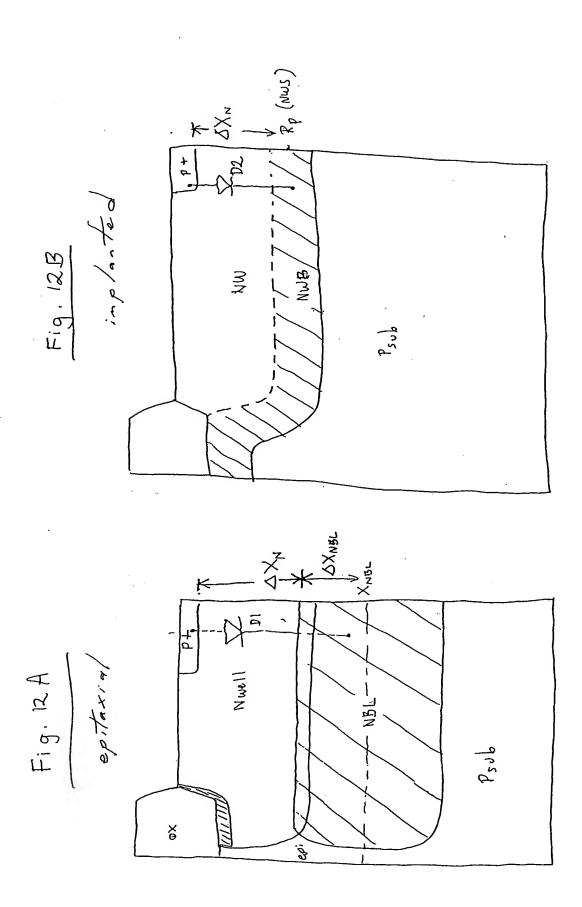


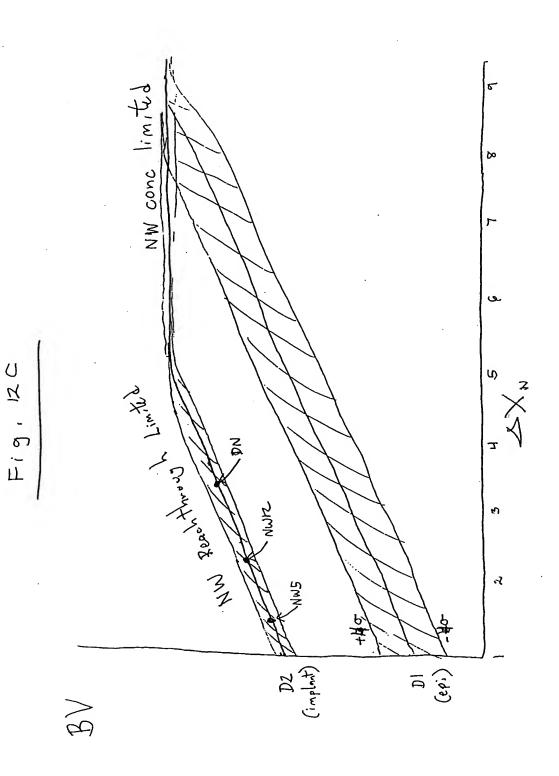


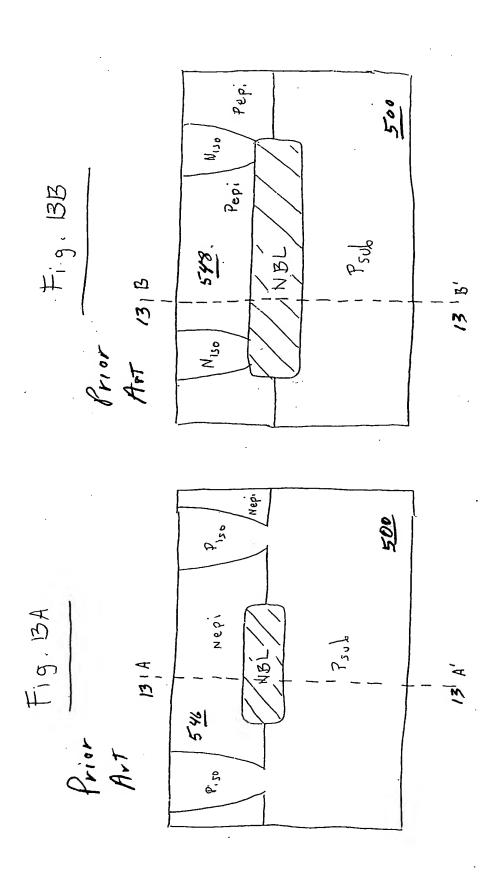


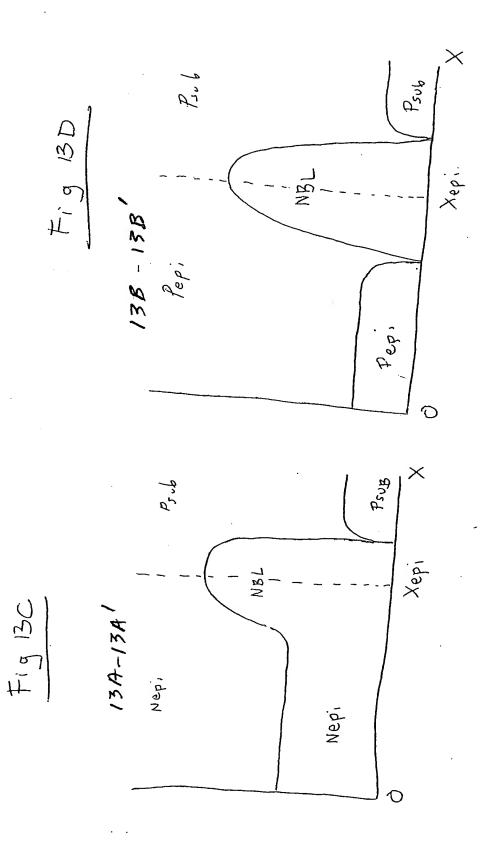












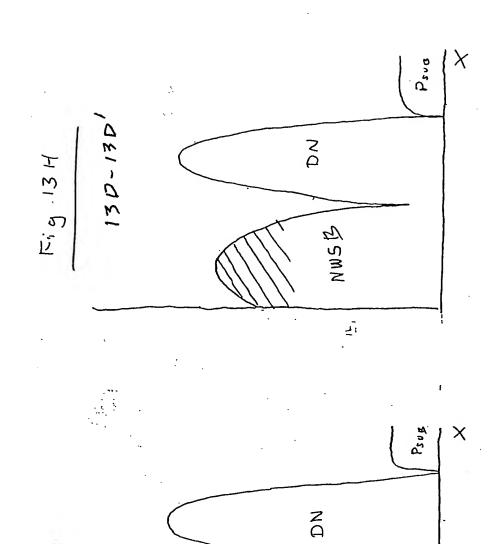
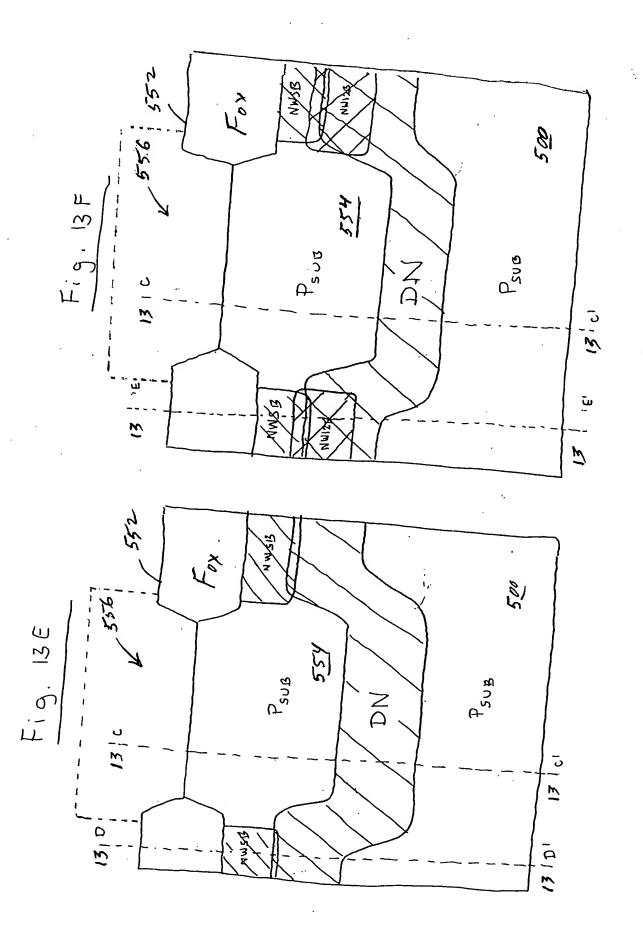
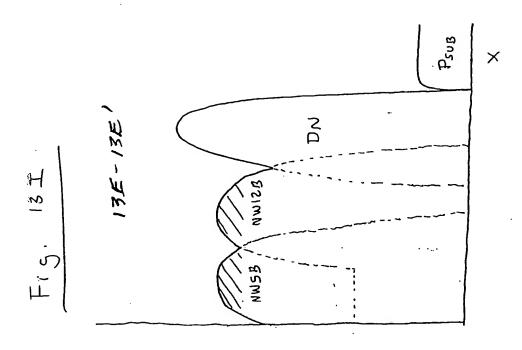


Fig. 136

135-136





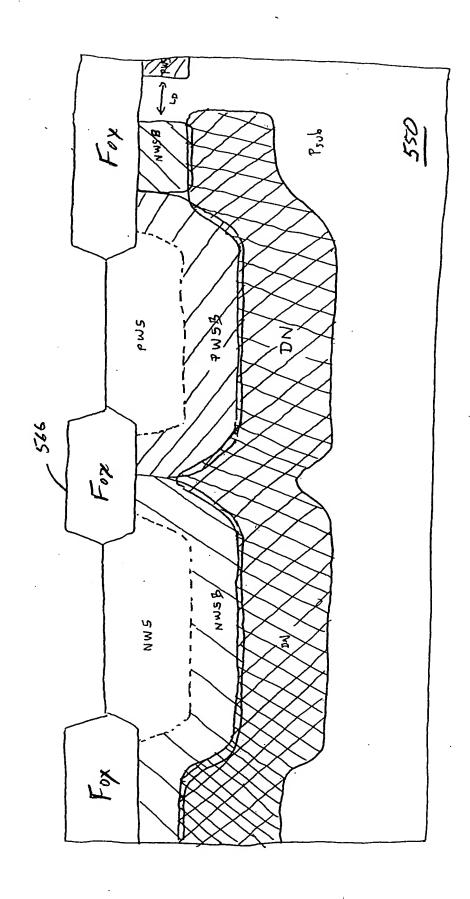


Fig 14A

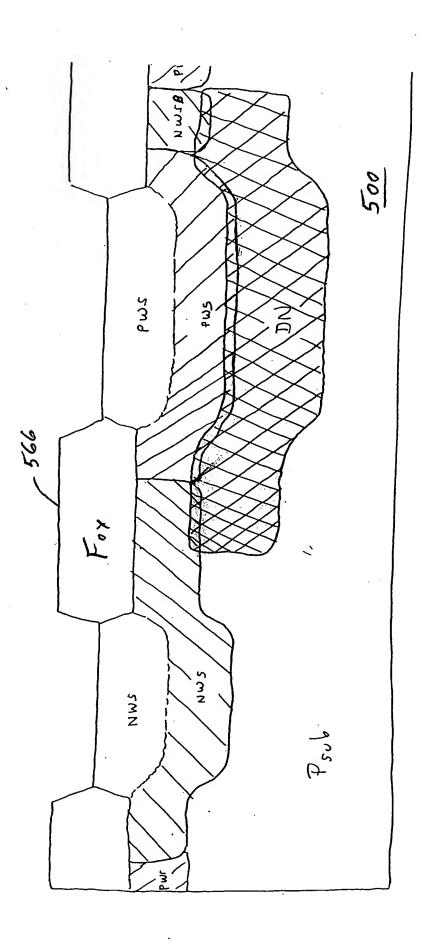


Fig. 14 B

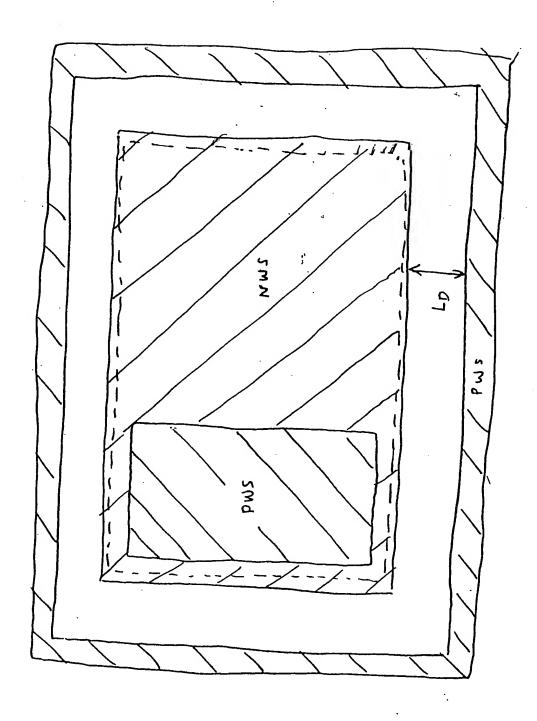
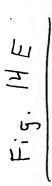


Fig. 14 C



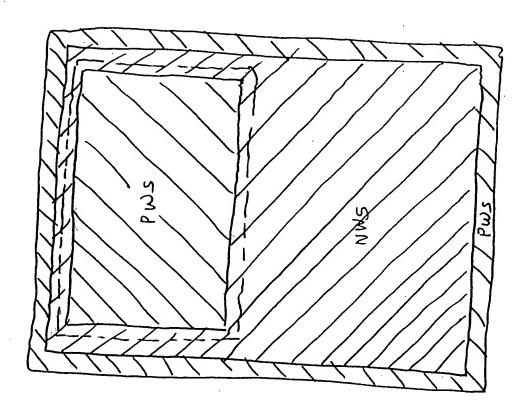
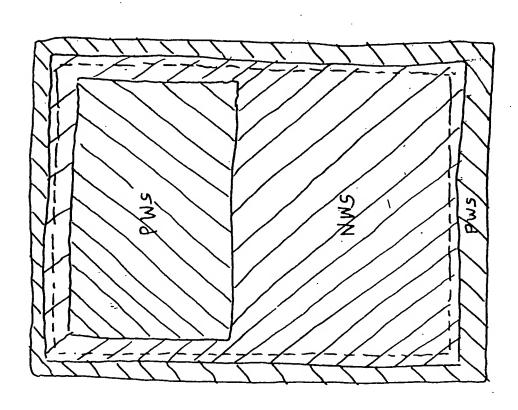
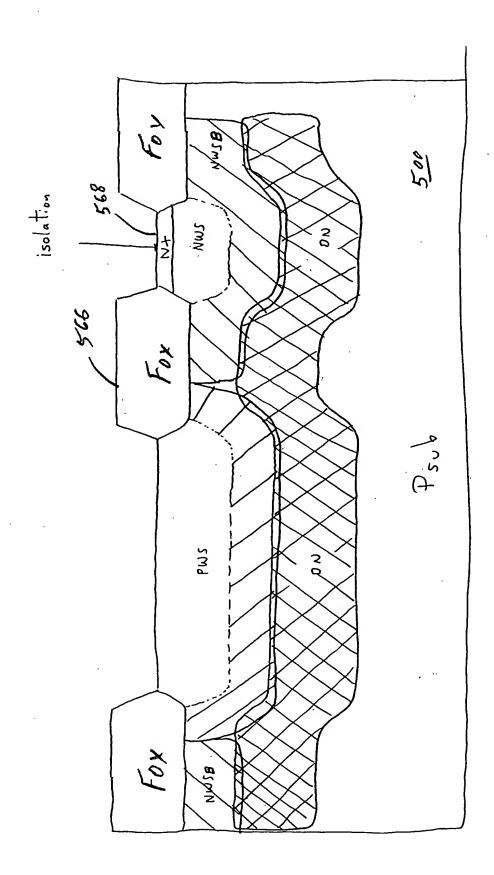


Fig 140





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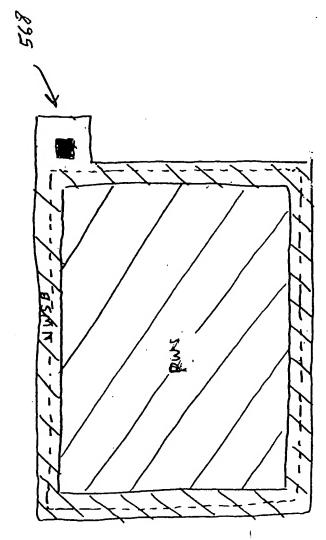
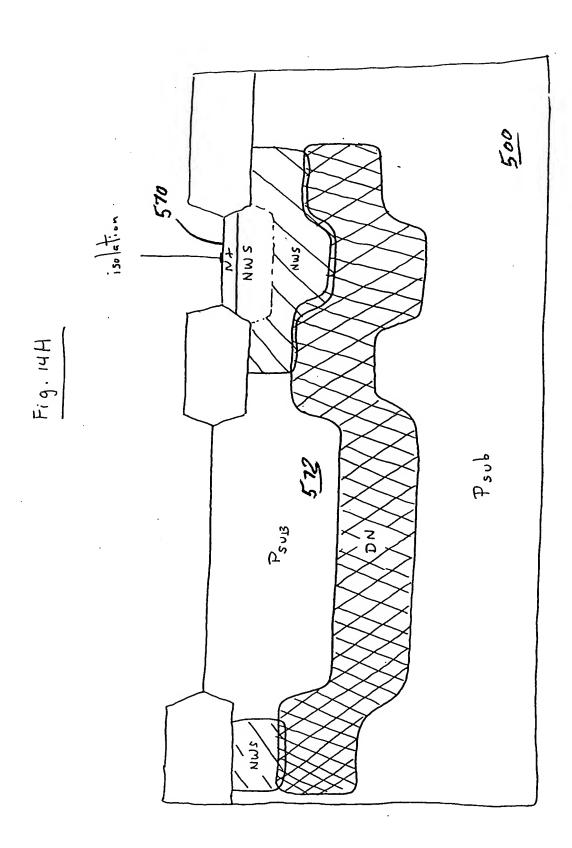


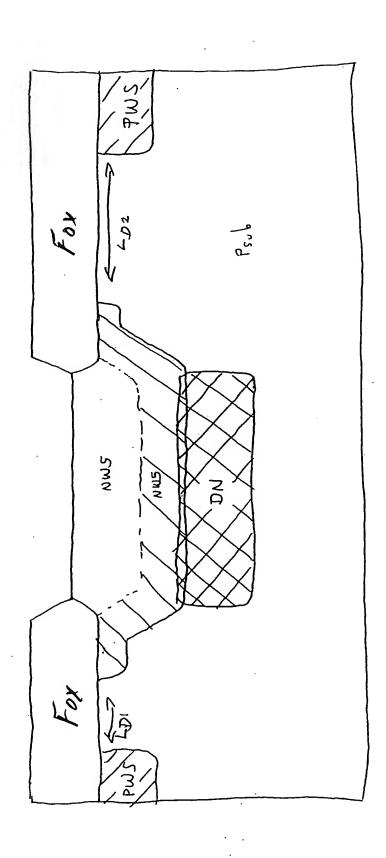
Fig. 146

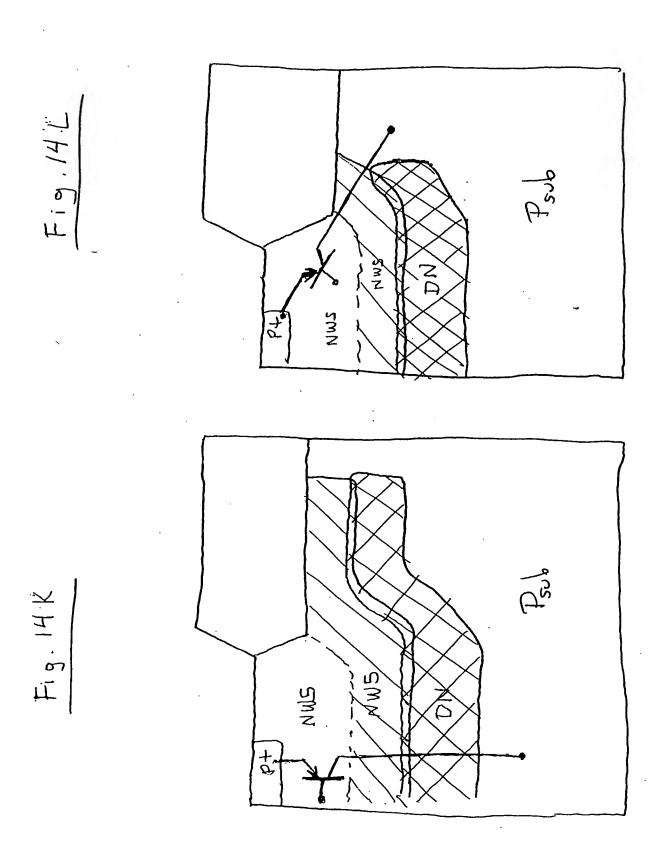


500 25 2 B S Fox

Fig. 14I.

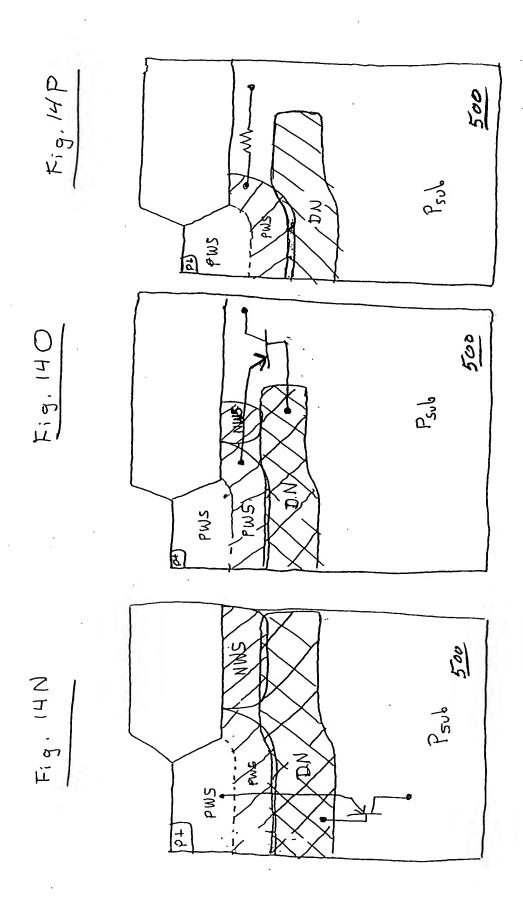
Fig. 143





200 PWS

F. g. 14.M



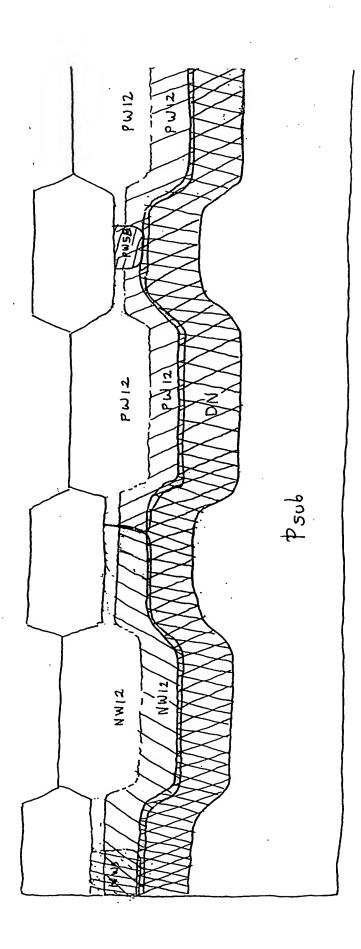
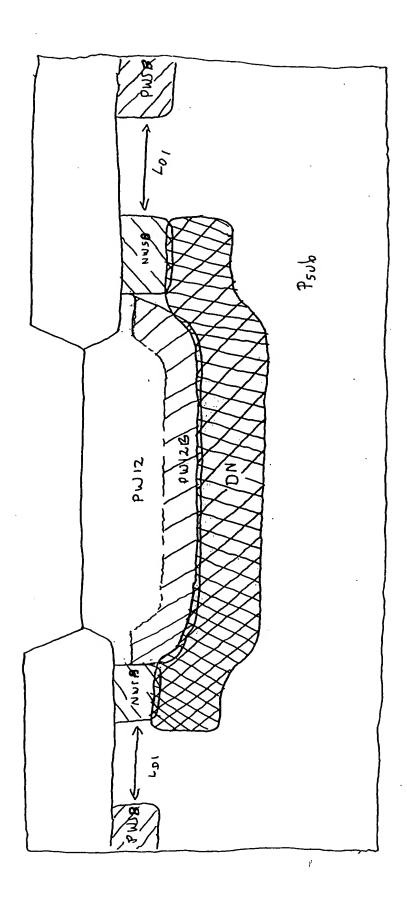


Fig. 15A



Fig, 15B

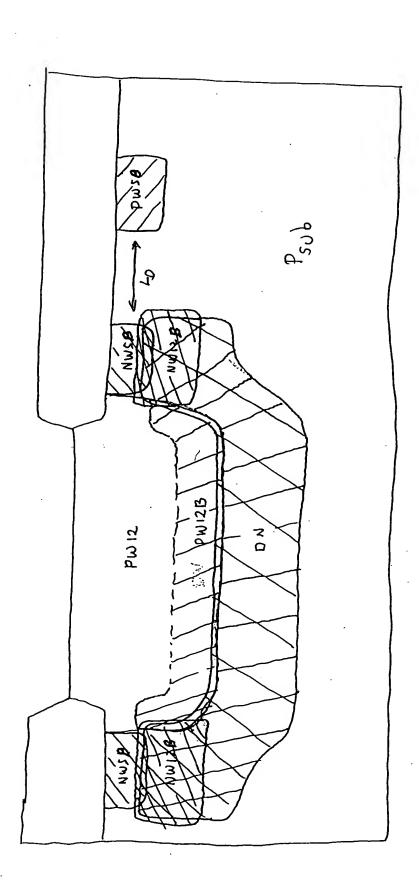


Fig. 15C

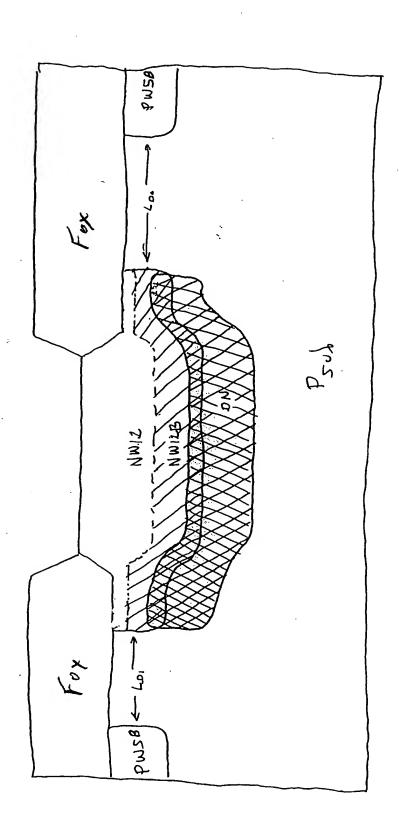
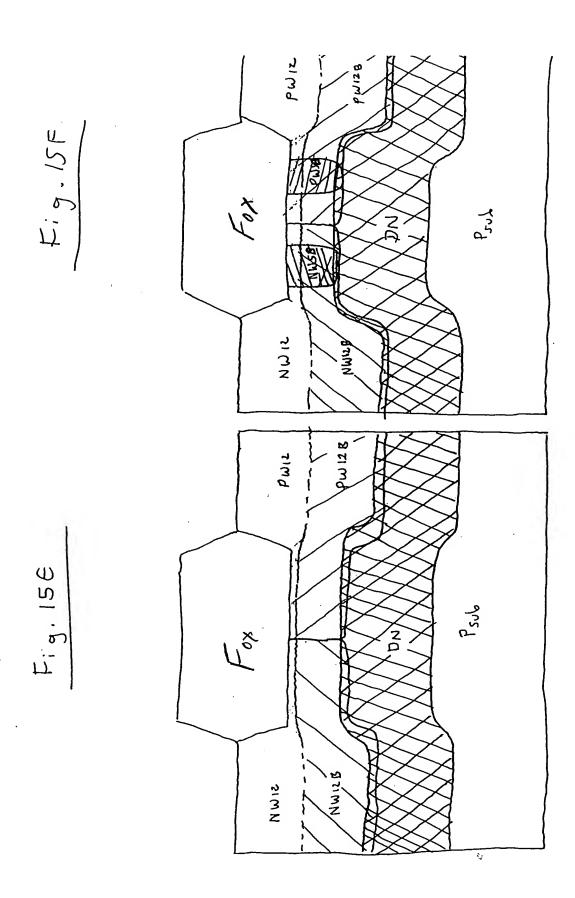


Fig. 15



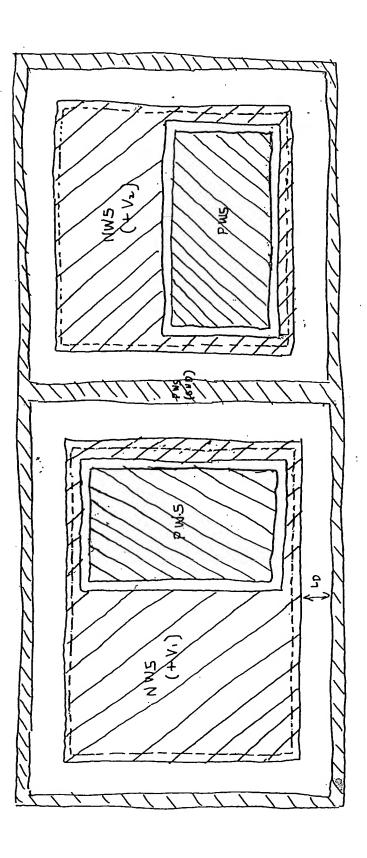
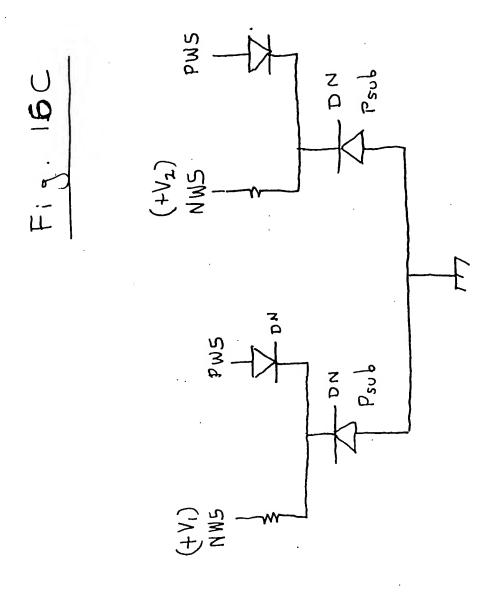


Fig. 16'8



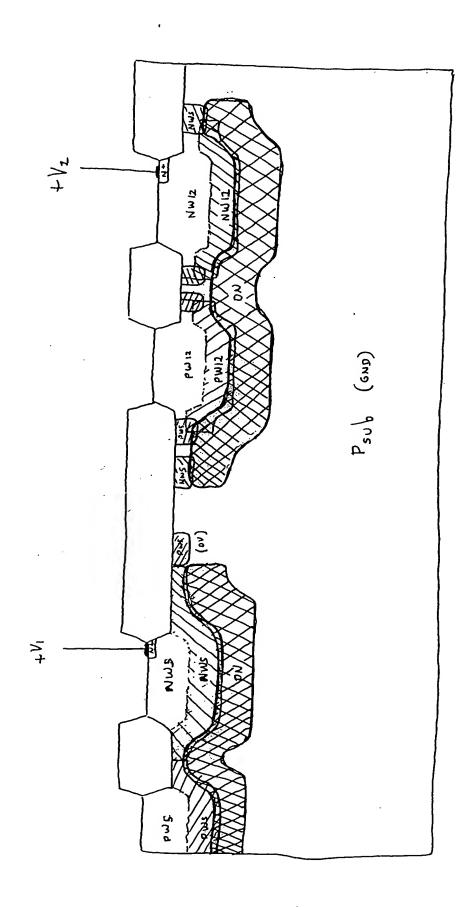
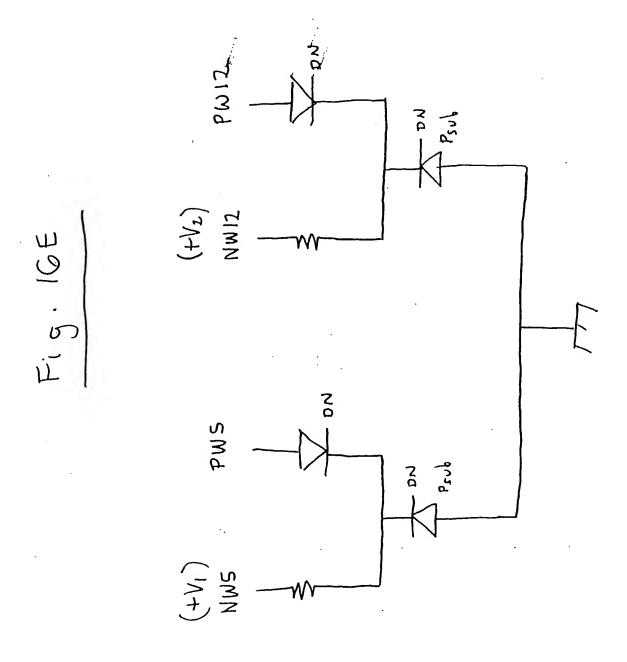
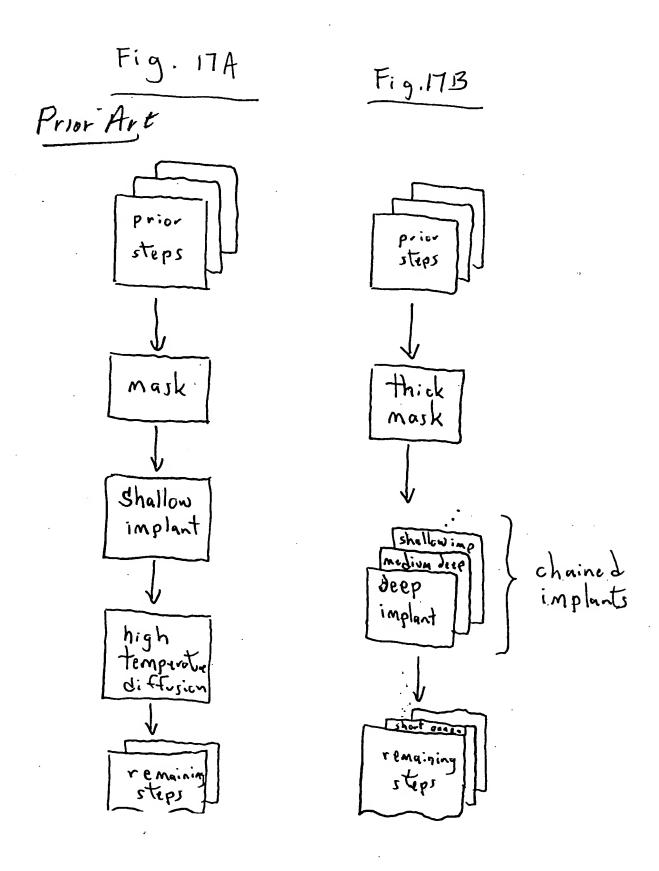


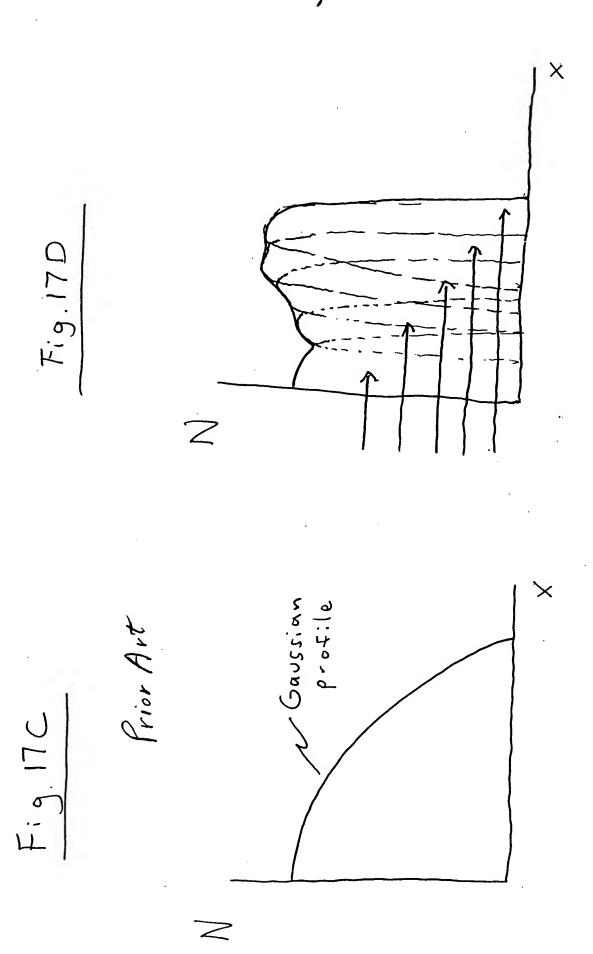
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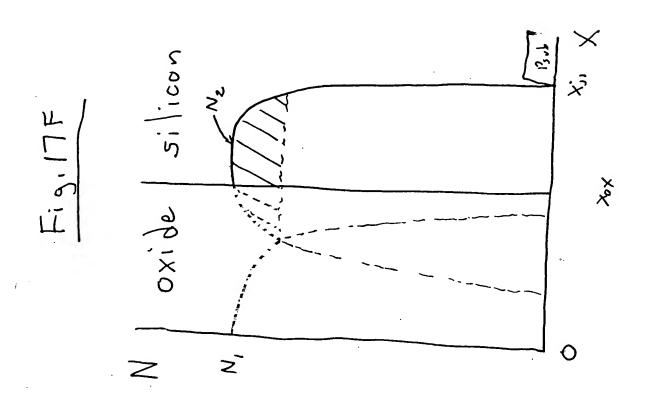


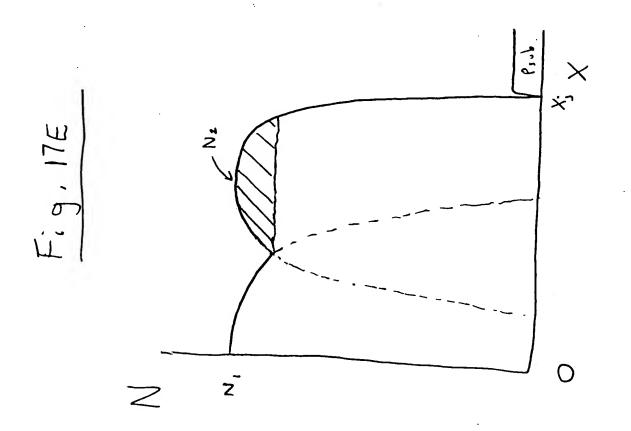
PW12 NW12 35 SMY

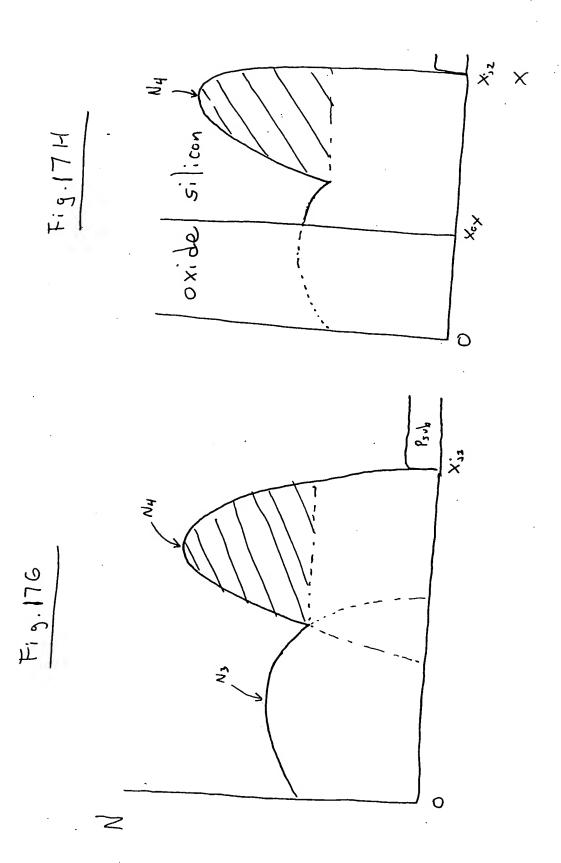
Fig. (6F

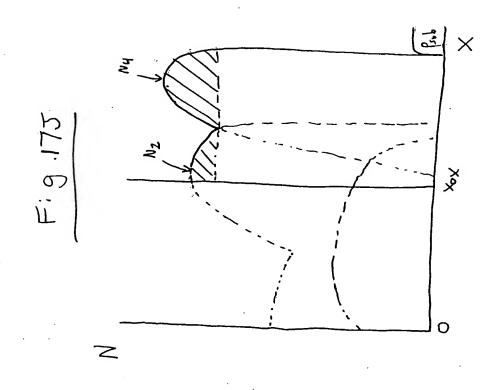


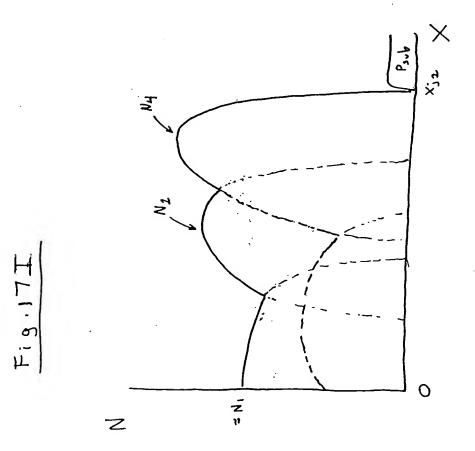


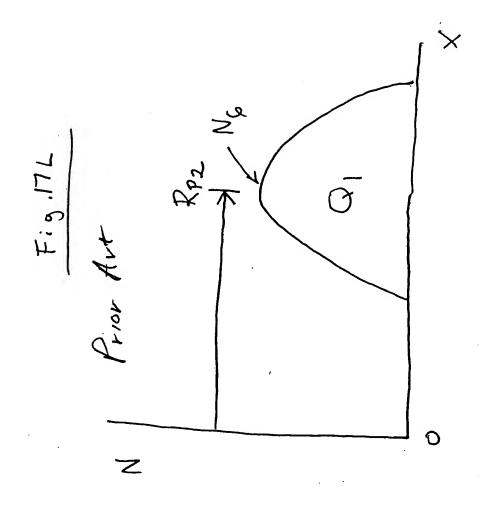


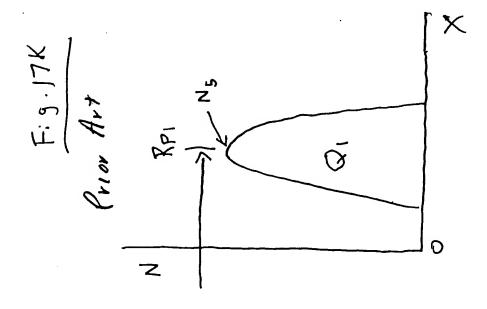


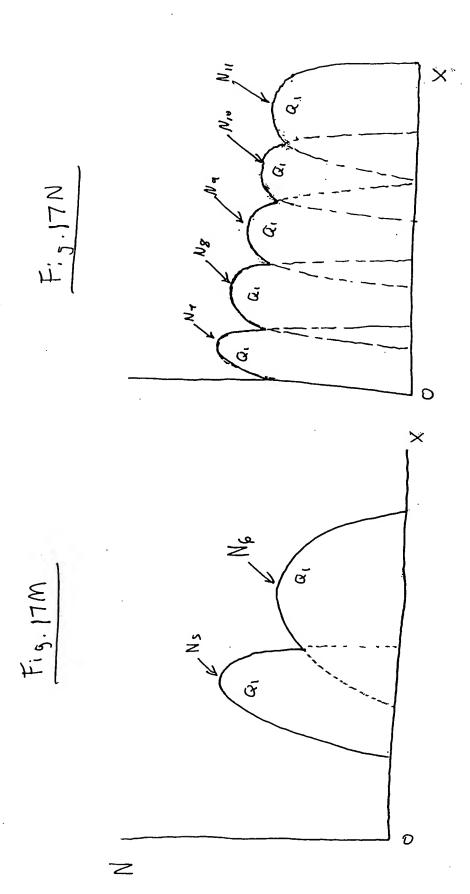


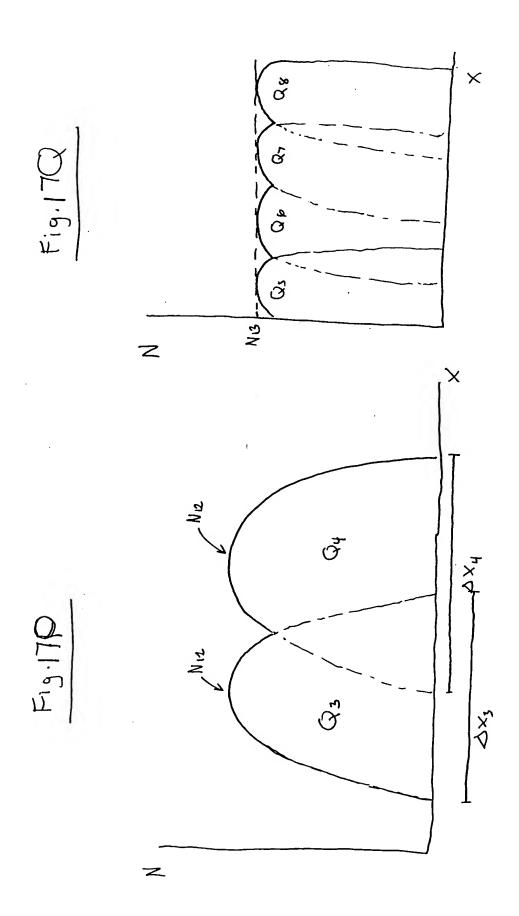


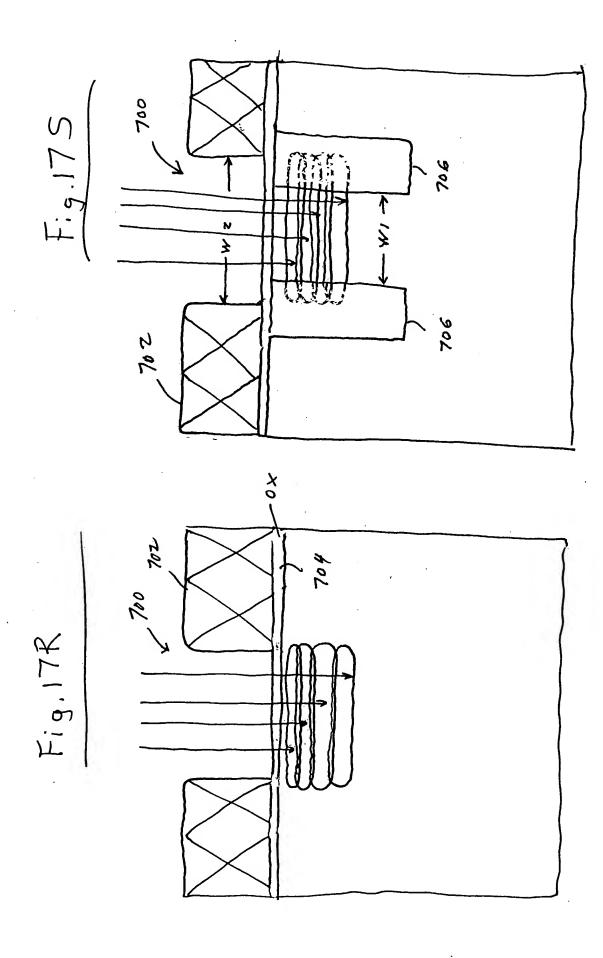


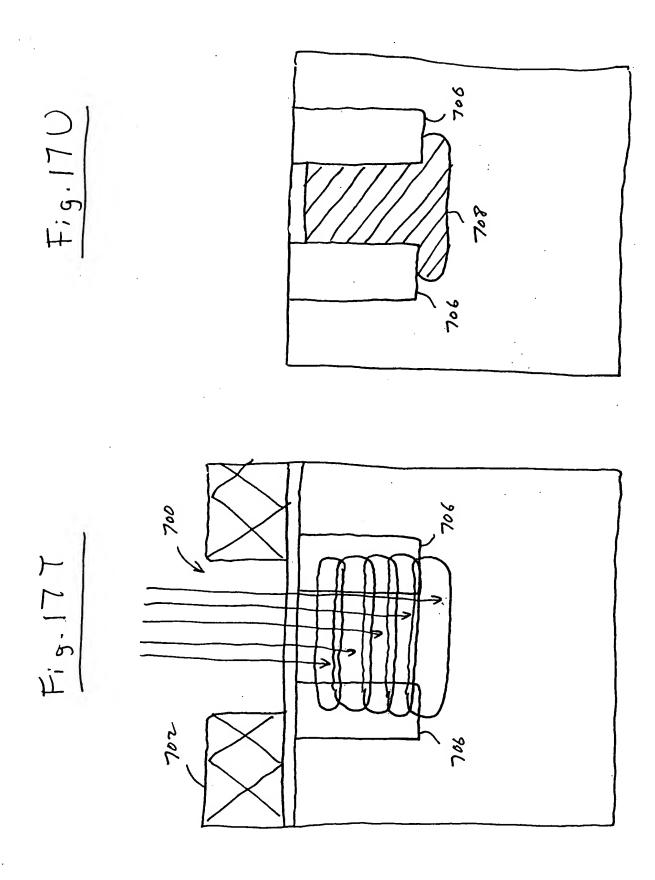


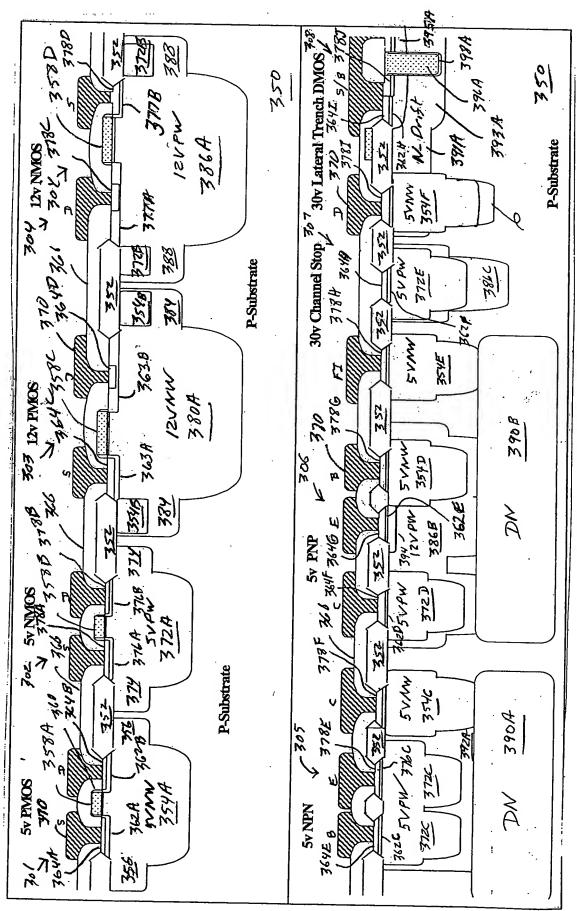




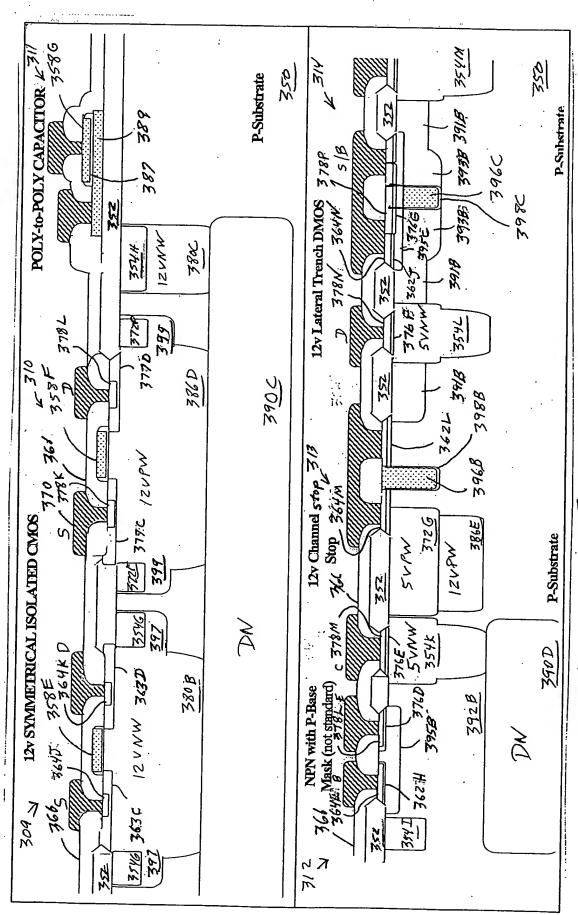




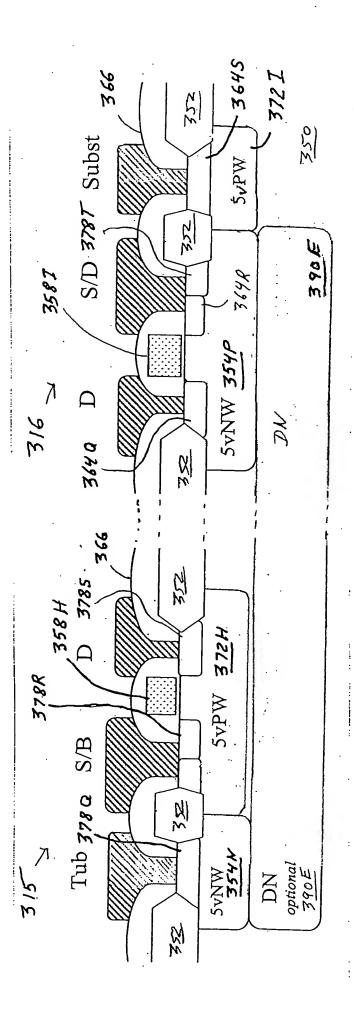




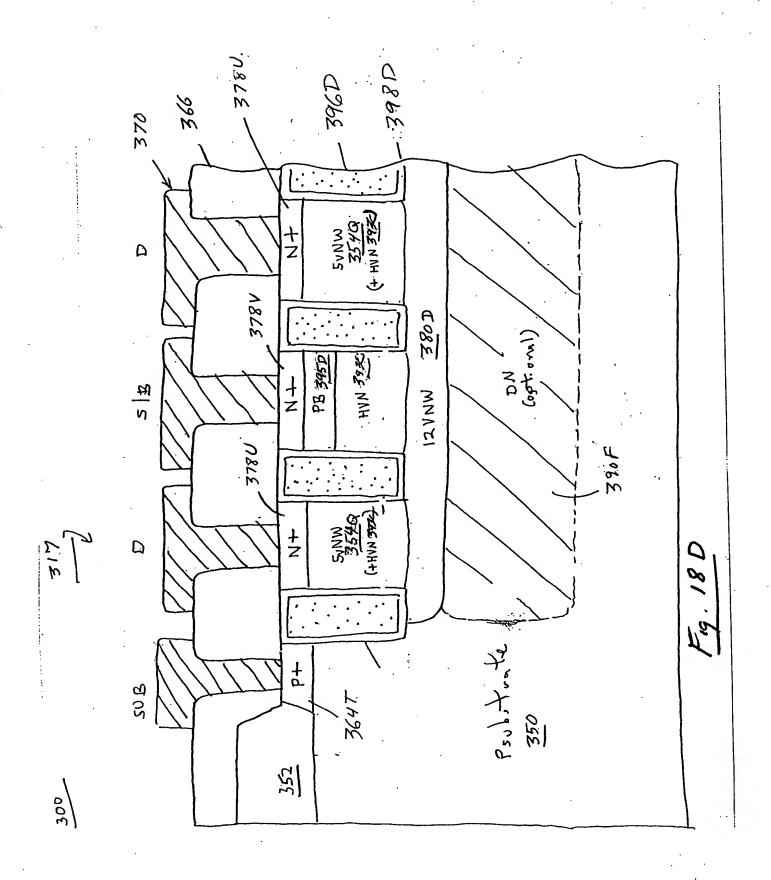
F19. 18A

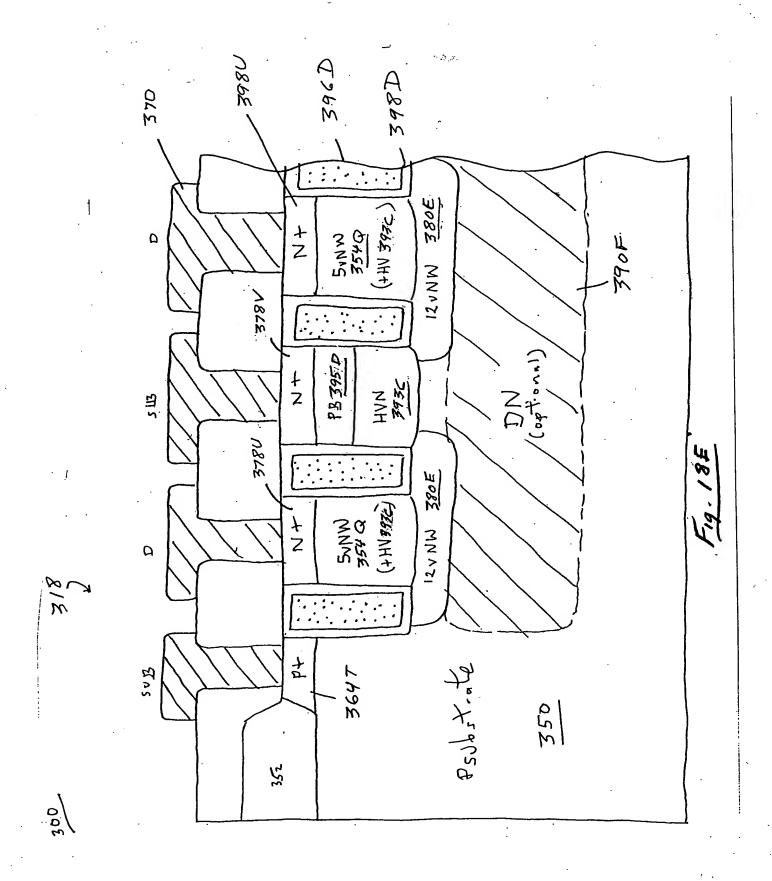


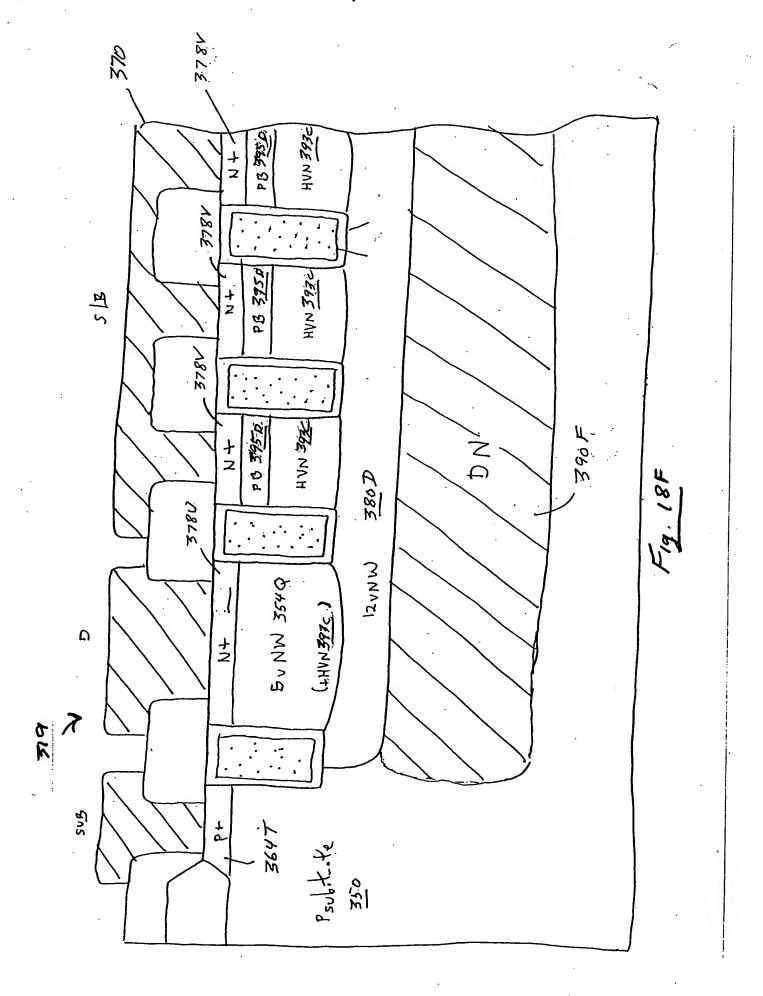
F.9. 18B



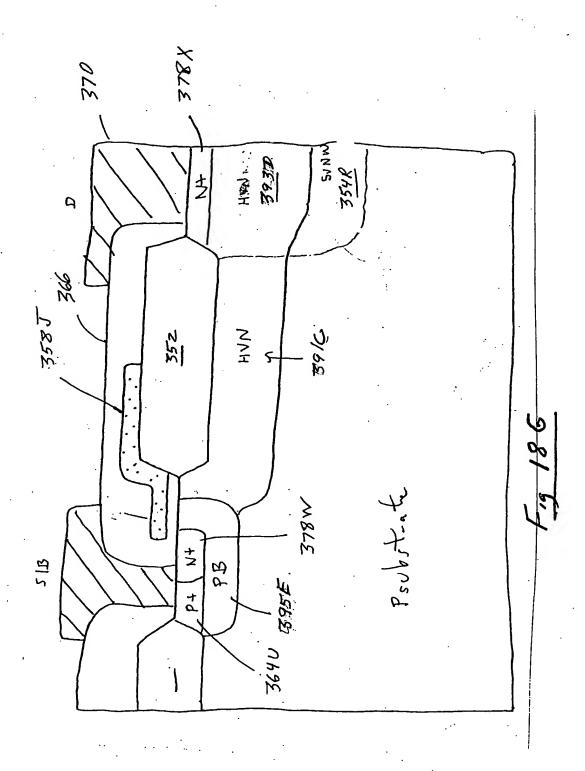
F19 18C

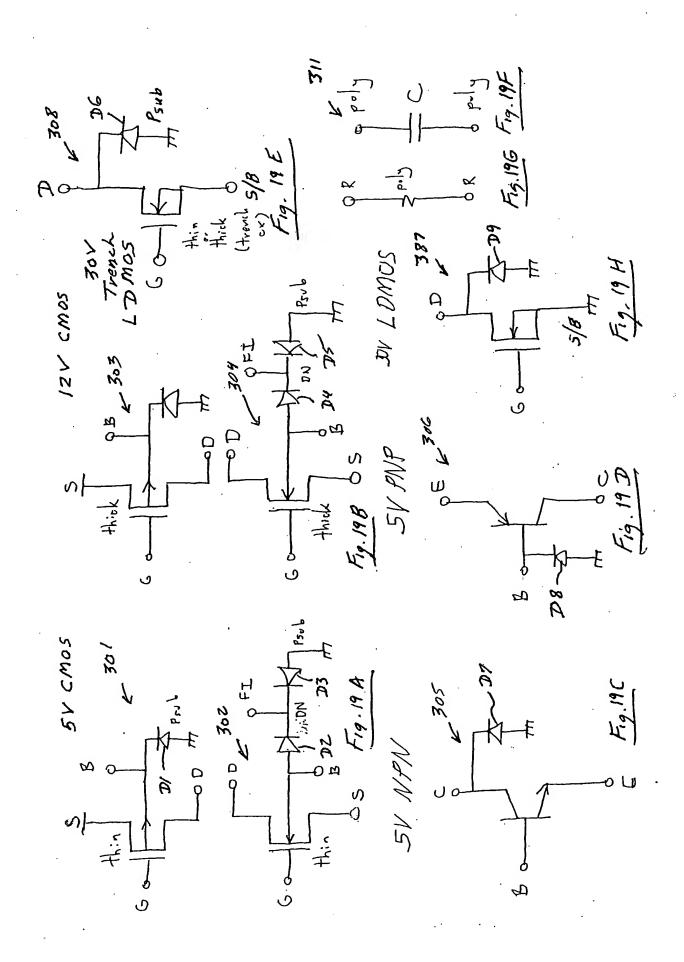


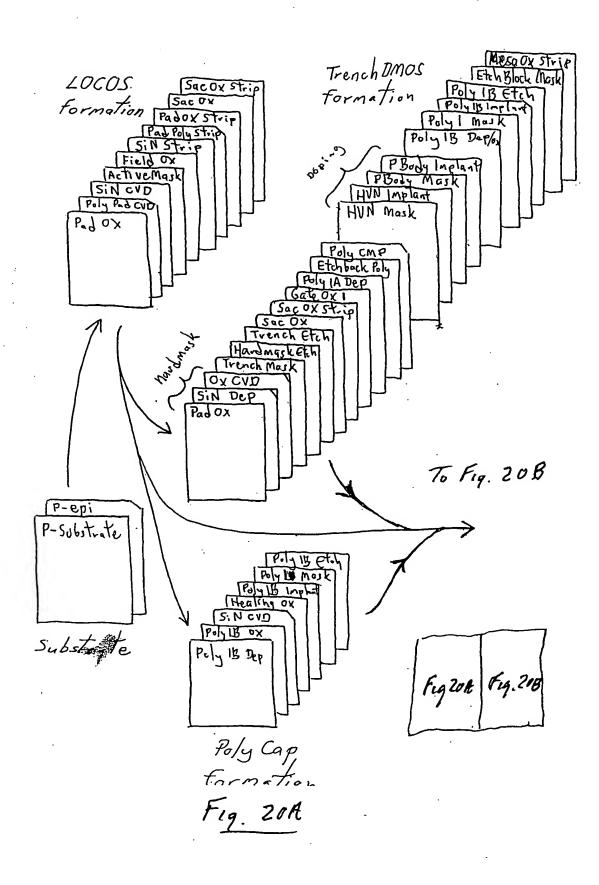




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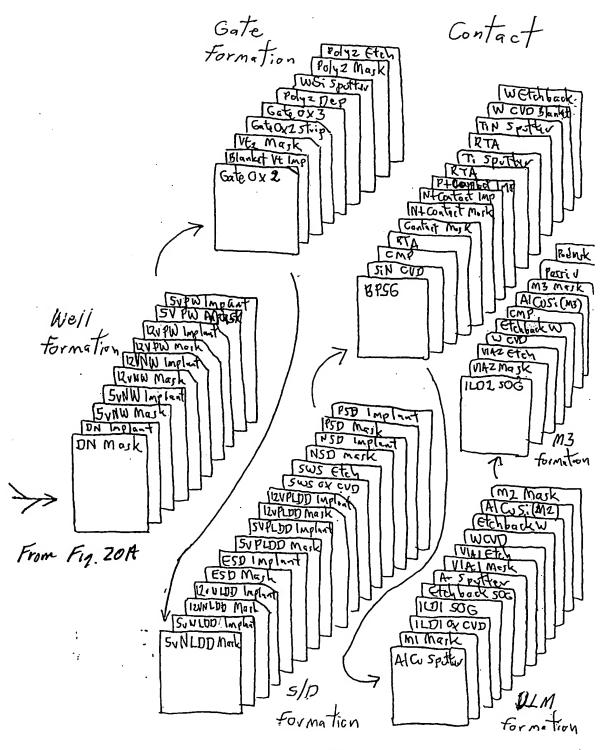
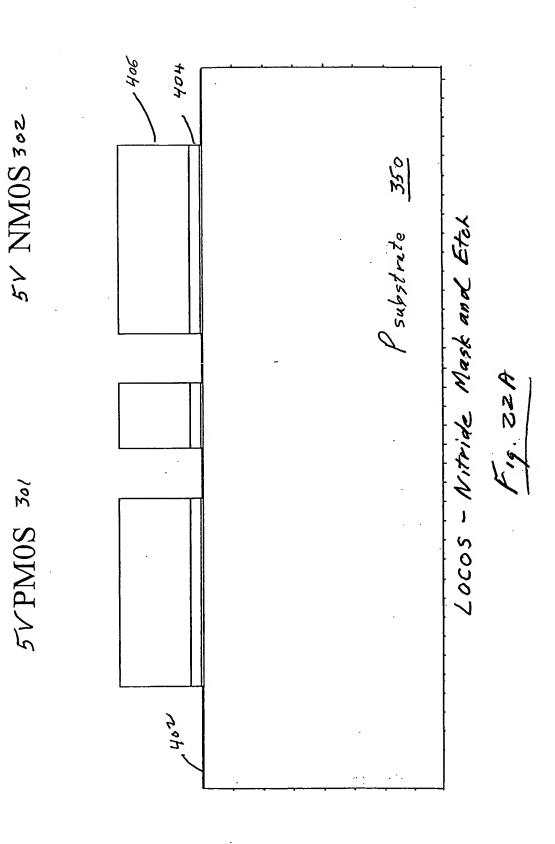


Fig. 20B

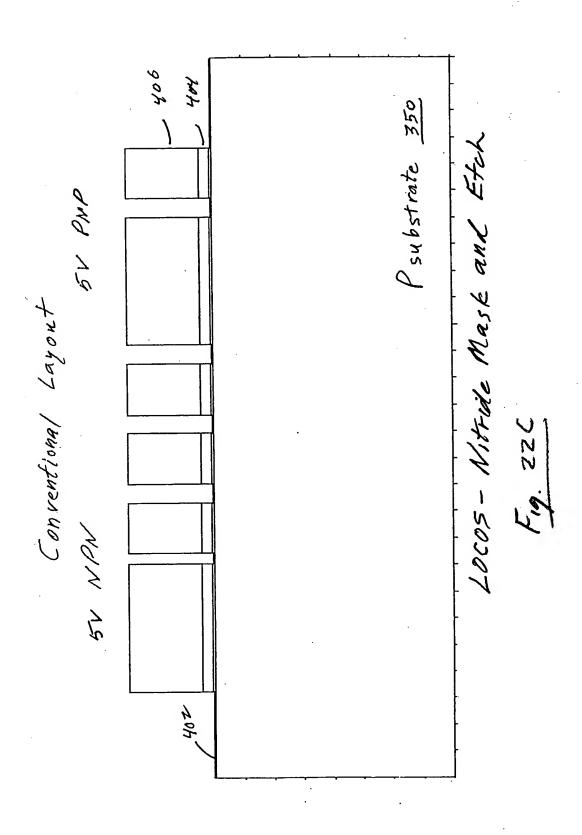
350 First Pad Oxide Layer Fig 21

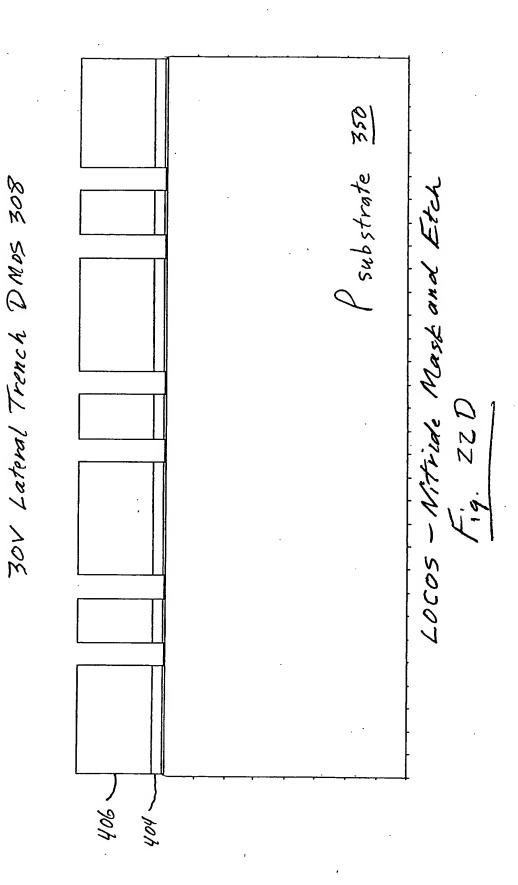
70h



90% -404 Psubstrate 350 Locos - Witrike Mask and Etch 5V PNP 306 High Fr Layout 5V NPN 305 704

F19. 22B





HOH!

Symmetrical 12 V CMOS

12V PM0S 309

12V NM0S 310

Psubstrate 350 LOCOS - Witride Mask and Etch

352 404 Psubstrate LOCOS - Field Osidation Fig. 23A 353

5V PM0S 301

51 NMOS 302

352

404

407

hoh

352

High Fr Layout

SV NPN 305

3 V PNP 306

352 X 352 X 552 X

2000s - Field Oxidation

F19. 23B

355 Psubstrate 350 SVPNP Conventional Layout LOCOS - Field Oxidation 404 Fig 23C SV NPN hoh 355

352 350 304 Lateral Trench DMOS substrate HON - 352 # **** #*** 352 HOH

LOCOS - Field Cridation

Fig. 23D

DIE. SOWN 121 Symmetrical 12V CMOS 404 " substrate Locos - Field Oxidation F19: 23E 352 12 r PMOS 309 404

352 Psubstrafe 350 408 Second And Oxide Layer Fig. 24A 408 352

5V PM0S 301

5V NM0S 302

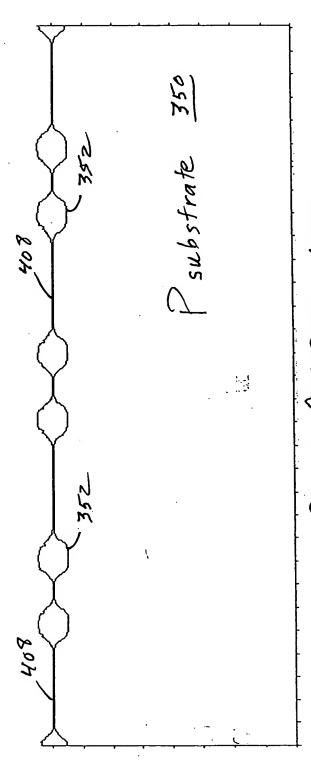
Substrate 350 308 AND 15 80% High Fr Layout 80h SV NPN 305 352 355

Second Pad Oxide Layer

F19. 248

Vsubstrate 350 80h Second Rad Oxide Layer Conventional Layout Fig. 24C . 7 804 5V NPN 355

30V Lateral Trench DMOS 308

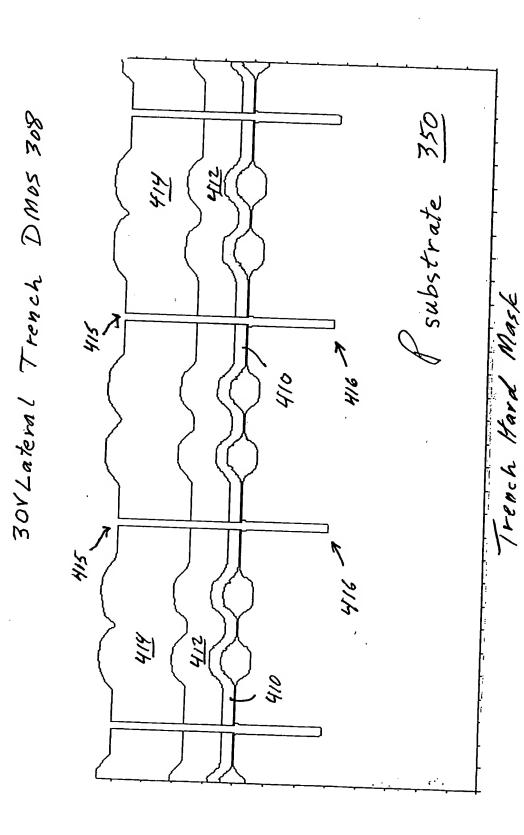


Second Pad Oxide Layer

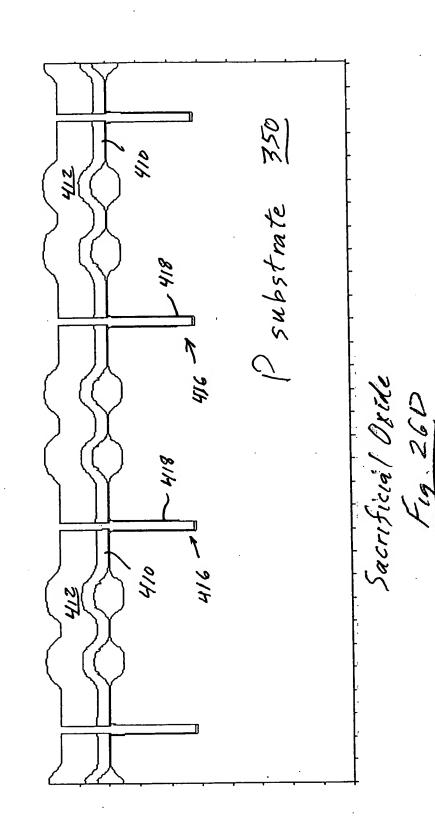
12V PMOS 309 12V CMOS 710

Psubstrate 350 .408 352 804

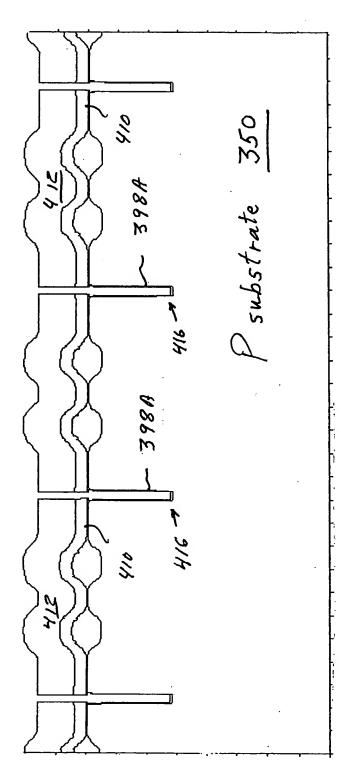
Second Pad Oxide layer



30V Lateral Trench DMOS 308

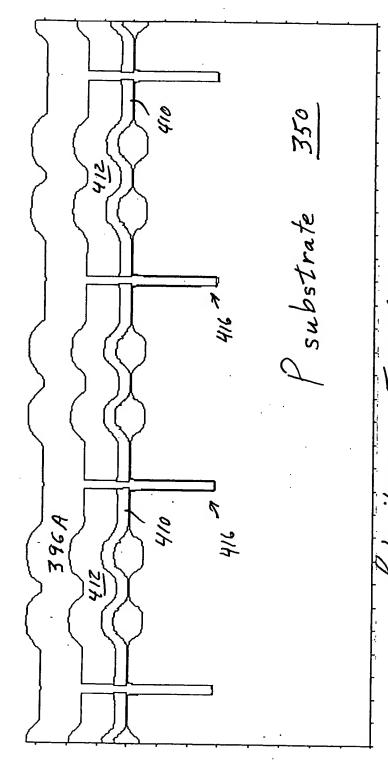


30 V Lateral Trench DMOS 308



Trench Gate Oxide

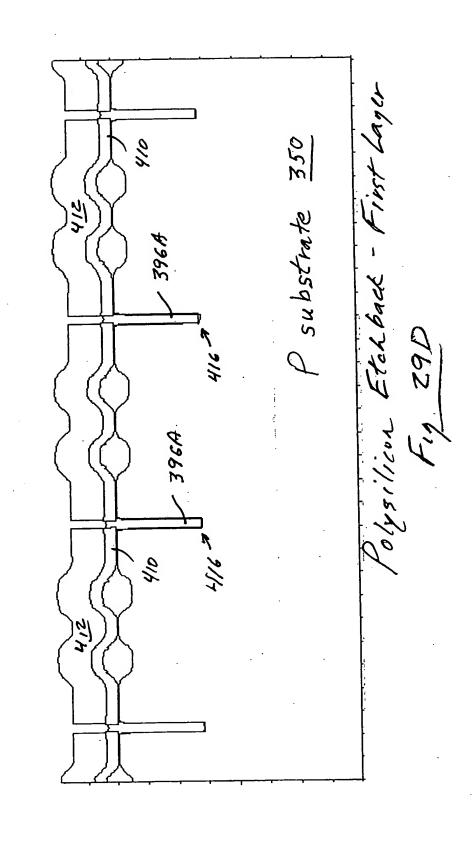
30 V Lateral Trench DMOS 308



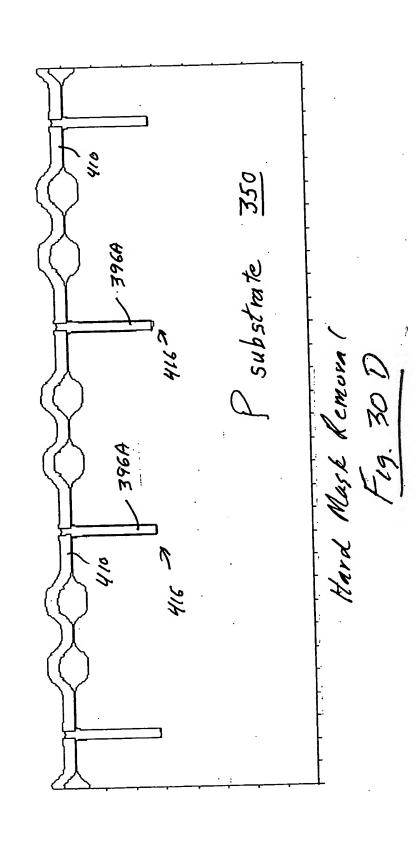
Polysilicon - First Layer

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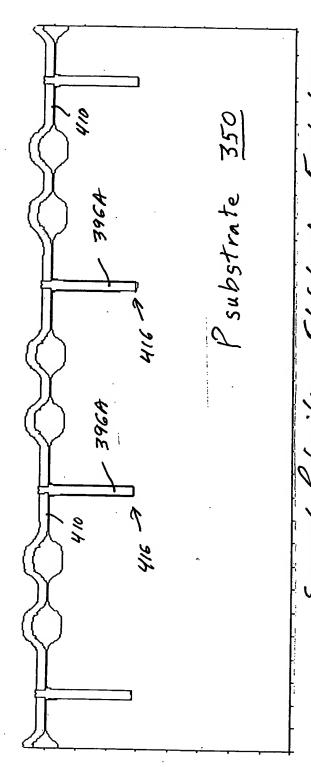
30V Lateral Trench DMOS 308



30V Lateral Trench DMOS 308

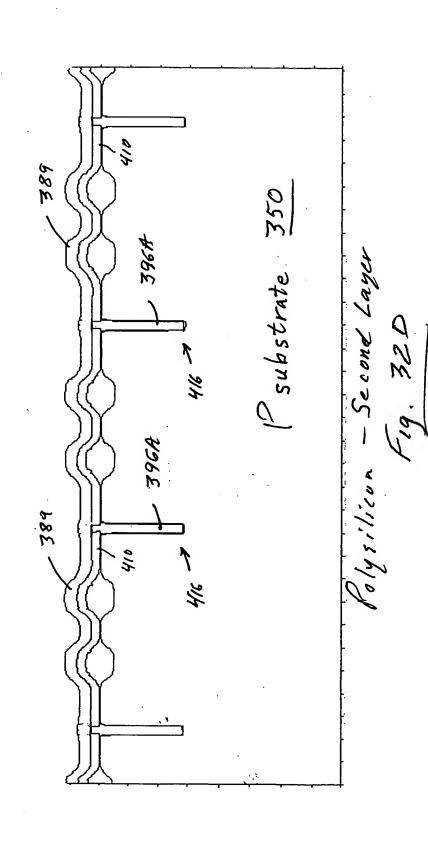


- 30 V Lateral Trench DMOS 308

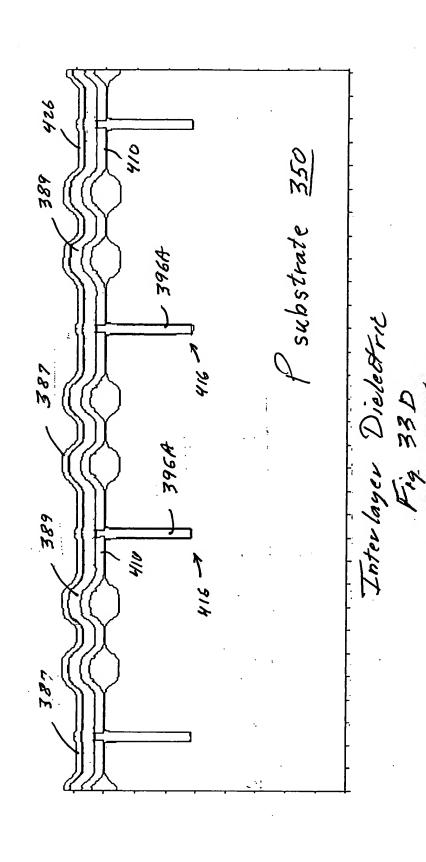


Second Polysilien Etchback - First Layer Fig. 310

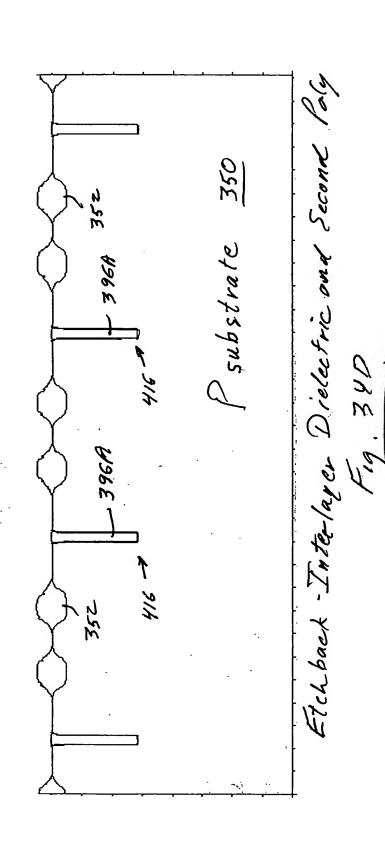
30V Lateral Trench DMOS 308

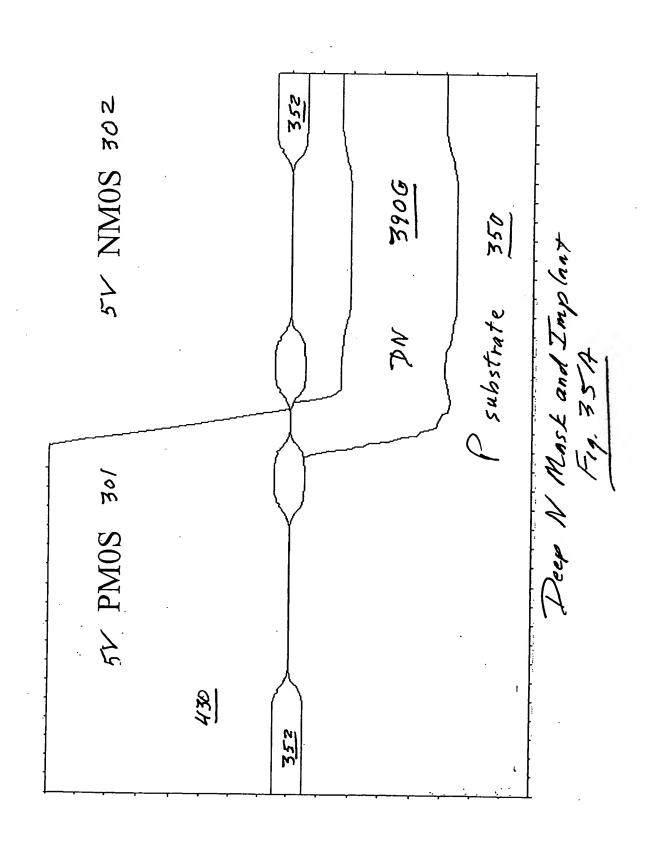


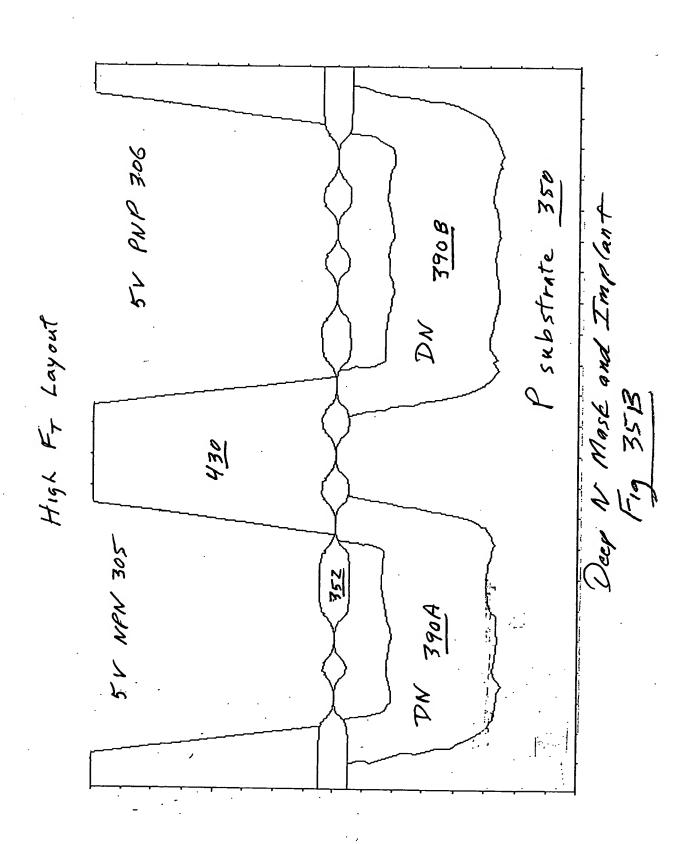
308 30V Lateral Trench DMOS

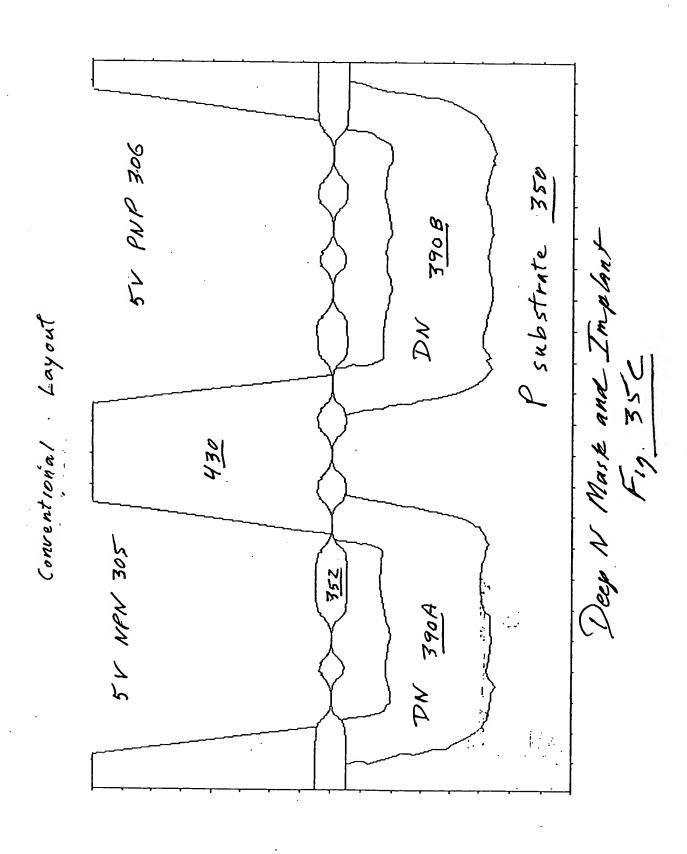


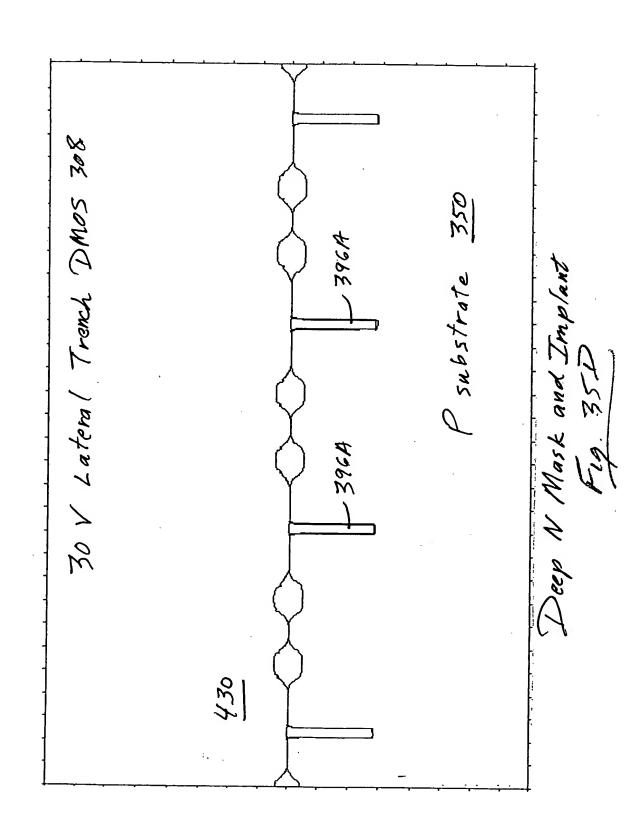
30 V Lateral Trench DMOS 308

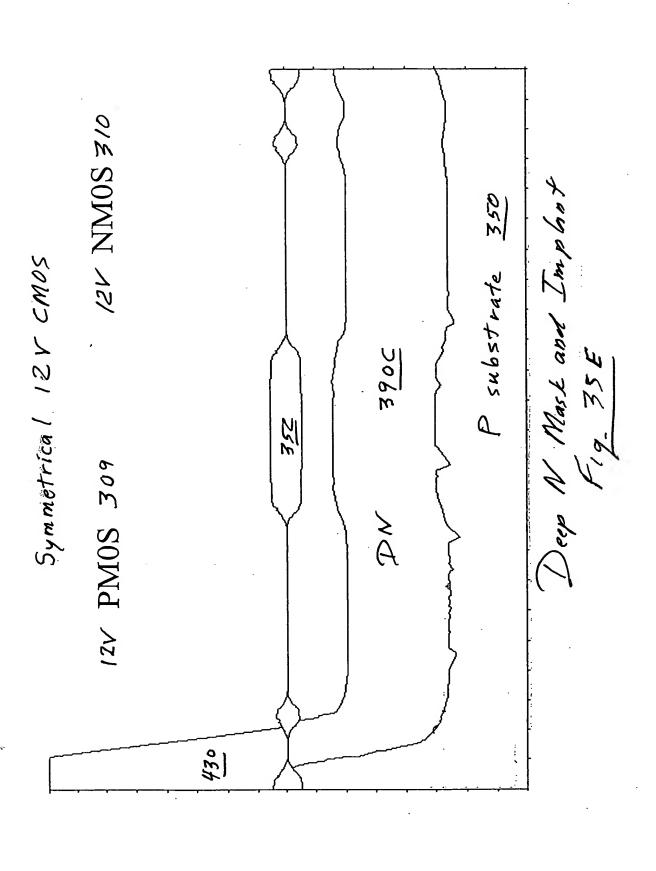


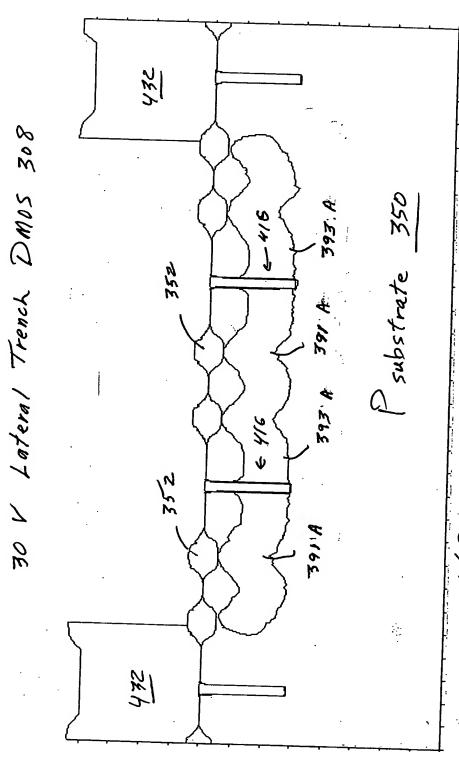








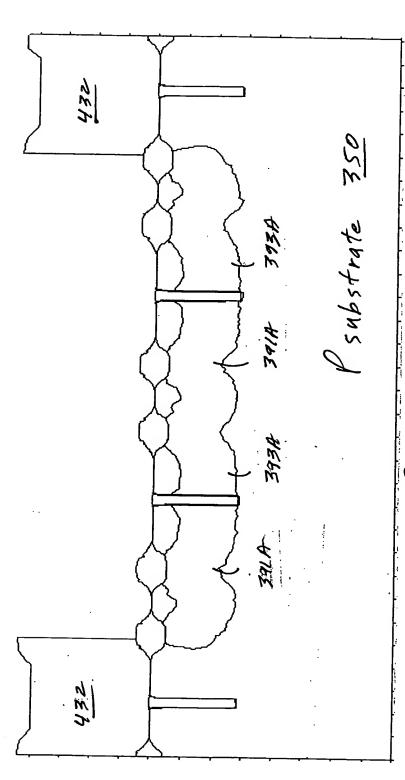




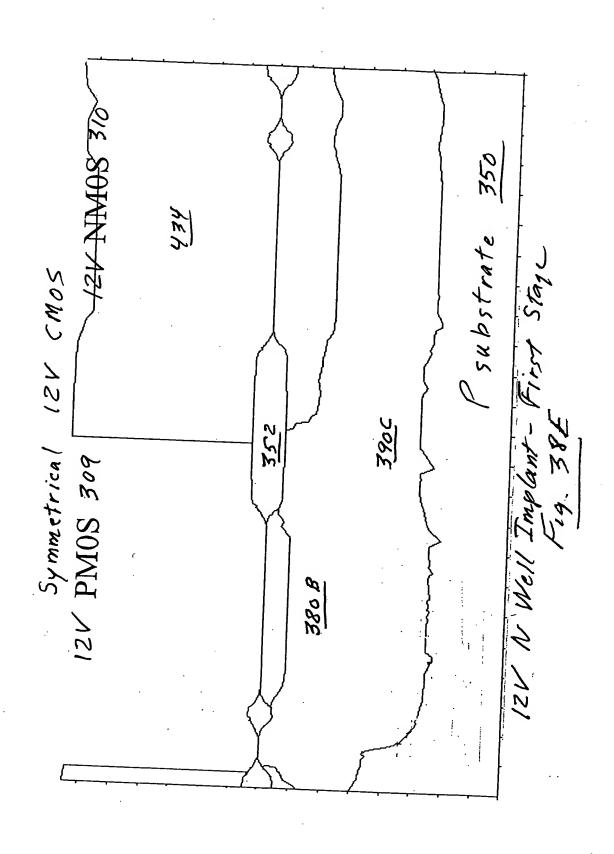
N Drist Implant - First Staye

F19, 360

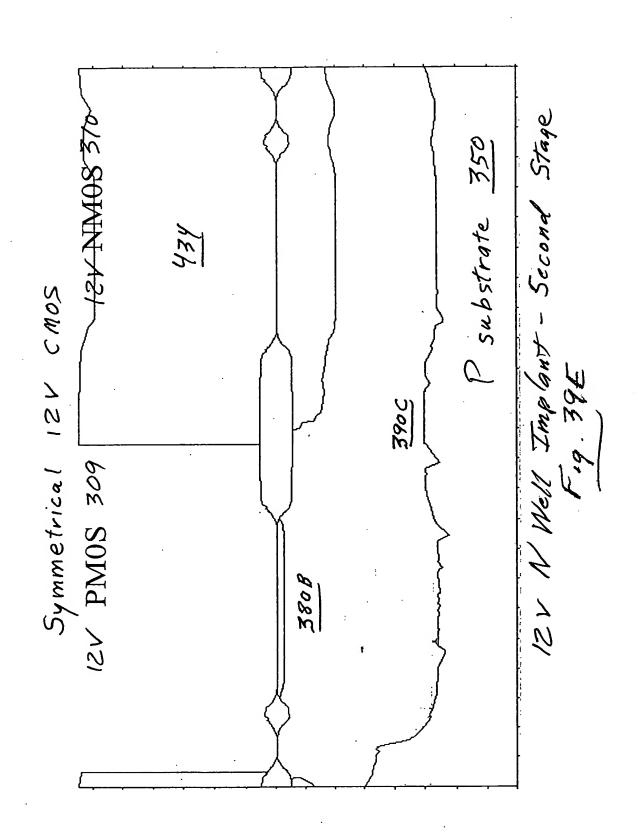
30 V Lateral Trench DMOS 308

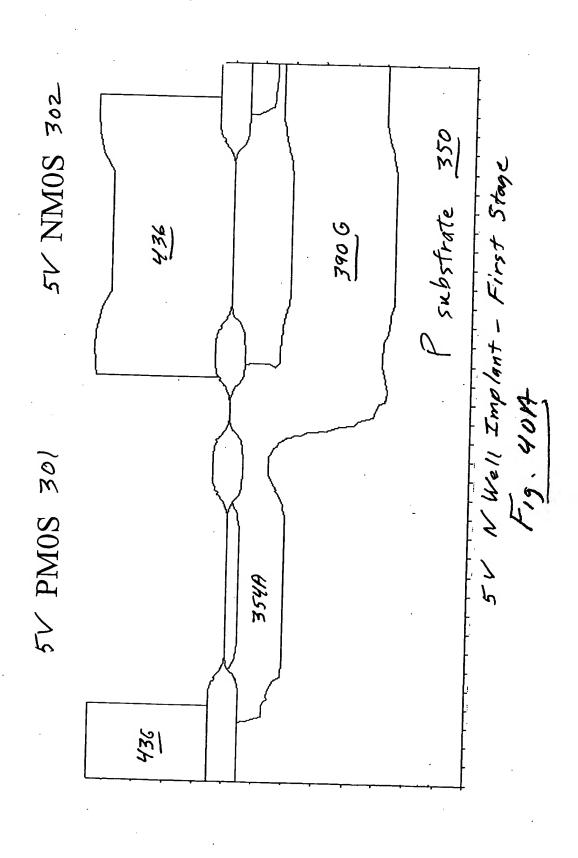


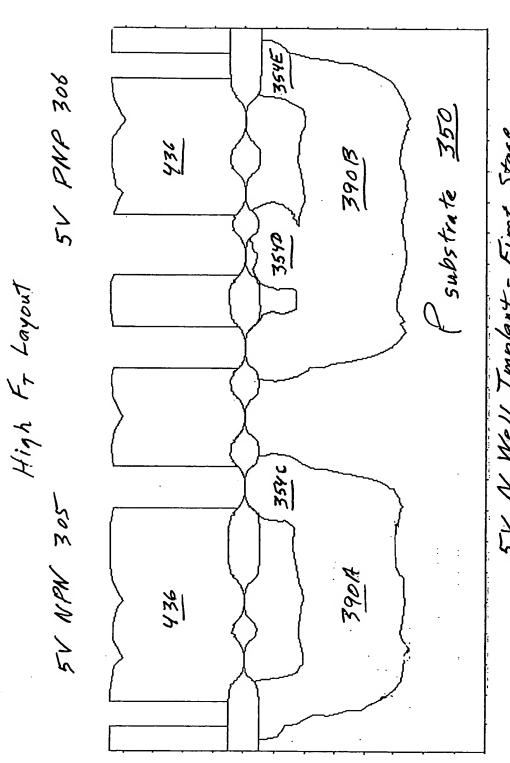
N Drist Impart - Second Stage Fig. 370



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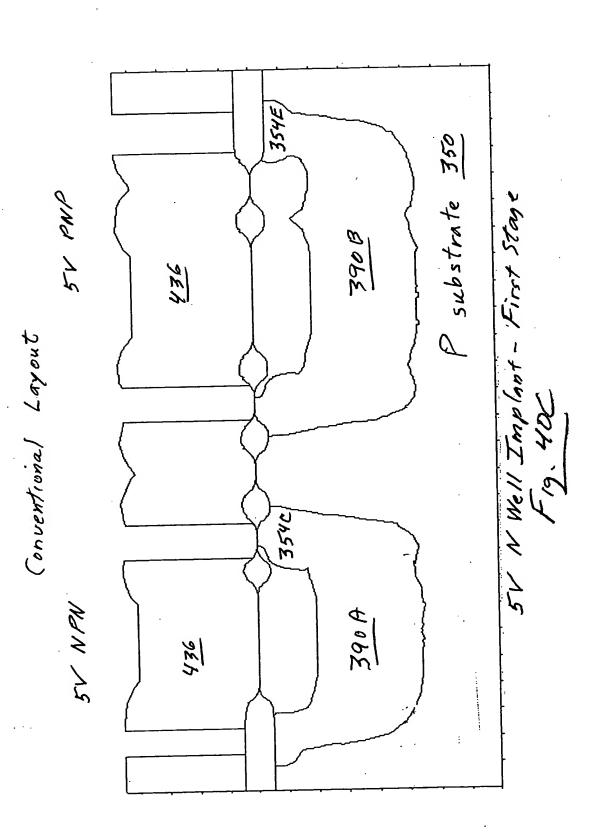




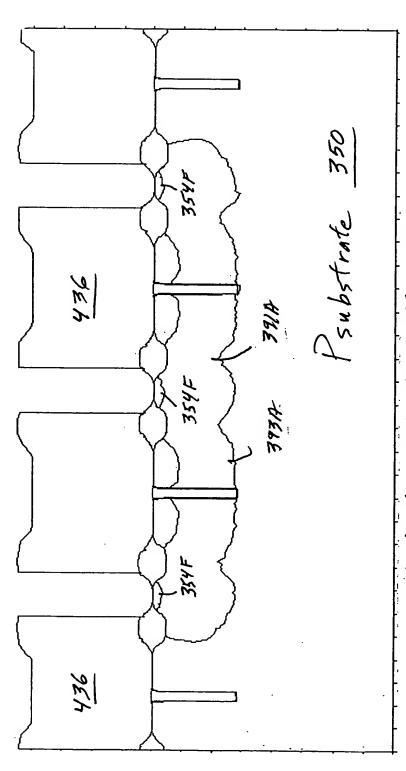


5V N Well Implant - First Stage

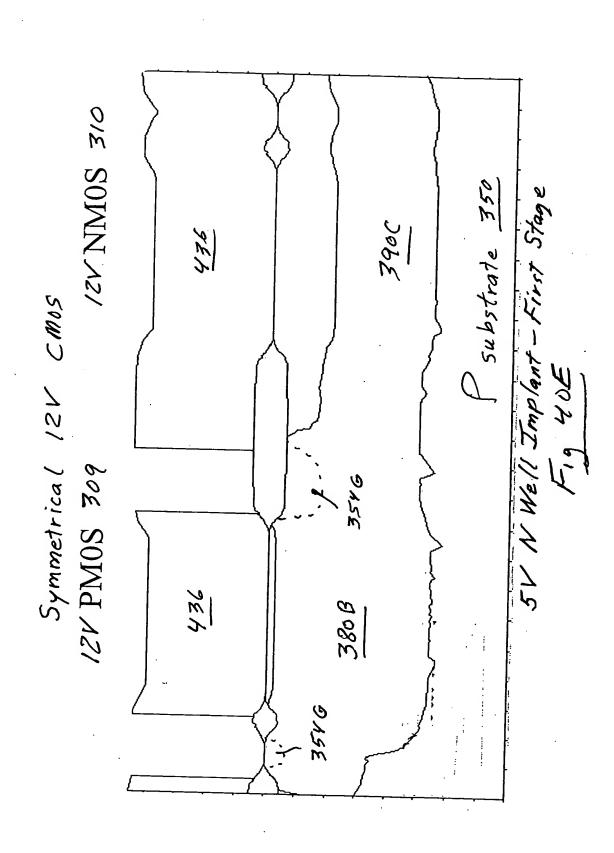
F12 408

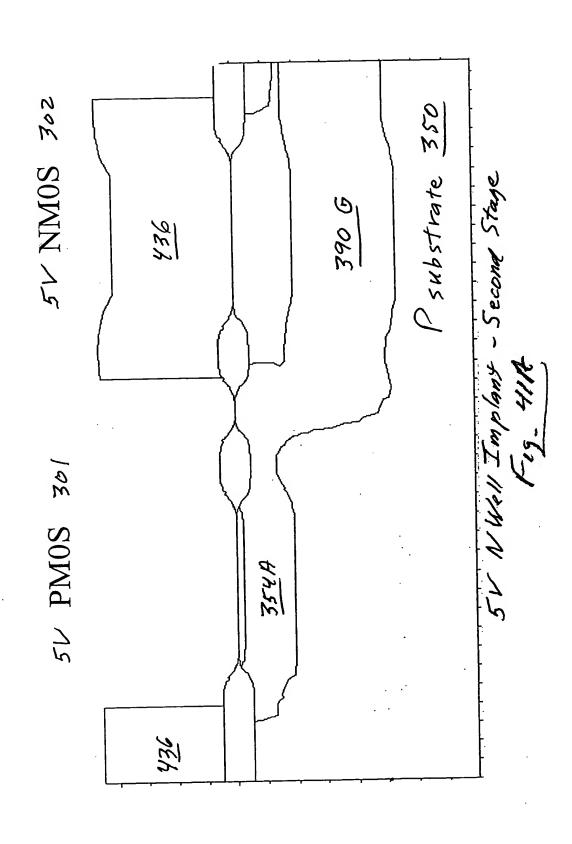


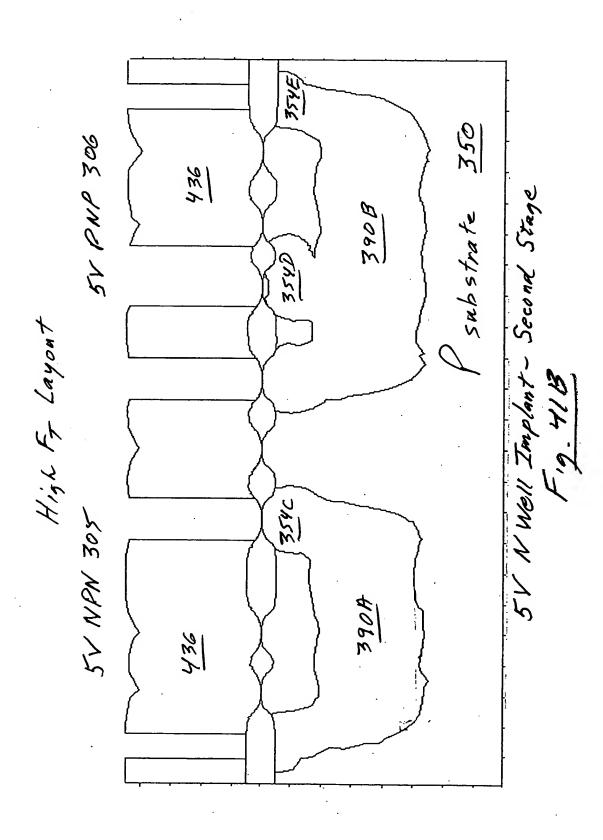
30V Lateral Trench DMBS 308

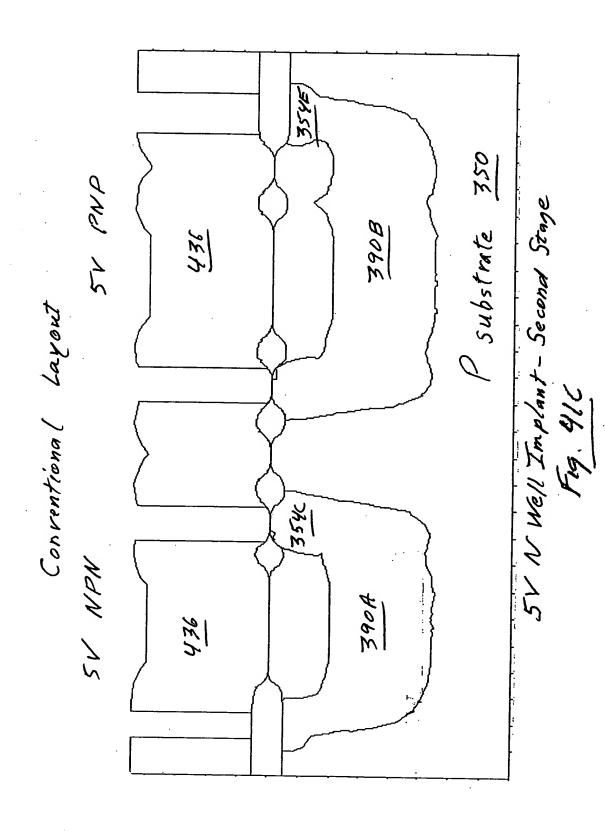


5V NWell Implant - First Stage

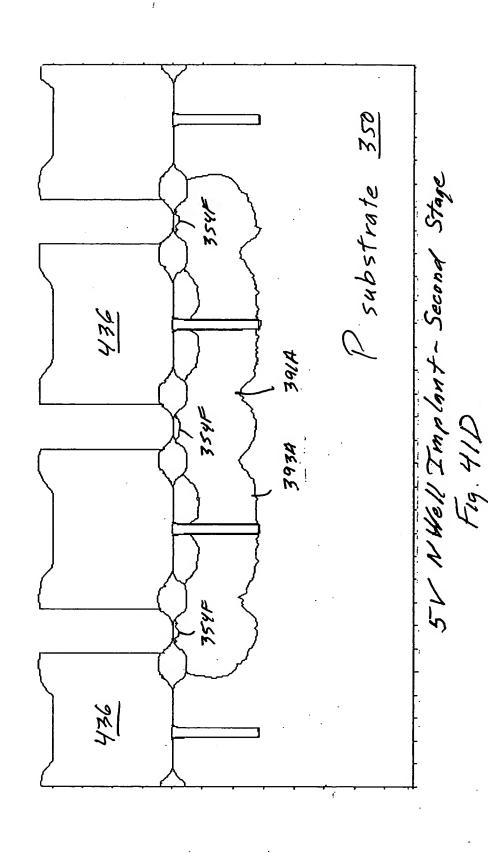


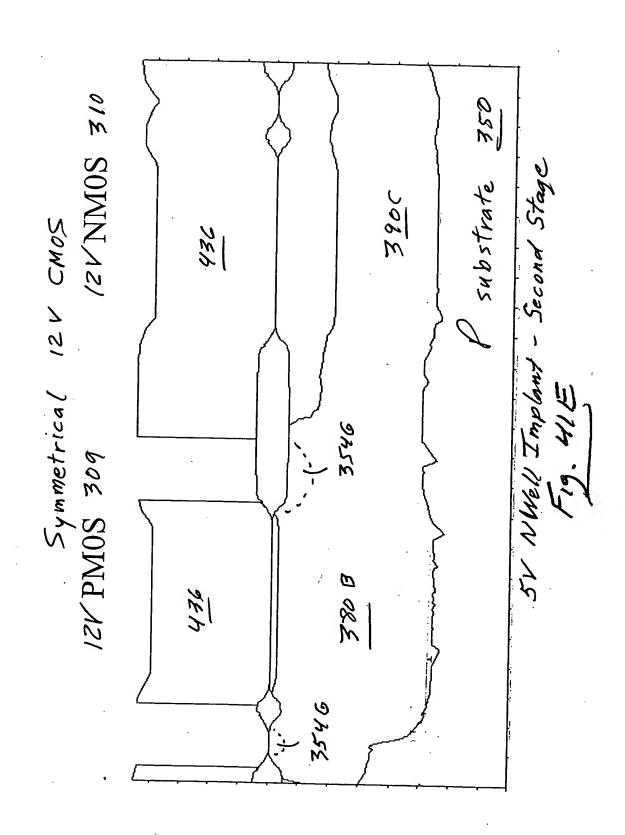


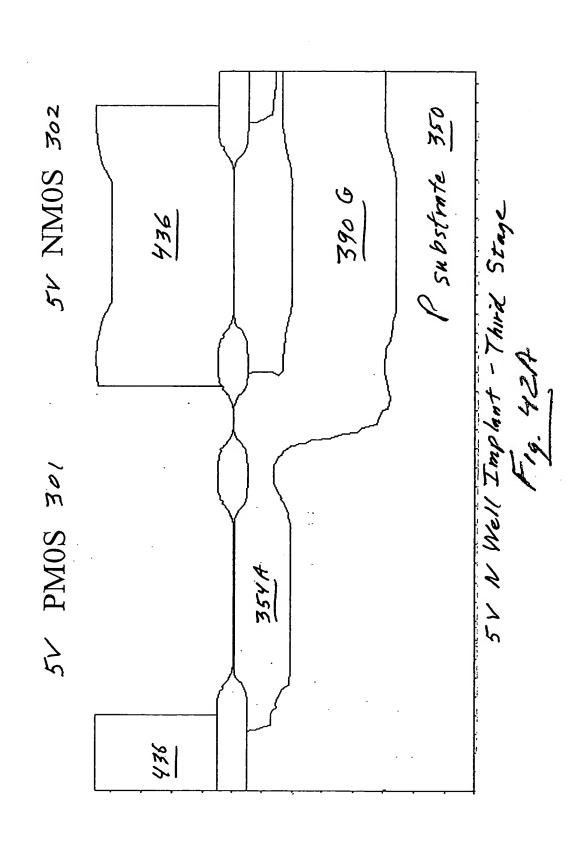


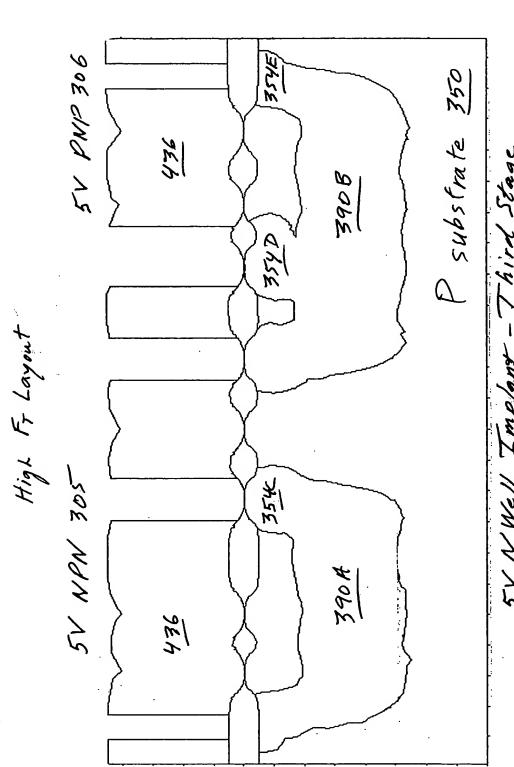


30V Lateral Trench DMOS 308



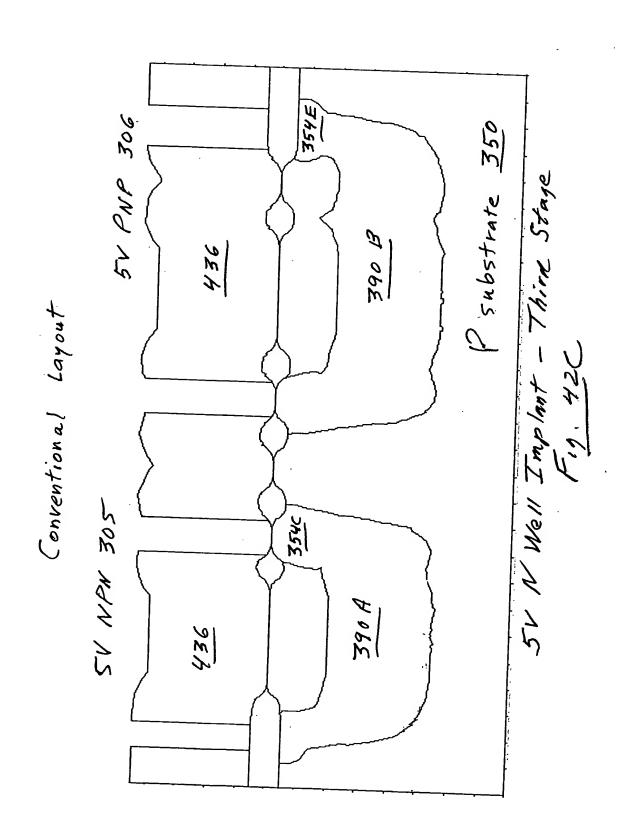




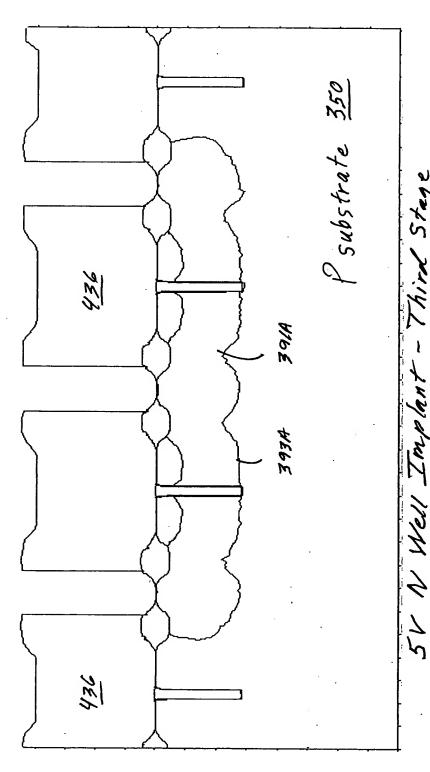


5V NWEll Implany - Third Stage

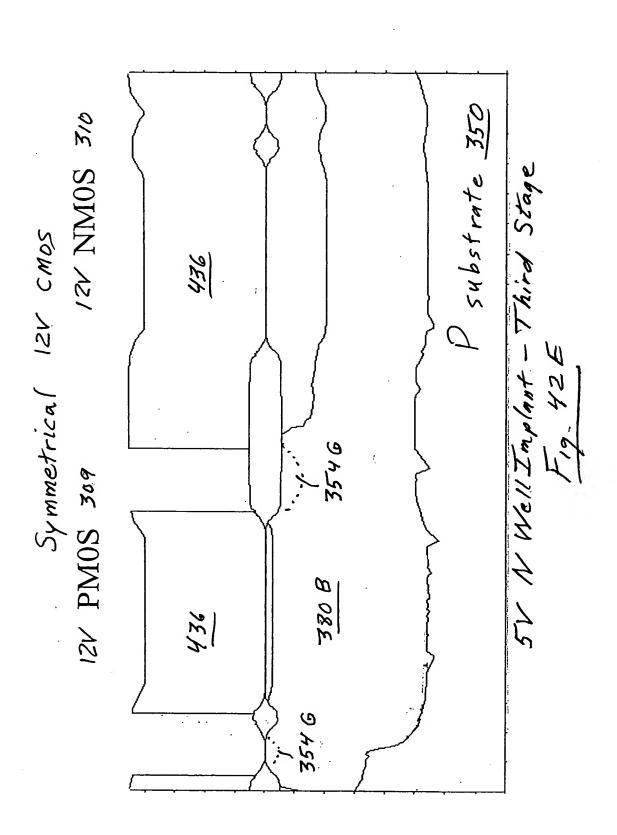
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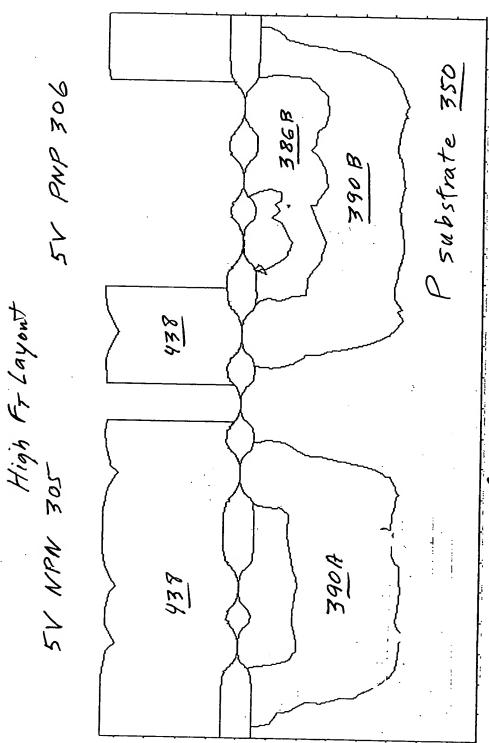


30V Lateral Trench DMOS 308

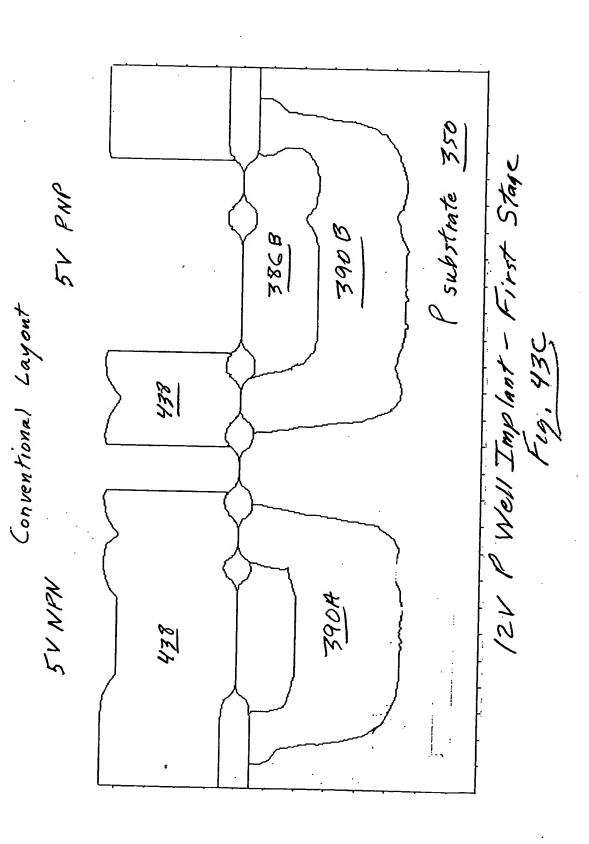


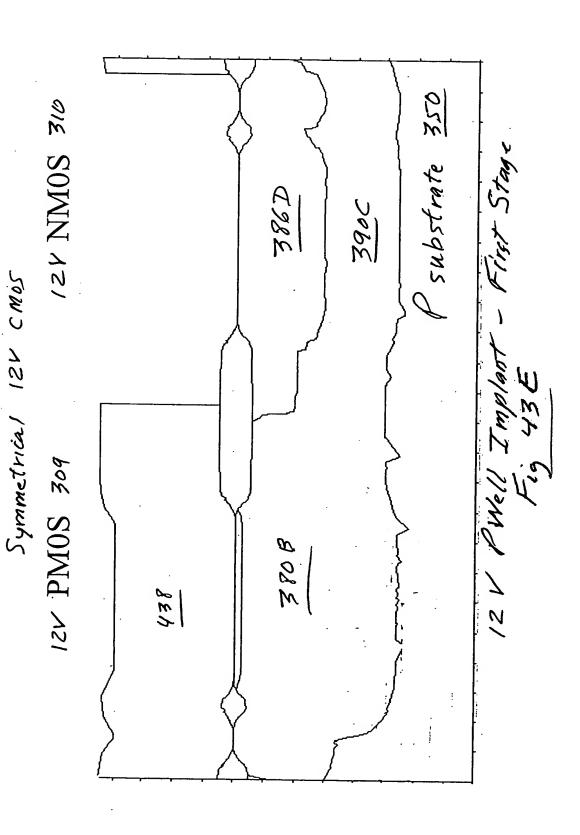
5V N Well Implant - Third Stage





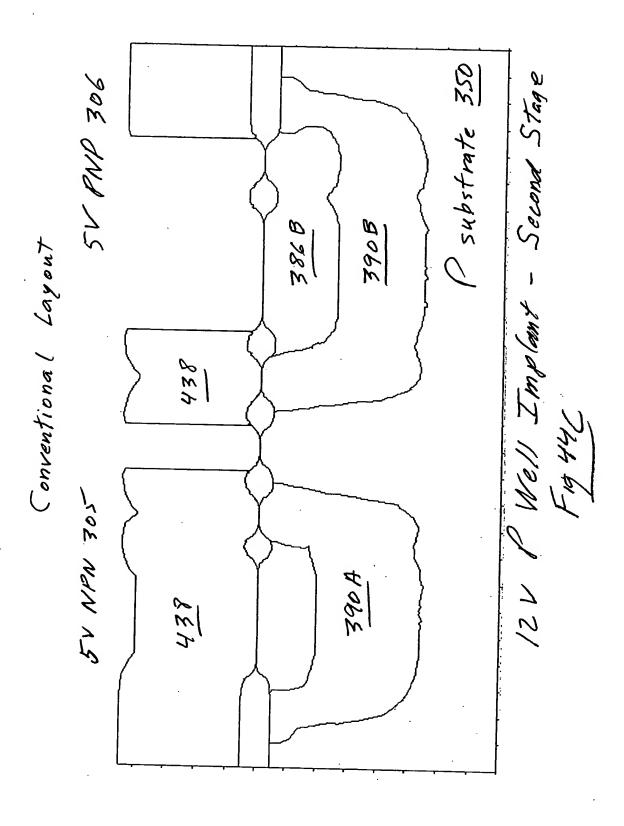
12V P Well Implant - First Staye Fig. 43B

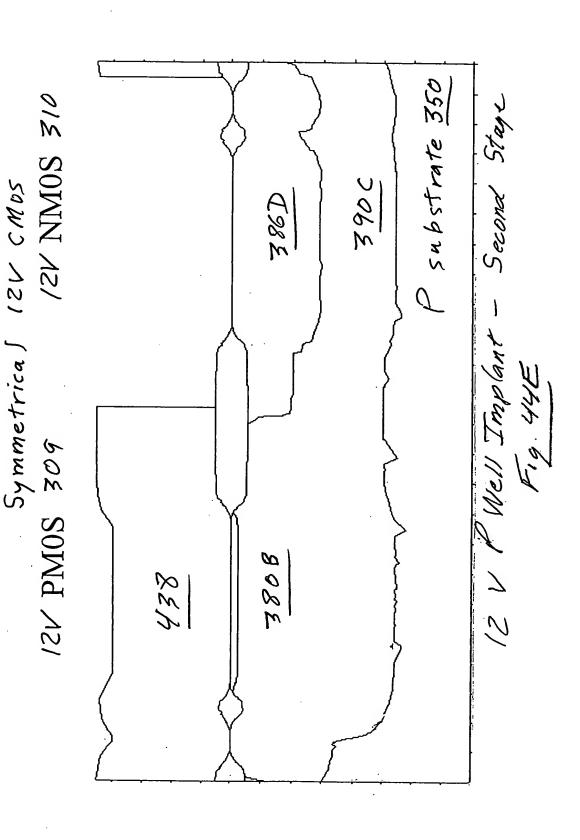


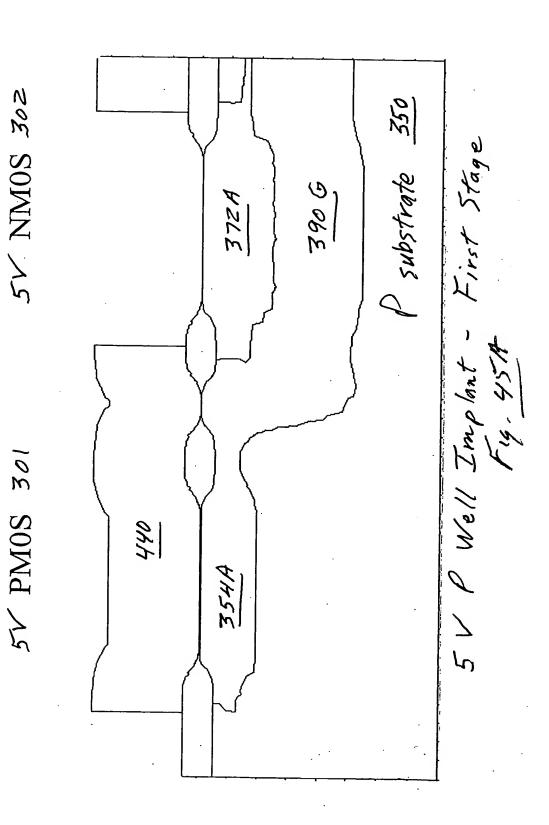


P substrate 350 5V PNP 306 E1 98 E 340 B High Fr Layout 438 5V NPN 305 390 R 438

12V P Well Implant - Second Stage Frg. 44 B







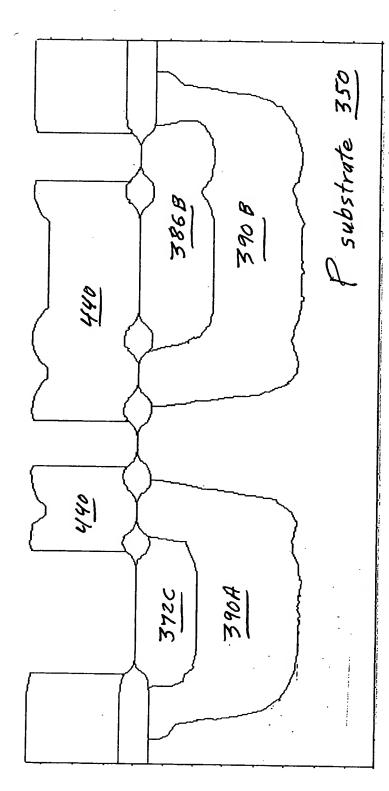
1 substrate 350 5V. PNP 306 386 B 390 8 246 High FT Layout 460 5V NPN 305 340 A 3720

5V P Well Implant - First Stage

Conventional Layout

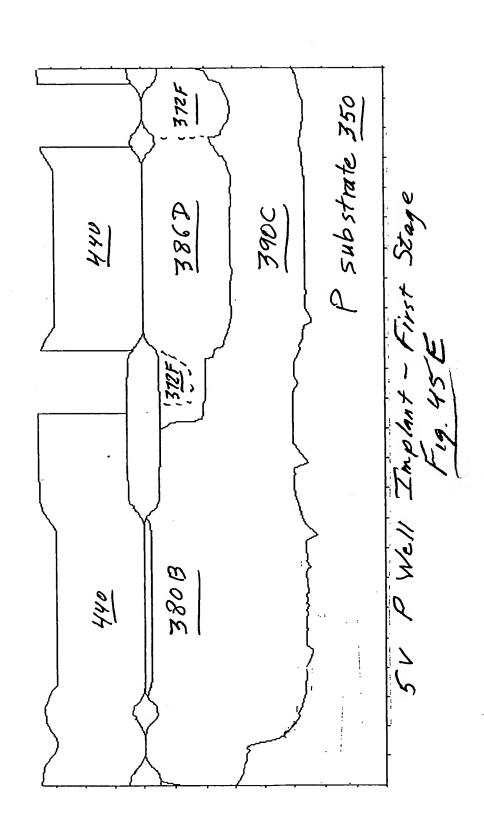
NAN 12

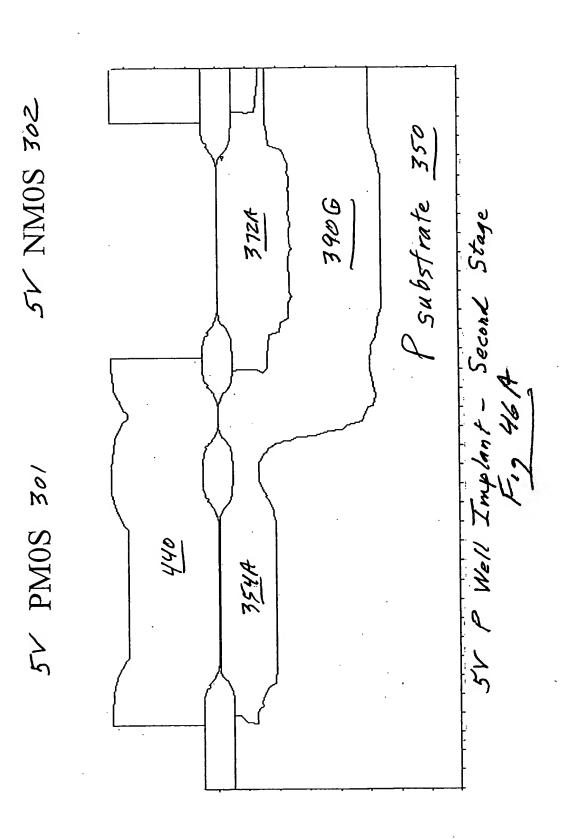
5V PNP



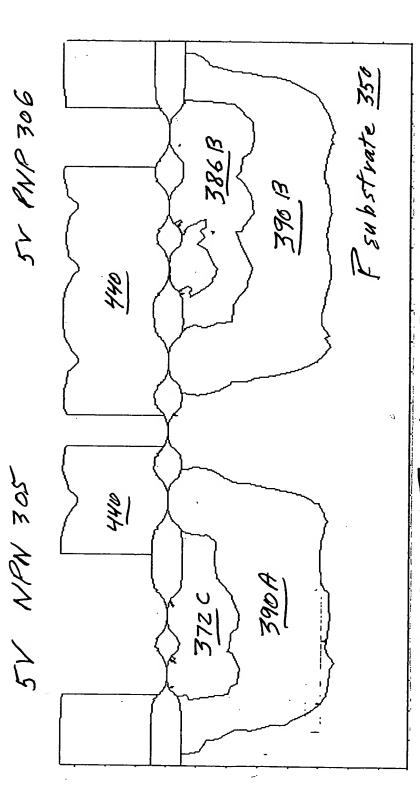
5V P Well Implant - First Stage Fig 45C

0/2 SOWN 12/ Symmetrical IZV CMOS 12V PMOS 309 12V





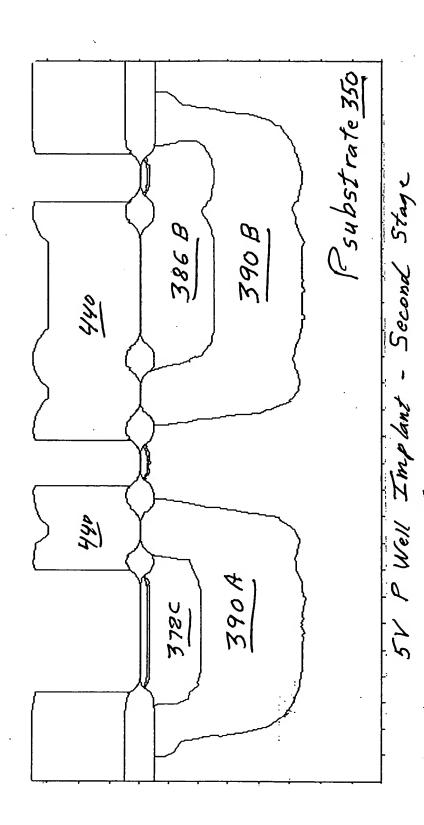
High Fr Layout



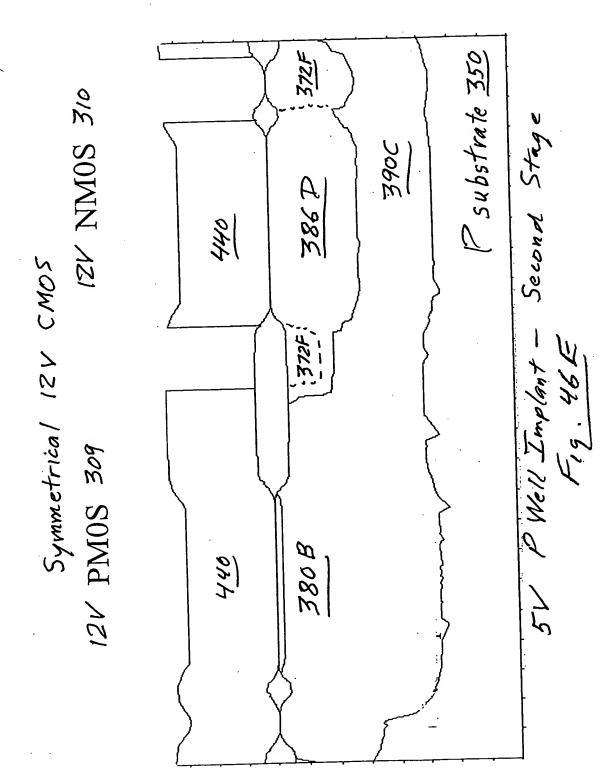
5VP Well Implant - Second Stage

0. N

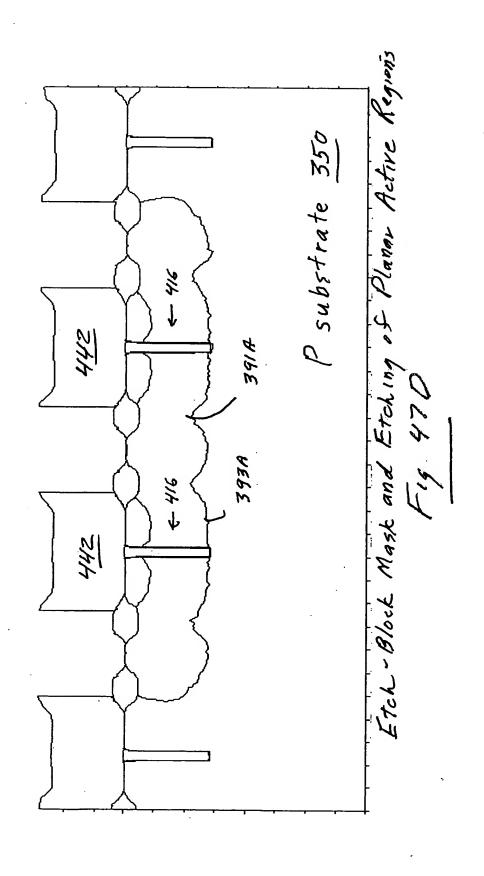
5V PNP 306 Conventional Layout 5V NPN 305



F19. 46C



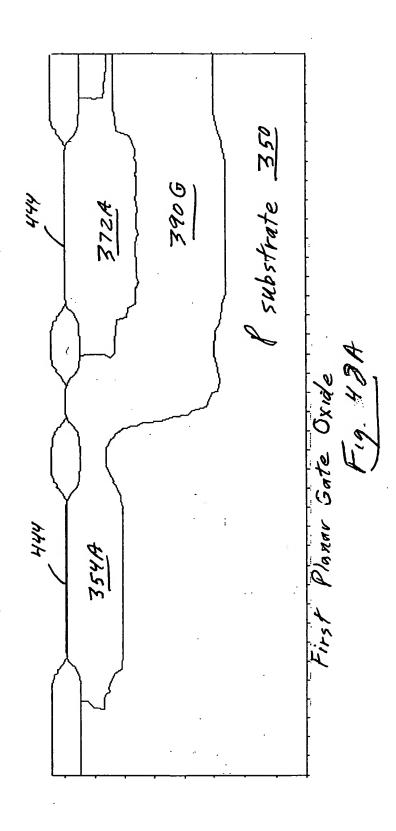
30V Lateral Trench DMOS 308



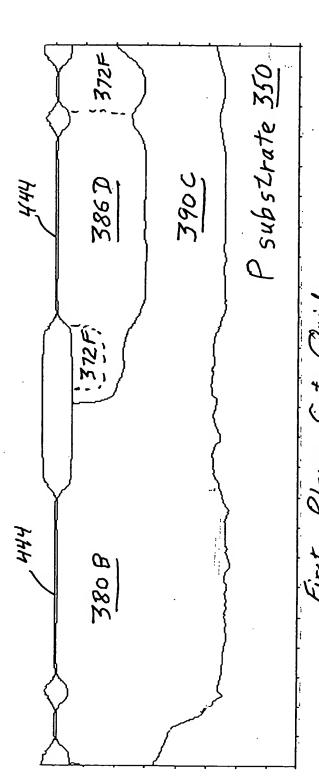
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5V PM0S 301

5V NM0S 302



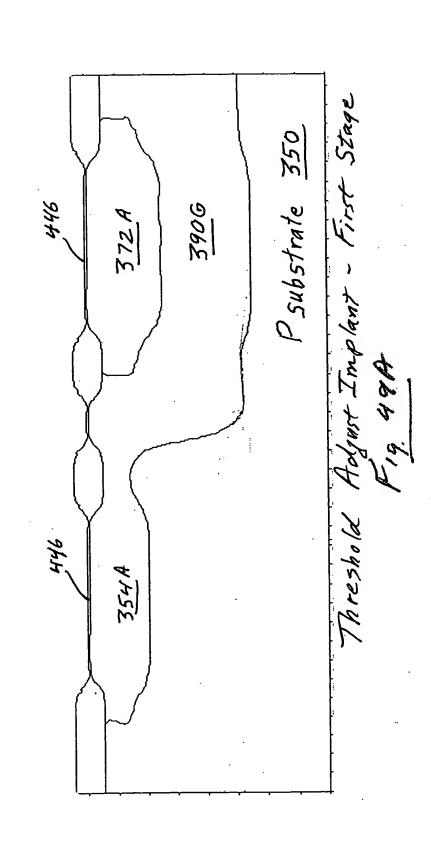
12V NM0S 310 Symmetrical 12V CMOS 12V PMOS 309 12V



First Planar Gate Oxide

5V PM0S 301

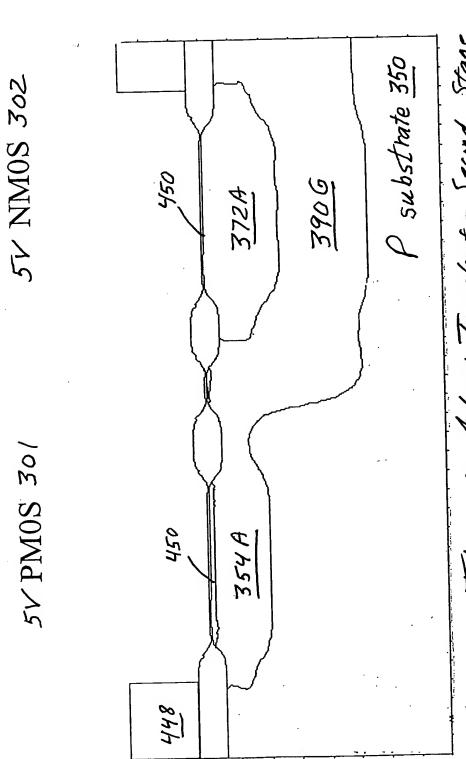
5V NM0S 302



/2V NM0S 3/0 Symmetrical 12V CMOS 12V PM0S 309

372F Psubstrate 350 390C 2440 286D 944 380 B

Threshold Adjust Implant - First Stage



Threshold Adjust Implant - Second Stage First Planar Gate Oxide Removal F19.50 A

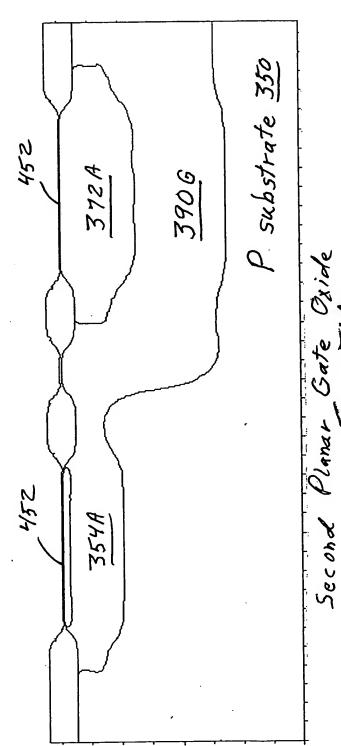
12V NM0S 310 Symmetrical 12V CMOS 12V PMOS 309 12V NM

, 372F P substrate 350 390C 386D 380B 844

Threshold Adjust Implant - Second Stage

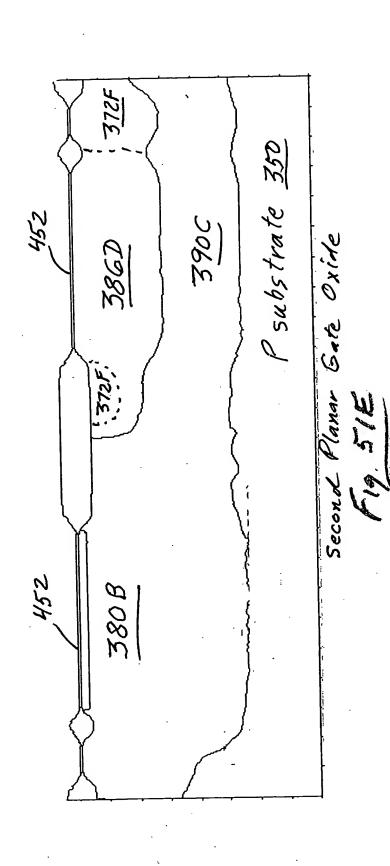
5V PM0S 301

5V NM0S 302



F10 51A

12V NM0S 310 Symmetrical 12V CMOS 12V PMOS 309 12V



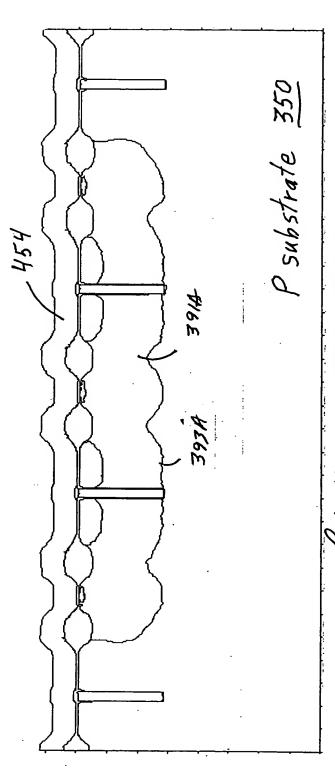
P substrate 350 3906 372A Jolysellien . 354A 424

5V PM0S 30/

51 NM0S 302

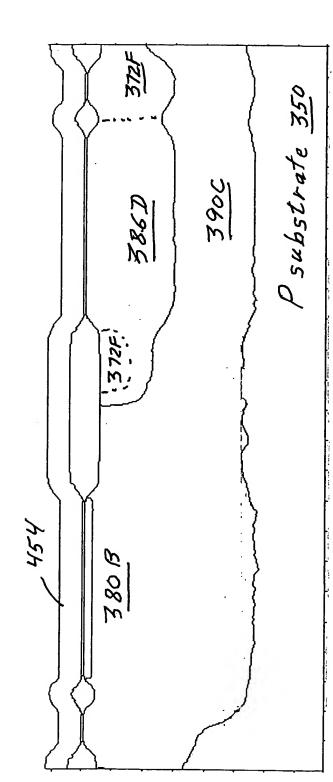
f.,

301 Lateral Trench DMOS 308

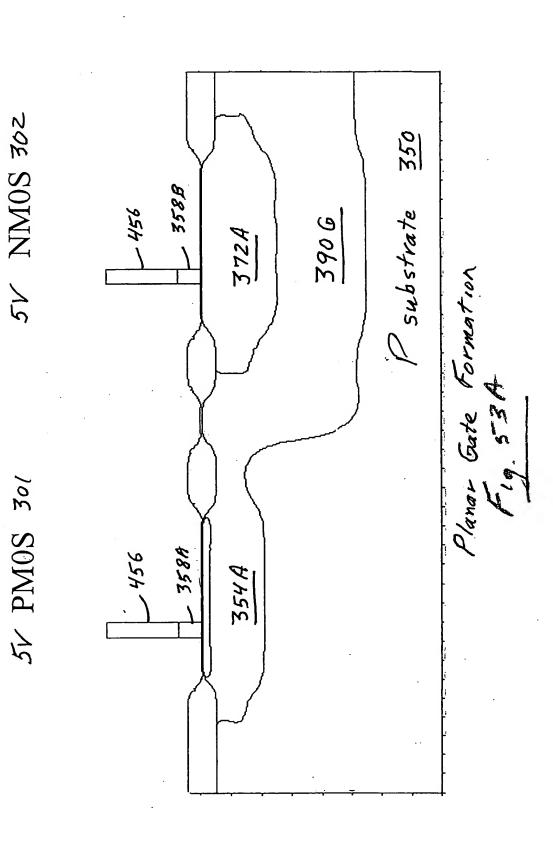


Polysilican - Third Layer

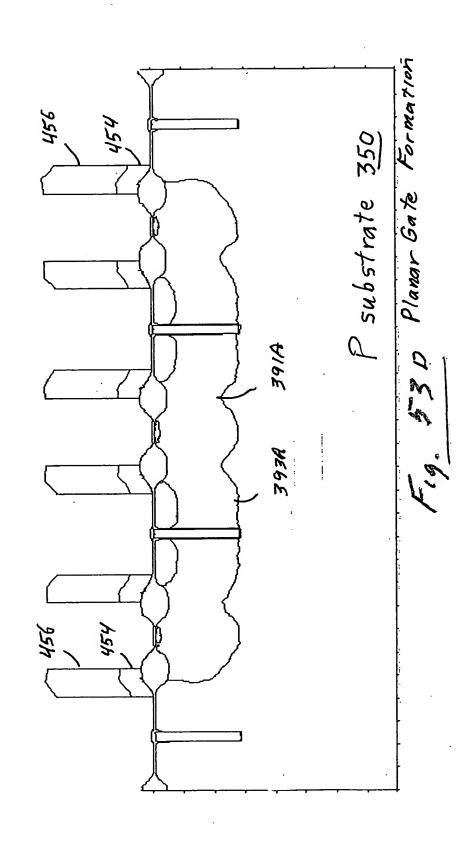
Symmetrica / 12V CMOS 12VPMOS 309 12V NMOS 310

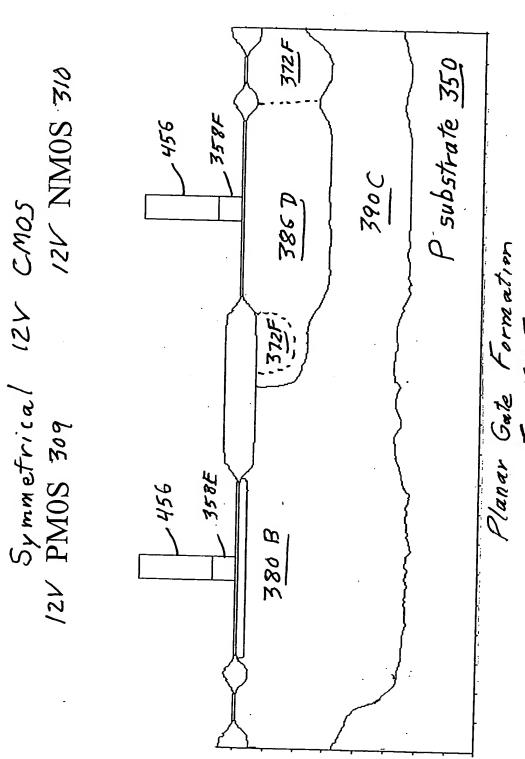


Polysilicon - Third Layer

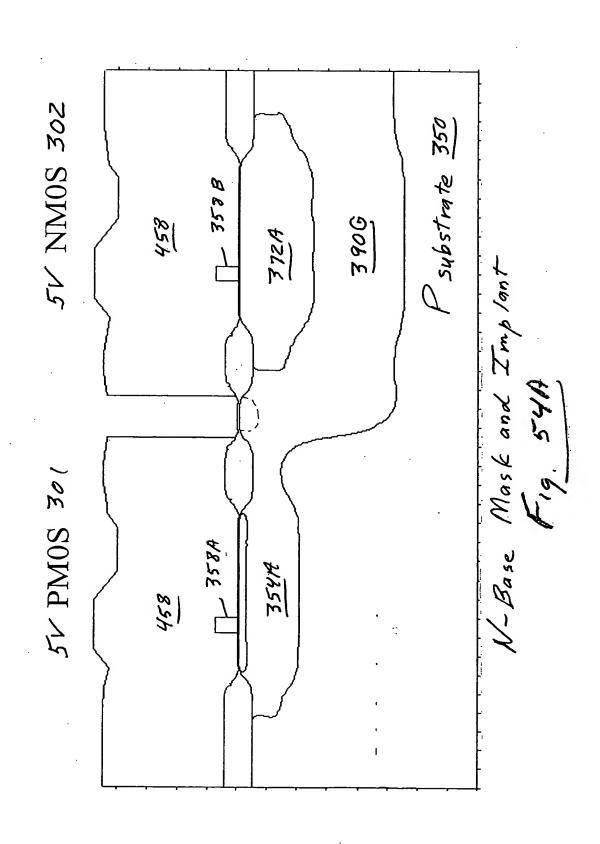


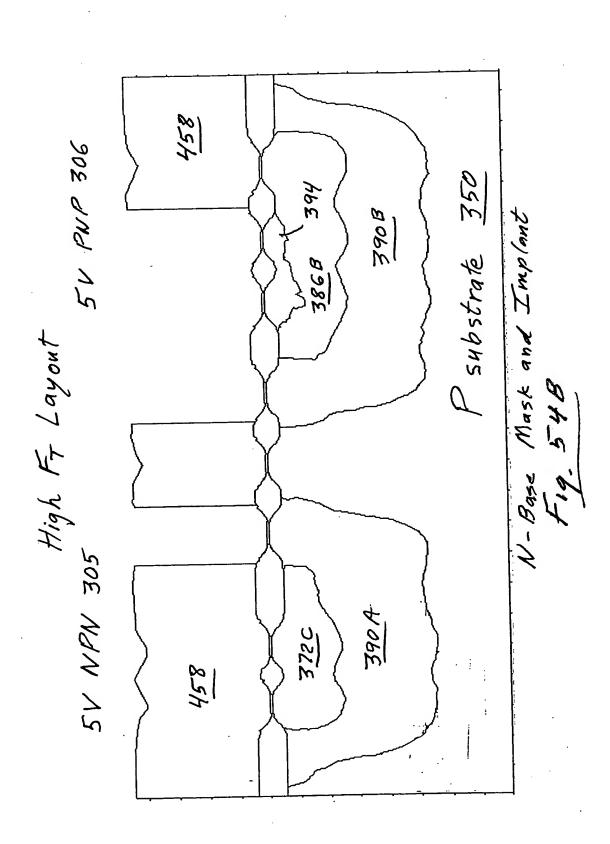
30V Lateral Trench DMOS 308

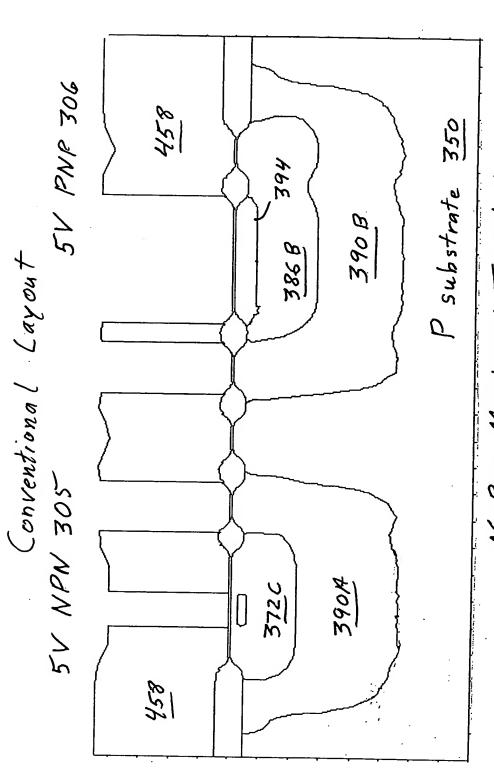




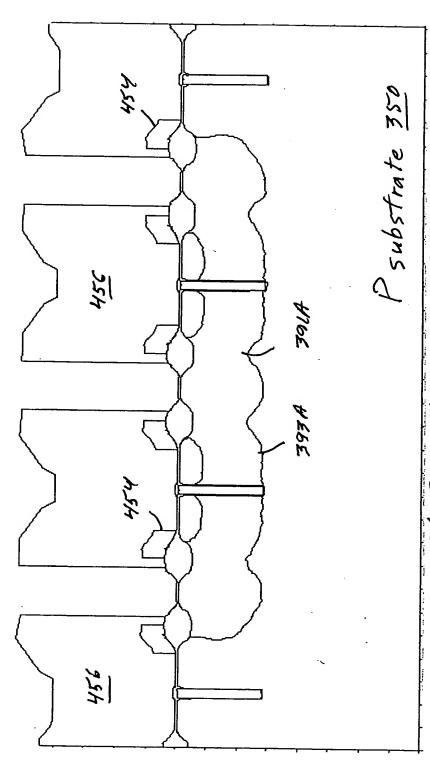
F19 53E





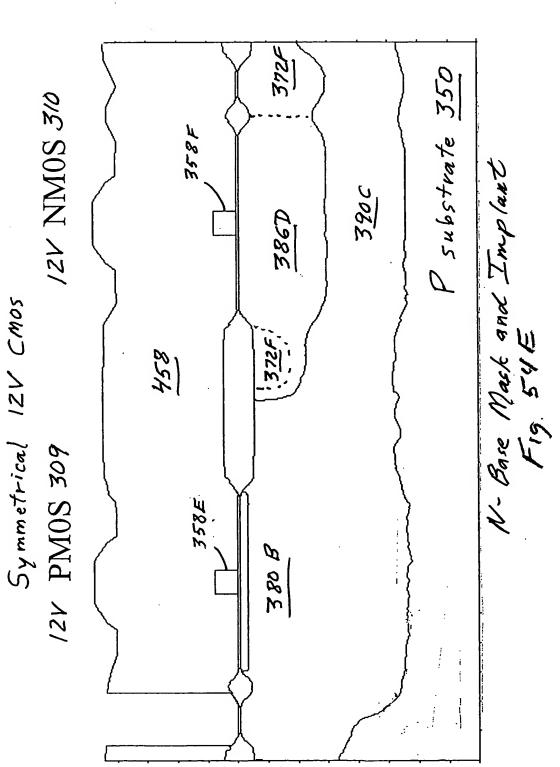


N-Base Mask and Implant Fig. 54C

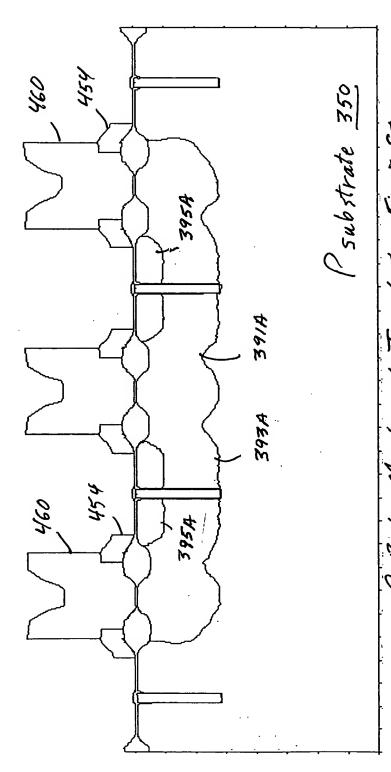


30V Lateral Trench DMB 308

N-Base Mask and Implant Fig. 54D

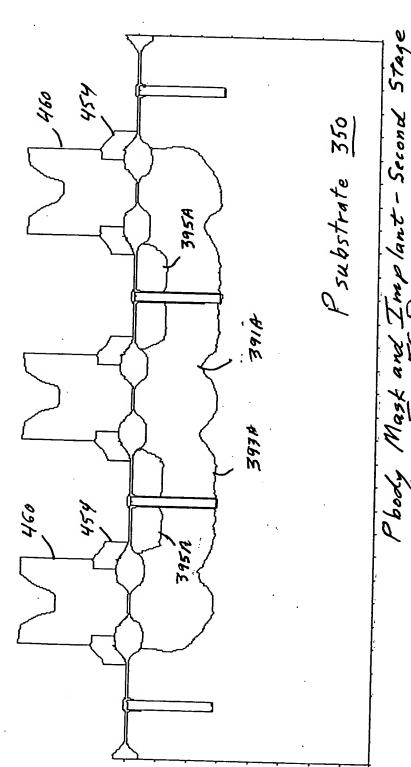


30V Lateral Trench DMOS 308



P Body Mask and Implant - First Stage Frg. 55 D

30V Lateral Trench DMOS 308

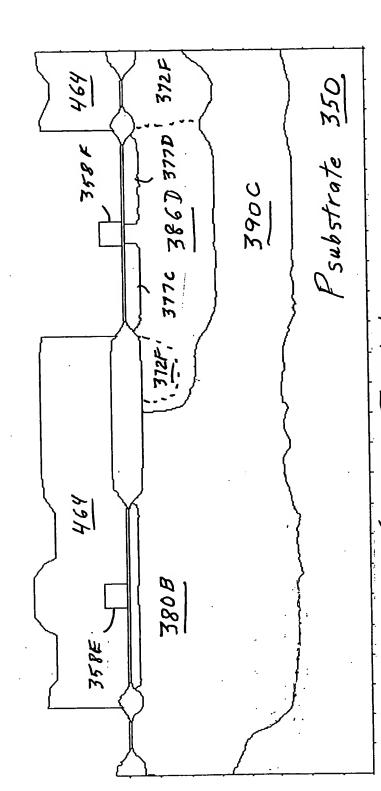


Pbody Mask and Implant - Second Stage

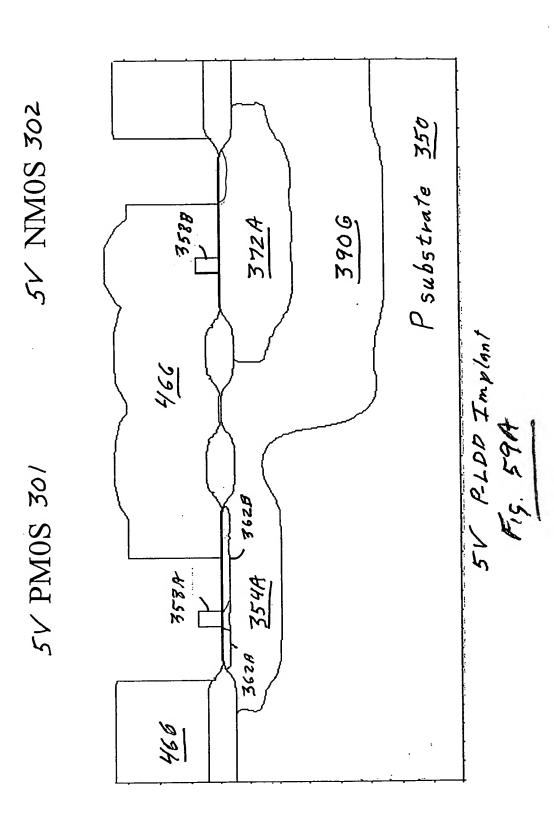
3726 Psubstrate 350 12V NIMOS 310 358F 390C 3867 762 Symmetrical 12V cMos 12V PMOS 309 372F! 3630 358E 380B 3830 462

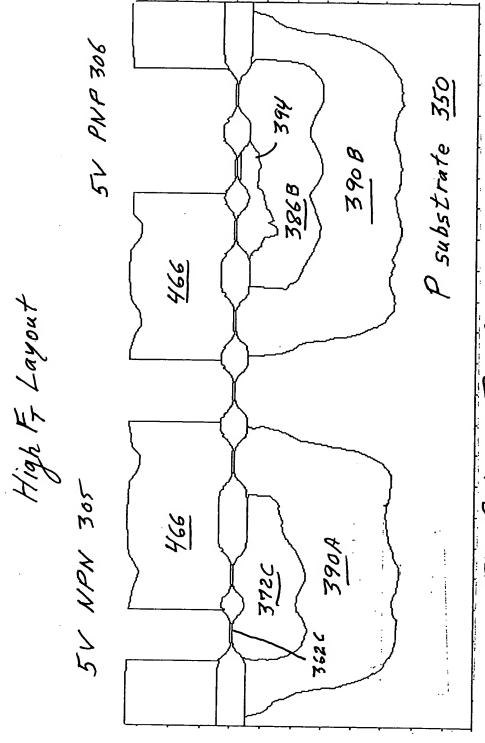
12V PLDD Implant

012 SOMN 721 Symmetrical 12V CMOS 12V PMOS 309



12V N-LDD Implant Fig 58 E





5V P-LDD Implant

466 Psubstrate 350 SV PNP 344 3908 3868 5V P-LOD Implant 99/1 SV NPN 390A 3720 994

Conventional Layout

P substrate 350 30V Lateral Trench DMOS 308 466 395A 3911 393A 395A 79/7

5V 1-100 Implant

5V NM0S 302

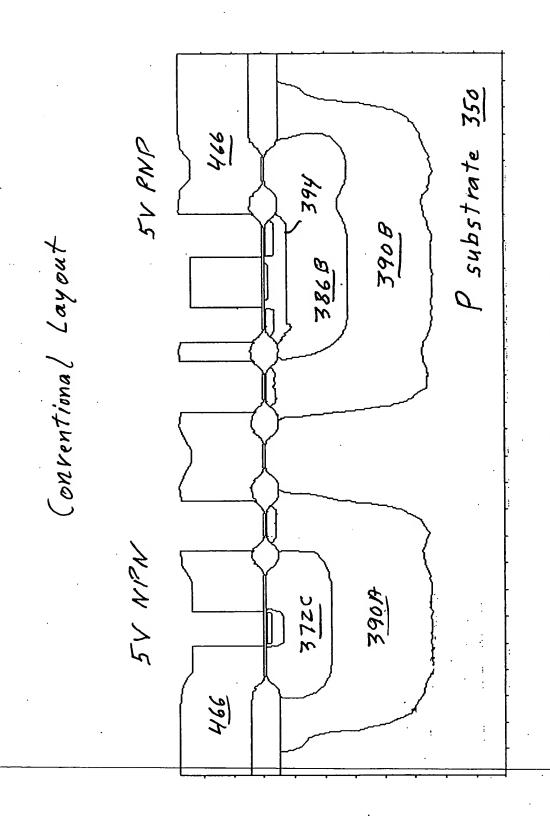
51 PM0S 301

P substrate 350 808 376B 340 G 376A 372A 3588 354A 358A 894

SV N-LDD Implans

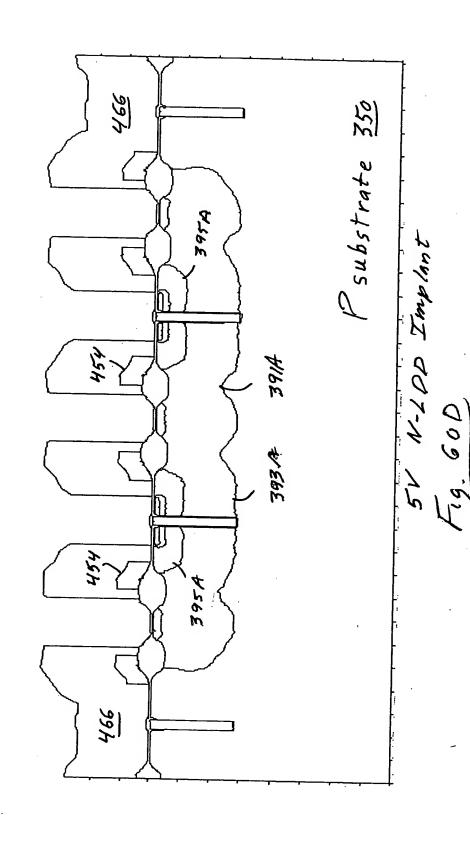
P substrate 350 5V PNP 306 468 394 390 13 386B High Fr Layout 5V NPN 305 390A 372C 894

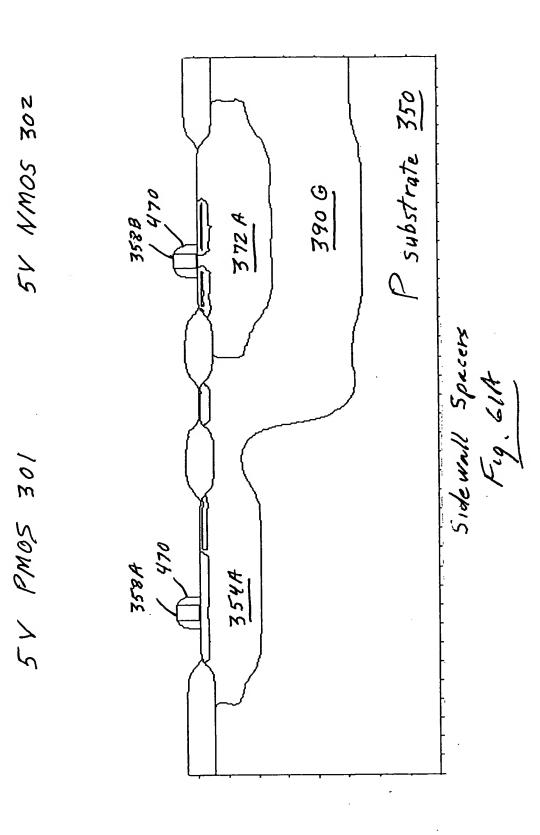
5V N-LOD Implant Fig 60 B



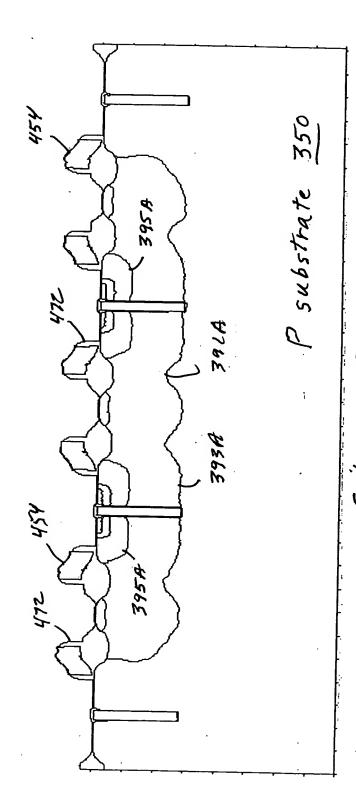
5V N-LOD Implant

30V Lateral Trench DMOS 308



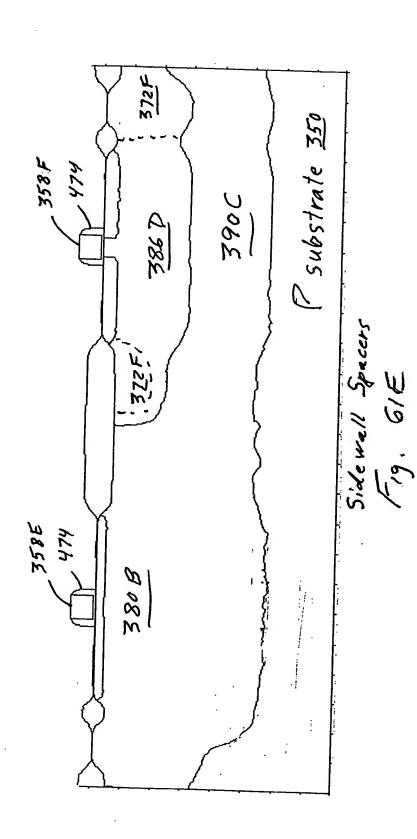


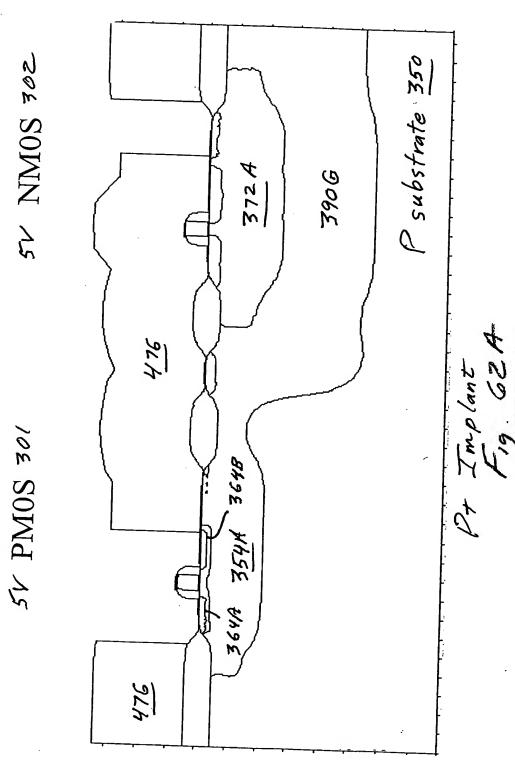
30V Lateral Treach DMOS 308



Sidewall Spacers Fig. 610

12× NMOS 310 Symmetrical 12V CMPS 12V PMOS 309

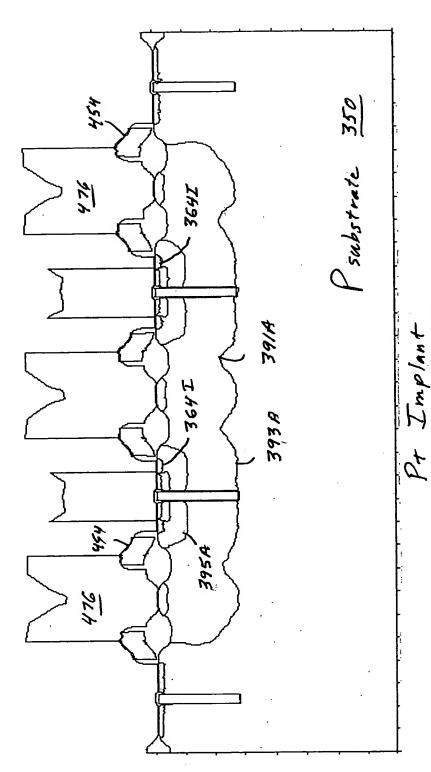




P substrate 350 364F 3646 5V PNP 306 344 390 B 386B 914 High Fy Layout 5V NPN 305 476 364E 390A 3726

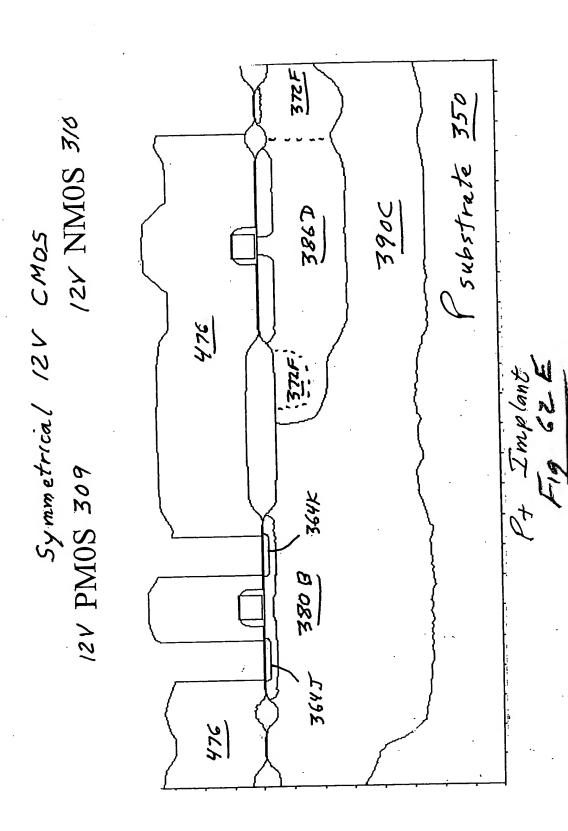
P substrate 350 344 5 PNP 3808 3868 Pt Implant Fig 62C 92 h 5V NPN 390A 3726 <u> 924</u>

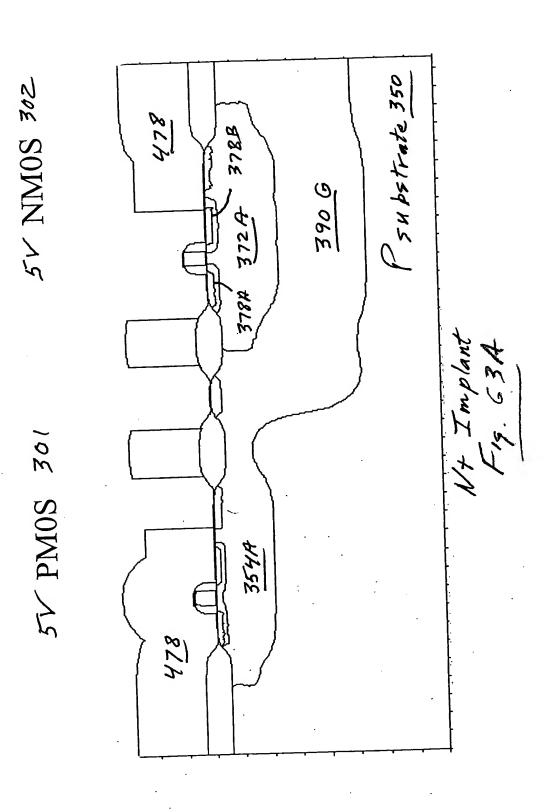
Conventional Layout



30V Lateral Trench DMG 308

Pt Implant Fig. 620

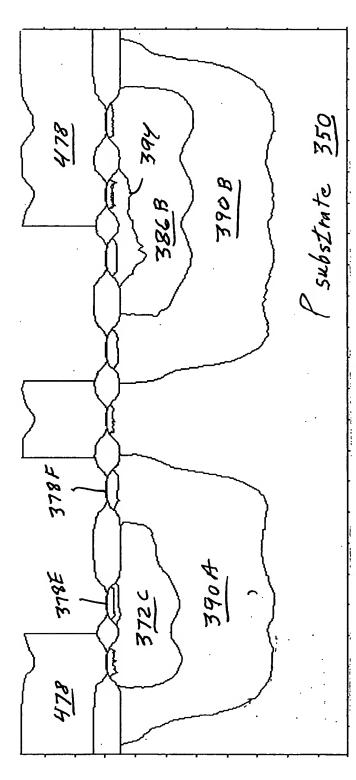




High Fr Layout

5V NPN 305

5V PNP 306



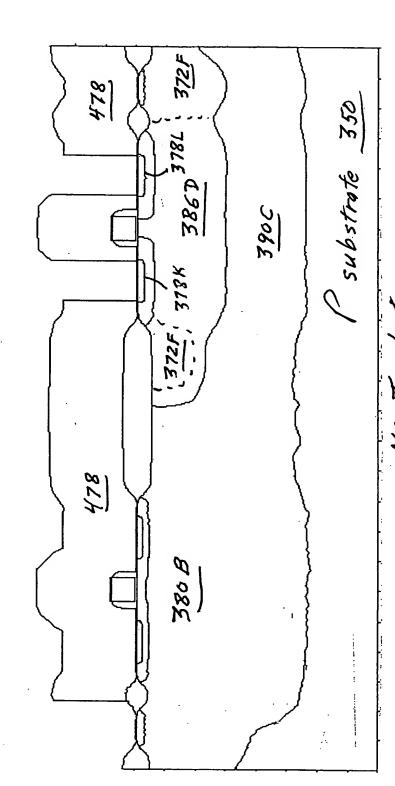
Nt Implant Flg. 63B

8418 SV PNP P substrate 350 398 3908 386B Conventional Layout Nt Implant Fig. 63C 5V NPN 390A 3726 470

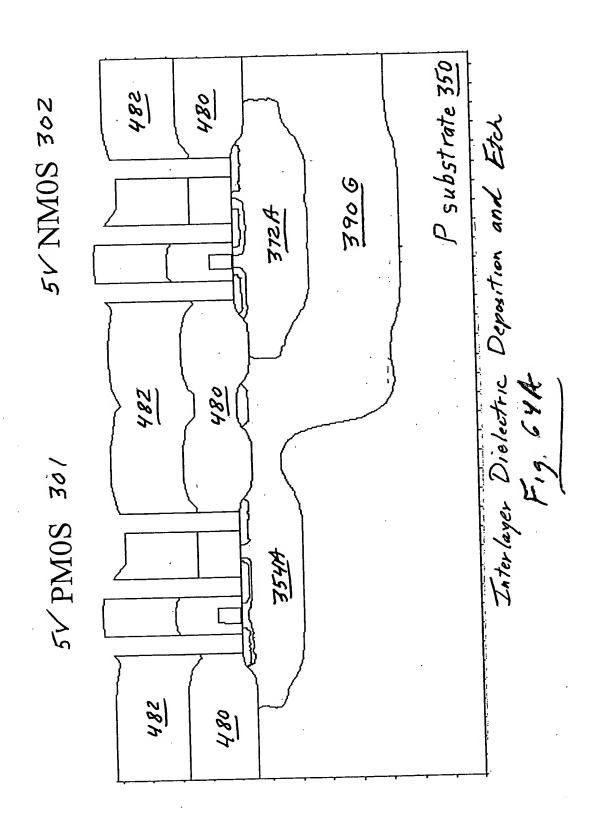
478 P substrate 350 30V Lateral Trench DMOS 308 3785 3781 3914 3785 393A (379I 395A' 8LH

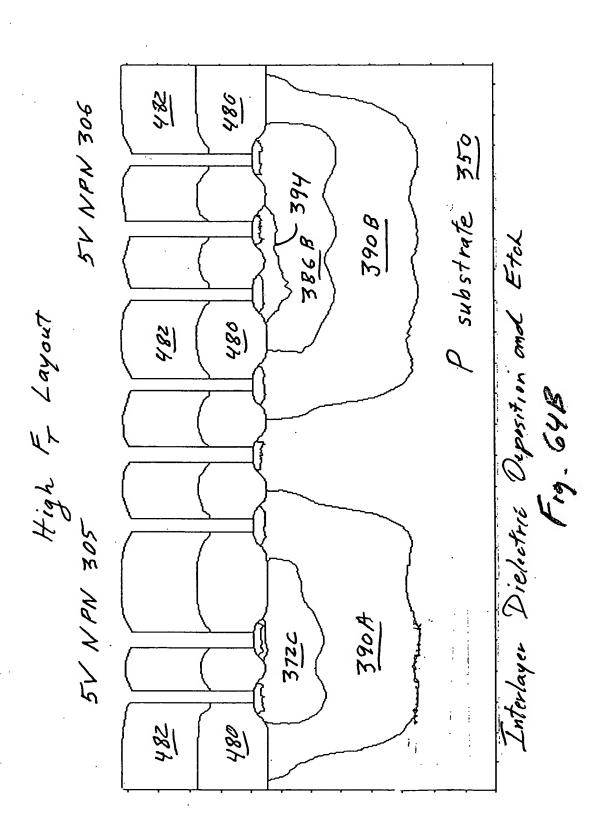
Nt Implant Fig 630

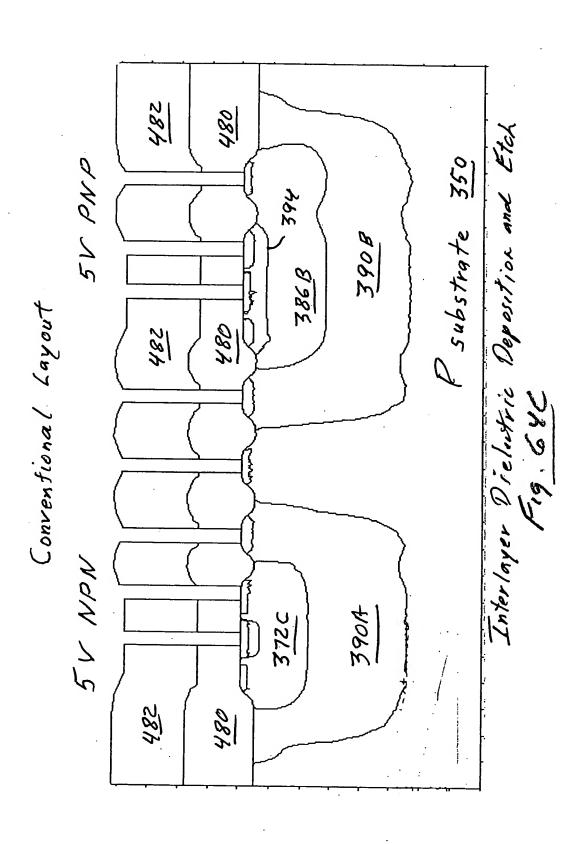
12V NM0S 3/0 Symmetrica (12V CMOS 12V PMOS 309 12

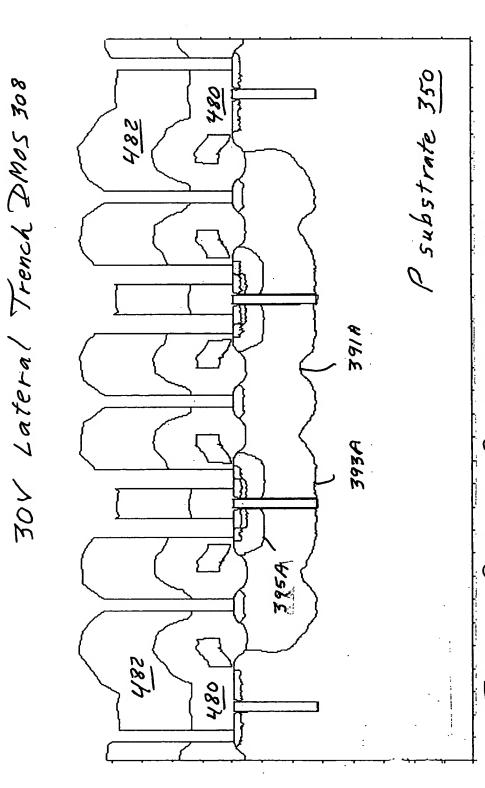


N+ Implant Fig 63 E



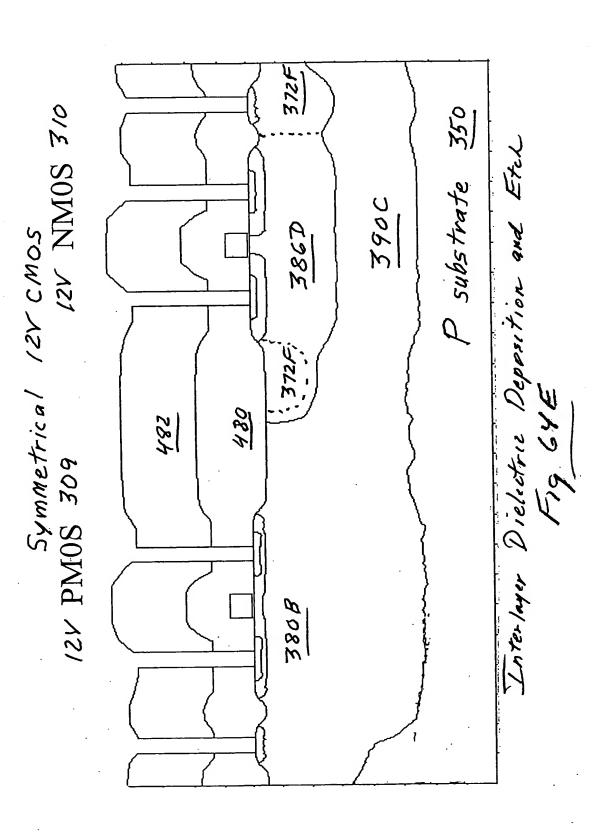


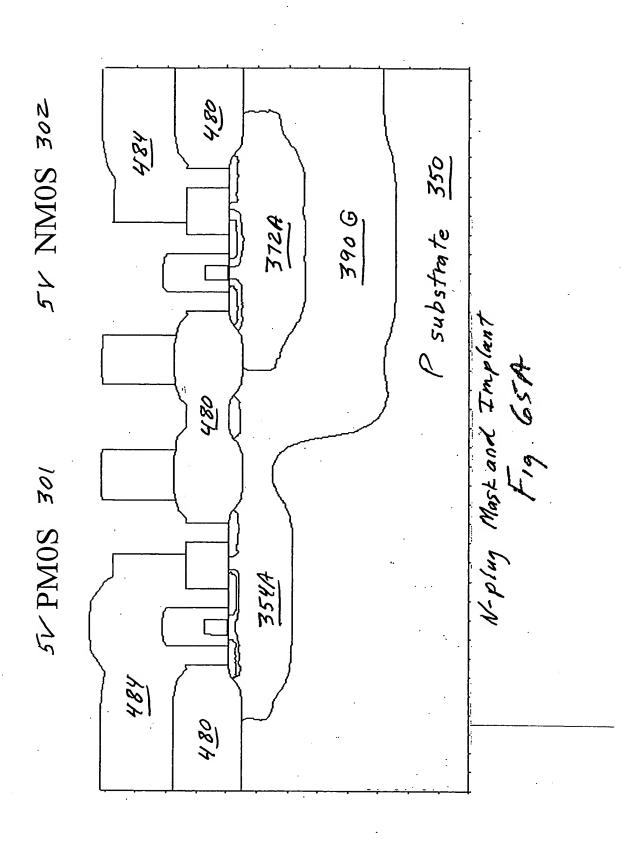


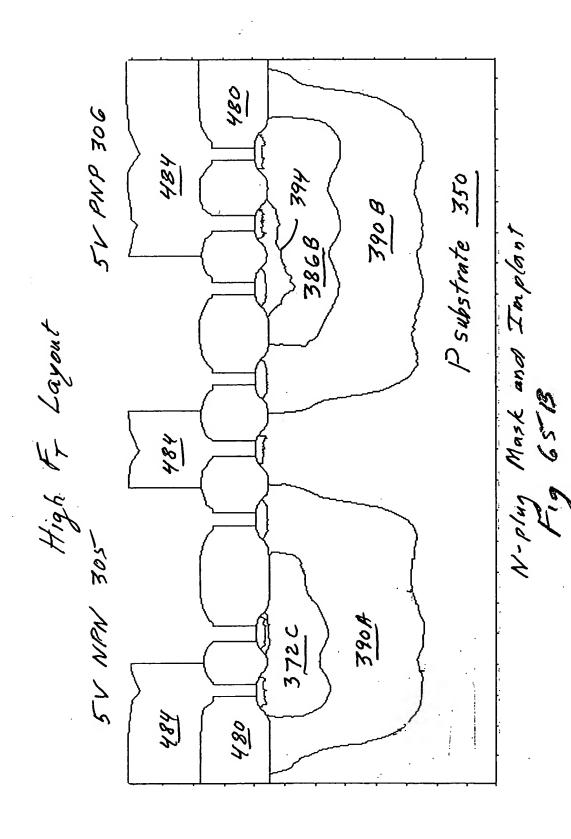


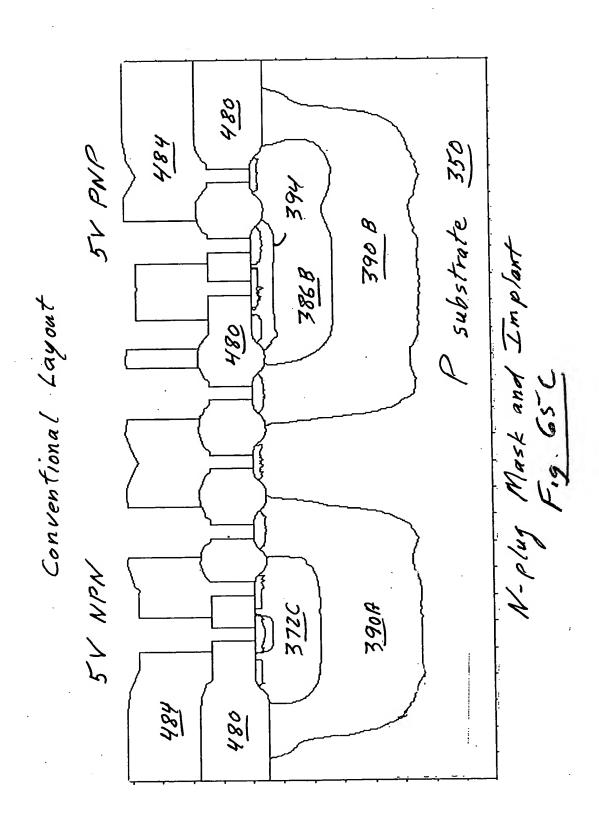
Interlayer Dieloctric Deposition and

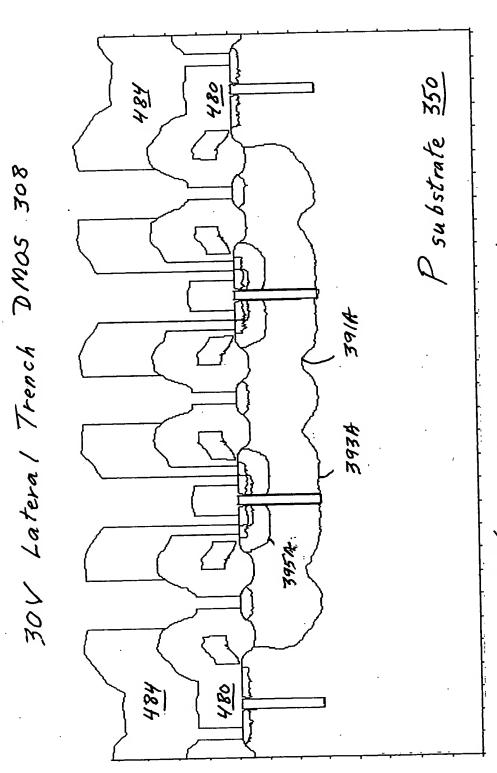
F19.640



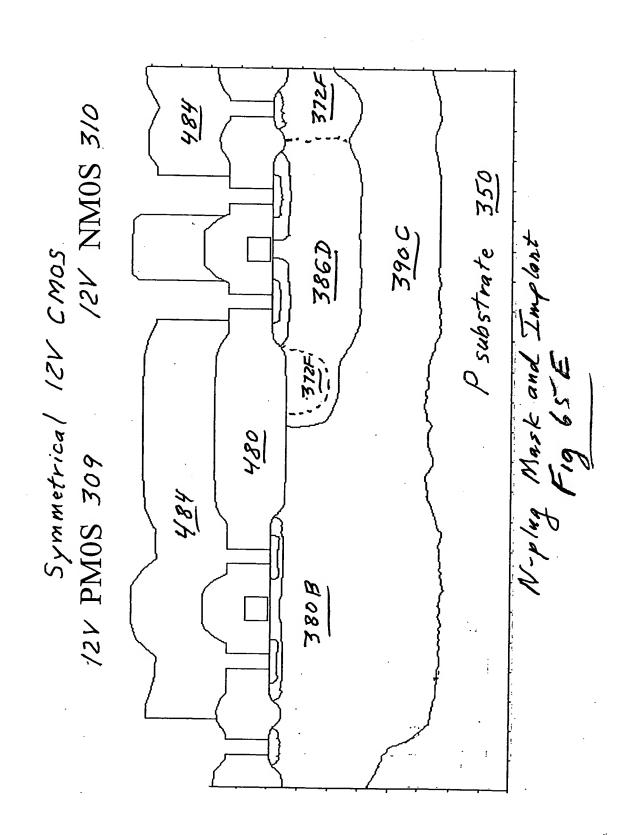






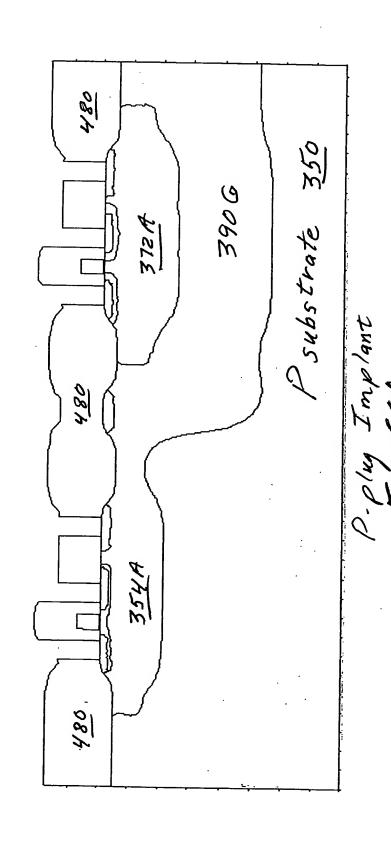


N-pluy Mask and Implant



5V NMOS 302

5V PM0S 301



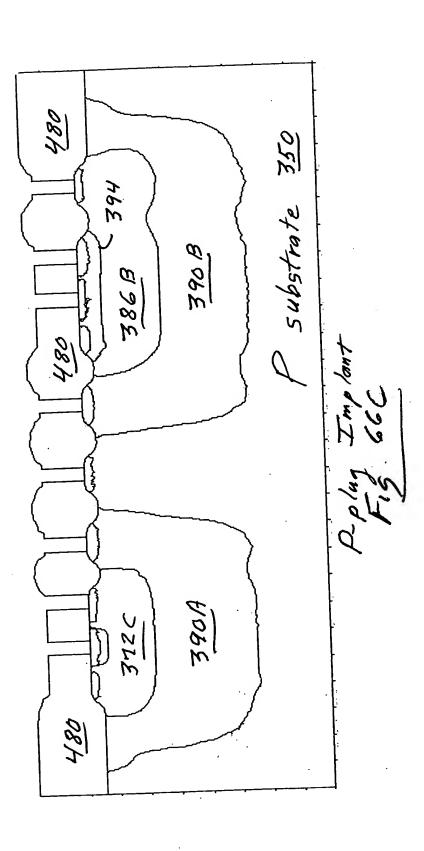
High F Layoul

5V PNP 306

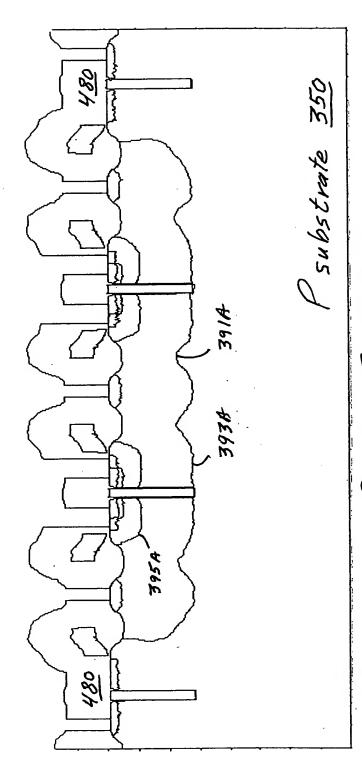
180 P substrate 350 394 3908 386B SOE NON 15 480 390A 3720 480

P-plug Implant Fig. 66 B

Conventional Layout SVNPN 5V PNP



30VLateral Trench DMOS 308



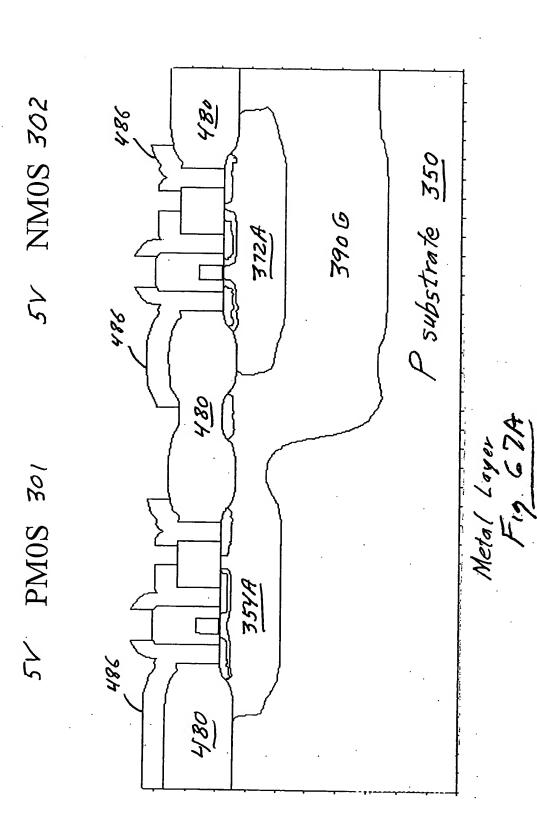
P-pluy Implant Fig. 66D

Symmetrical 12V cmos 12V PMOS 309 12V NMOS 310

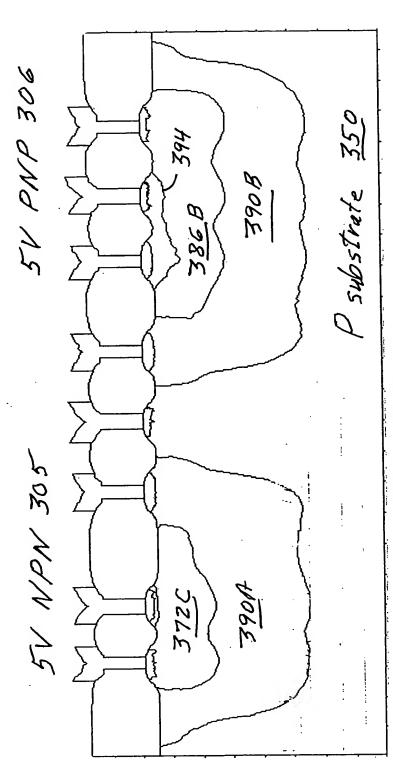
721E 390C 386D 326 480 380 B

P-plug Implant F19 GGE

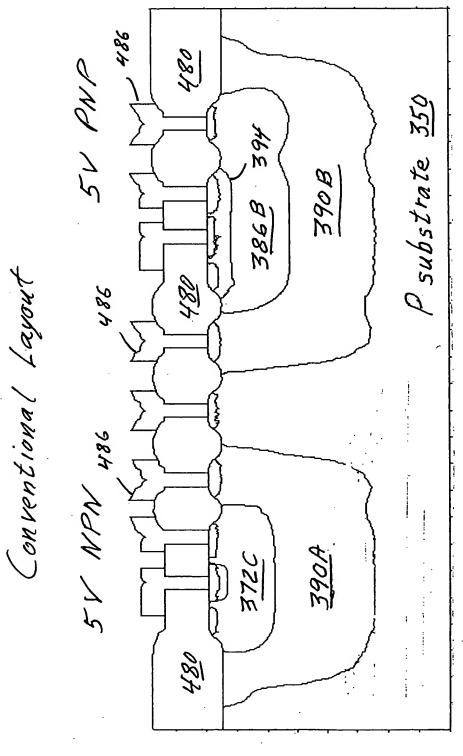
P substrate 350



High F Layout

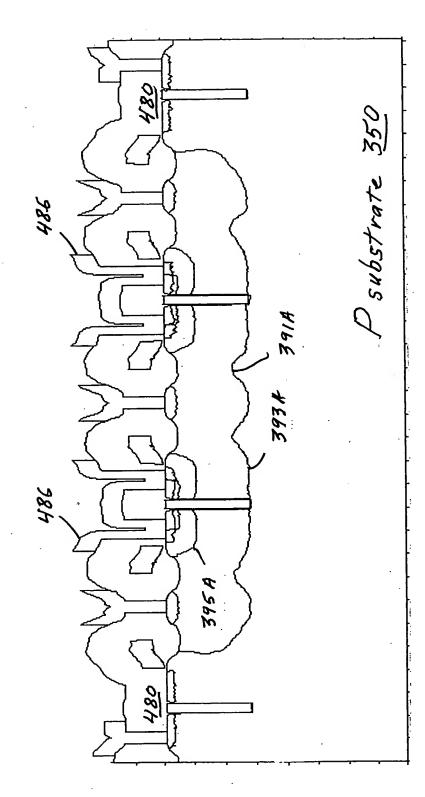


Metal Layer Fig. 67B

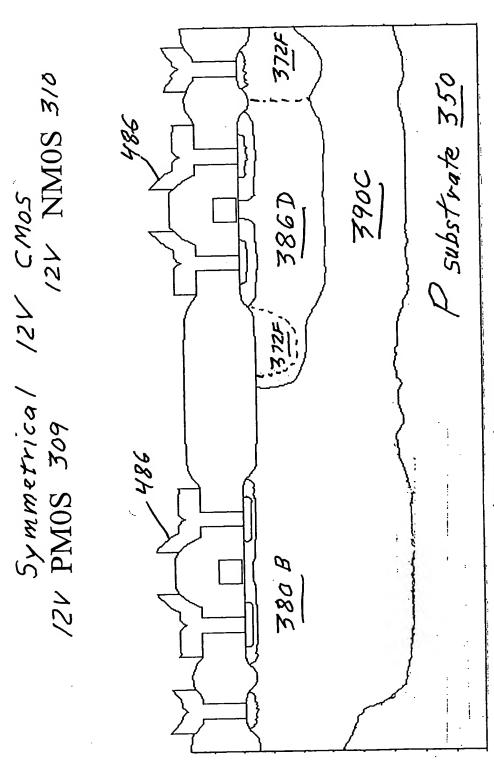


Metal Layer F19.67C

30V Lateral Trench DMOS 308



Metal Layer



Metal Layer

Fig. 17V

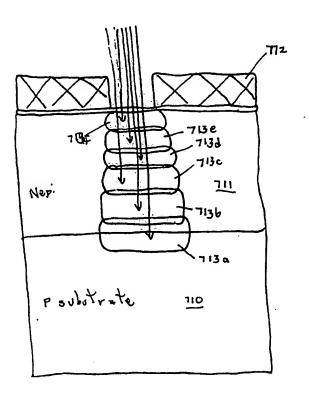


Fig. 17W

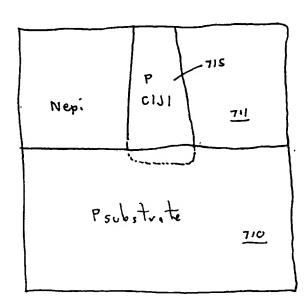
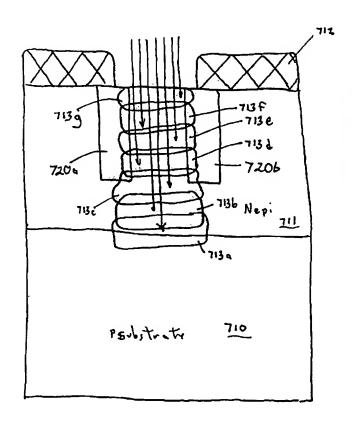


Fig. 17x

Fig. 174



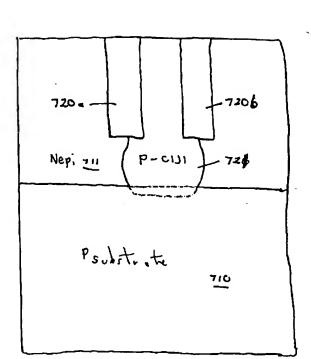


Fig. 172

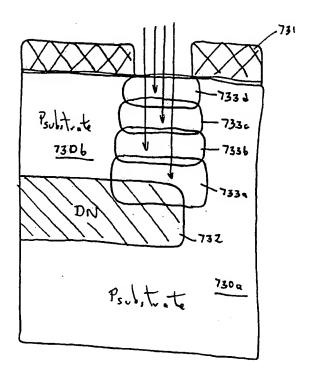
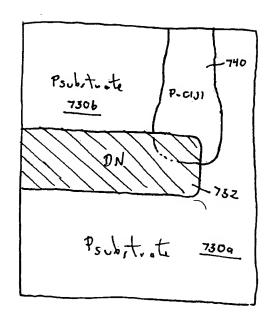


Fig. 17 AA



733 e 731
750a 7734
7336
7306
7306
7306
7300
7300

Fig. 17cc

